

(10 Gigabit Small Form Factor Pluggable Module)

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Publication History

Revision Number	Description	Date
0.1	Initial Publication of Document, Preliminary	3/27/02
0.5	First full draft	4/11/02
0.7	Second full draft	5/23/02
0.8	Third full draft	6/21/02
0.9	Pre-Public Release 0	7/15/02
0.91	Pre-Public Release 1	7/16/02
0.92	1st-Public Release	7/19/02
0.93	Pre-Meeting Editing Draft	8/21/02
0.95	Internal draft	09/21/02
0.99	2nd pre-Public Release	10/31/02
1.0	Pre-Ratification Draft	12/2/02
2.0	Adoption Draft	12/16/02
3.0	Adopted Specification	3/3/03
3.1	Modified Copyright Statement	4/2/03

Foreword

The XFP Promoters, Broadcom Corporation, Brocade Communications Systems, Inc., Ciena Corporation, Emulex Corporation, Finisar Corporation, nnovation Core SEI, Inc. (a Sumitomo Electric Company), JDS Uniphase Corporation, I Maxim Integrated Products, Tyco Electronics Corporation, Velio Communication, and many contributors gathered together to develop a specification for a 10 Gigabit small foot print pluggable module. The Promoters stated a wish to encourage broad and rapid industry adoption of the specification. The XFP specification may be offered to formal standards bodies to further support the adoption of the specification. The XFP Promoters and Contributors solicited technical review and contributions to the XFP specification among many component, module, and system designers and manufacturers to assure that it meets a broad variety of requirements.

Signed agreements exist among the promoters and between the promoters and contributors that allowed them to carry forward these activities in a manner that encouraged rapid development, open sharing of technology, and the timely resolution of disagreements. The agreements further explained and protected the rights of both promoters and contributors. Similar agreements protect the rights of adopters of the specification.

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Acknowledgments

The XFP members would like to acknowledge and thank Dr. Ali Ghiasi for his tremendous effort and diligence in editing this specification.

The members would like to thank Dr. Lew Aronson and Mr. Ed Bright for writing the Management and Mechanical chapters. In addition, they would like to thank Mr. Tom Lindsay for the jitter Appendix, Dr. Piero Bradley for jitter section, Mr. Lawrence Williams for the XFI Channel Simulation and Modeling and the Optimum Via Appendix, Mr. Henrik Johansen for the compliance test boards Appendix, Mr. Steve Silverman for the power supply section, Mr. Gary Heitkamp for the Thermal Appendix, Mr. Randy Clark for the 2-Wire Protocol, Mr. Ron Miller for the TDR Appendix, and Dr. Stefanos Sidiropoulos for the VPS section.

The members would also like to thank Mr. Robert Snively for skillfully steering the MSA, as without him we could not have achieved our goal.

Special thanks are due to all those who attended the meetings and made contributions, as this document is a collection of their work.

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CHAPTER 1: SCOPE OF XFP SPECIFICATION

1.1 INTRODUCTION

 This specification defines the electrical, management, and mechan terfaces of the XFP module. The module is a hot pluggable small for serial-to-serial data-agnostic multirate optical transceiver, intended support Telecom (SONET OC-192 and G.709 "OTU-2") and Datace plications (10 Gb/s Ethernet and 10 Gb/s Fibre Channel). Nominal rates range from 9.95 Gb/s, 10.31 Gb/s, 10.52 Gb/s, 10.70 Gb/s, at emerging 11.09 Gb/s. The modules support all data encodings for technologies. The modules may be used to implement single mode multi-mode serial optical interfaces at 850 nm, 1310 nm, or 1550 nm XFP module design may use one of several different optical connets. The XFP specification includes the following information: XFP reference model and description 3.2 Chapter 2: XFP Electrical Interface, Low Speed Electrical Interface Gb/s serial electrical specification (XFI) Chapter 3: High Speed Electrical Specification XFL, High spee Gb/s serial electrical specification (XFI) Chapter 5: Management interface, Management and diagnost terface Chapter 6: Mechanical and Board definition, Mechanical interincluding guides, EMI shields, module retention, cooling, and e cal connector. Appendix A: Application Reference Model Appendix A: Application Reference Model Appendix B: XFI Channel Measurements and Modeling. Appendix C: Differential S-Parameters and TDR. Appendix D: Optimum Via Design. 	
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Appendix F: Module Thermal Testing	

1.2	REQUIREMENTS ON PRESS	ANNOUNCEMENTS	1
		All press announcements specifying XFP compliant modules and compo- nents shall include the following text to identify the origin of the XFP spec-	2 3
		ification.	4
		The XFP is a development activity promoted by Broadcom Corporation,	5
		Brocade Communications Systems, Inc., Emulex Corporation, Finisar	6 7
		Corporation, JDS Uniphase Corporation, Innovation Core SEI, Inc., Maxim Integrated Products, Ciena Corporation, Tyco Electronics Corpo-	8
		ration, Velio Communication, and many contributors.	9
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CHAPTER 2: XFP ELECTRICAL INTERFACE

2.1 INTRODUCTION

The XFI "Ziffy" is the high speed serial electrical interface for XFP modules with a nominal baudrate of 9.95-11.1 Gb/s. XFI connects a serial 9.95-11.1 Gb/s SerDes to a module over 300mm of improved FR4¹ material or up to 200mm of standard FR4 with one connector. The electrical interface is based on high speed low voltage AC coupled logic with a nominal differential impedance of 100 Ω . The XFP module could be an Electrical-to-Optical or an Electrical-to-Electrical device.

The XFP modules and the host system are hot-pluggable. The module or 14 the host system shall not be damaged by unexpected insertion or removal 15 of the module. 16

2.2 GENERAL REQUIREMENTS

All electrical specifications shall be met over the entire specified range of power supplies given in section 2.7.

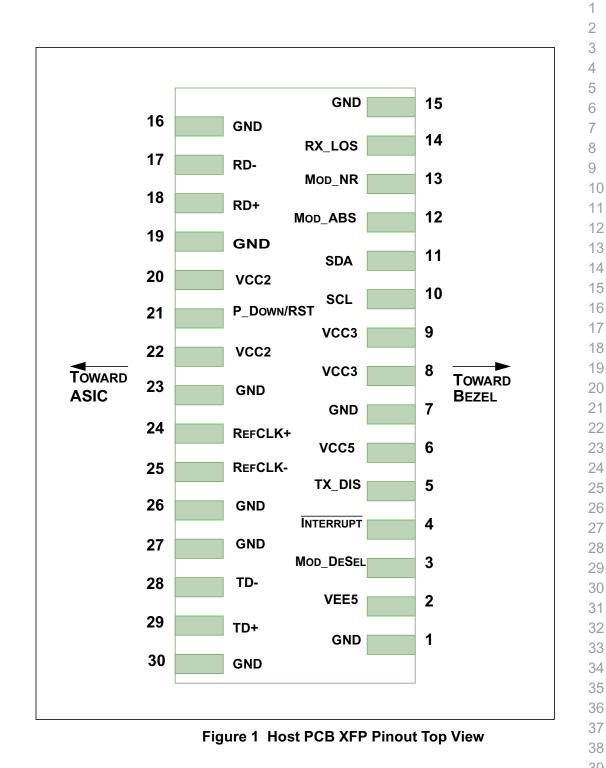
All XFP electrical specifications apply over the Environmental and23Thermal range described in section 6.13. If an extended operating range24is specified by the module vendor (see 5.35), then the electrical specifications apply over this extended operating range.232626

2.3 XFP HOST CONNECTOR DEFINITION

The XFP host connector is based on a 0.8 mm pitch 30 position right angle connector <u>6.9</u>. Host PCB pin assignment is given by Figure 1 and pin definition are listed in Table 1. All XFP compliance points are defined using this connector. An improved version of this connector will be available from Tyco and possibly from other sources. It is recommended that host systems use the new improved connector for better signal integrity and EMI.

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^{1.} Standard FR4 has a typical loss tangent of 0.022, where improved FR4 such
as Nelco 4000-13 has a typical loss tangent of 0.016.41



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- 41 42

Table 1 Module Electrical Pin Definition

Pin	Logic	Symbol	Name/Description	Note		
1		GND	Module Ground	1		
2		VEE5	Optional -5.2V Power Supply			
3	LVTTL-I	Mod_DeSel	Module De-select; When held low allows module to respond to 2-wire serial interface			
4	LVTTL-O	Interrupt	errupt; Indicates presence of an important condition which can be read over the 2-wire 2 ial interface			
5	LVTTL-I	TX_DIS	Transmitter Disable; Turns off transmitter laser output			
6		VCC5	+5V Power Supply			
7		GND	Module Ground	1		
8		VCC3	+3.3V Power Supply			
9		VCC3	+3.3V Power Supply			
10	LVTTL-I/O	SCL	2-Wire Serial Interface Clock	2		
11	LVTTL-I/O	SDA	2-Wire Serial Interface Data Line	2		
12	LVTTL-O	Mod_Abs	Indicates Module is not present. Grounded in the Module	2		
13	LVTTL-O	Mod_NR	Module Not Ready; Indicating Module Operational Fault	2		
14	LVTTL-O	RX_LOS	Receiver Loss Of Signal Indicator	2		
15		GND	Module Ground	1		
16		GND	Module Ground	1		
17	CML-O	RD-	Receiver Inverted Data Output	1		
18	CML-O	RD+	Receiver Non-Inverted Data Output	1		
19		GND	Module Ground	1		
20		VCC2	+1.8V Power Supply	3		
21	LVTTL-I	P_Down/RST	Power down; When high, requires the module to limit power consumption to 1.5W or below. 2-Wire serial interface must be functional in the low power mode.			
			Reset; The falling edge initiates a complete reset of the module including the 2-wire serial interface, equivalent to a power cycle.			
22		VCC2	+1.8V Power Supply	3		
23		GND	Module Ground	1		
24	PECL-I	RefCLK+	Reference Clock Non-Inverted Input, AC coupled on the host board			
25	PECL-I	RefCLK-	Reference Clock Inverted Input, AC coupled on the host board			
26		GND	Module Ground	1		
27		GND	Module Ground	1		
28	CML-I	TD-	Transmitter Inverted Data Input			
29	CML-I	TD+	Transmitter Non-Inverted Data Input			
30		GND	Module Ground	1		

3. The 1.8 V power supply can be optionally programmed to voltages lower than 1.8 V in modules supporting the variable power supply. 42

2.4 LOW SPEED ELECTRICAL	ARDWARE PINS	1
	In addition to the 2-wire serial interface the XFP module has the following	2
	low speed pins for control and status:	3 4
	Mod_NR	5
	Mod_DeSel	6
	Interrupt	7
	• TX_DIS	8
	Mod_ABS	9 10
	RX_Los	11
	P_Down/RST.	12
		13
		14
2.4.1 Mod_NR		15
	The Mod_NR is an output pin that when High, indicates that the module has detected a condition that renders transmitter and or receiver data in-	16 17
	valid, shall consist of logical OR of the following signals:	18
		19
	Transmit Signal Conditioner Loss of Lock	20
	Transmitter Laser Fault	21
	Receiver Signal Conditioner Loss of Lock	22 23
	Other conditions deemed valuable to the detection of fault may be added to the Mod_NR.	23 24
		25
	The Mod_NR output pin is an open collector and must be pulled to Host_Vcc on the host board.	26
		27
2.4.2 MOD_DESEL		28 29
	The Mod_DeSel is an input pin. When held Low by the host, the module	30
	responds to 2-wire serial communication commands. The Mod_DeSel al- lows the use of multiple XFP modules on a single 2-wire interface bus.	31
	When the Mod_DeSel pin is "High", the module shall not respond to or ac-	
	knowledge any 2-wire interface communication from the host. Mod_DeSel	33
	pin must be pulled to VCC3 in the module.	34 35
	In order to avoid conflicts, the host system shall not attempt 2-wire inter-	36
	face communications within the Mod_DeSel assert time after any XFP modules are deselected. Similarly, the host must wait at least for the pe-	37
	riod of the Mod_DeSel deassert time before communicating with the	38
	newly selected module. The assertion and de-assertion periods of dif-	39
	ferent modules may overlap as long as the above timing requirements are met.	40 41

XFP Specification REVISON 3.1	XFP Electrical Interface	April 2, 2003
2.4.3 INTERRUPT		
	Interrupt is an output pin. When "Low", indicates tional fault or a status critical to the host system. open collector output and must be pulled up to H	The Interrupt pin is an
2.4.4 TX_DIS		
	TX_DIS is an input pin. When TX_DIS is asserte transmitter output must be turned off. The TX_DI to VCC3 in the XFP module.	-
2.4.5 MOD_ABS		
	Mod_ABS is pulled up to Host_Vcc on the host bo XFP module. Mod_ABS is then asserted "High" v physically absent from a host slot.	0
2.4.6 RX_LOS		
	The RX_LOS when High indicates insufficient or signal reception. The RX_LOS pin is an open co be pulled up to Host_Vcc on the host board.	-
2.4.7 P_Down/RST		
	This is a multifunction pin for module Power Dow P_Down/RST pin must be pulled up to VCC3 in t	
2.4.7.1 Power Down Function	DN	
	The P_Down pin, when held High by the host, pl standby (Low Power) mode with a maximum pow This protects hosts which are not capable of coo ules which may be accidentally inserted.	ver dissipation of 1.5W.
	The module's 2-wire serial interface and all laser	safety functions must be
	fully functional in this low power mode. During P_	
	still support the completion of reset Interrupt, as v ality of the variable power supply as described in	
2.4.7.2 RESET FUNCTION		
	The negative edge of P_Down/RST signal initiate	es a complete module
	reset.	

2.4.7.3 MODULE BEHAVIOR DURING POWER DOWN AND RESET During execution of a reset (t_init) or while held in Power Down mode, a module may be unable to determine the correct value for Mod NR and RX LOS. These outputs as well as all interrupt related flags, except com-pletion of Reset flag, shall be disregarded by the host. When the module completes a Reset and is not in Power Down mode, the module must rep-resent the correct value of both signals on its outputs before posting a completion of reset interrupt to the host (see Table 39, bit 0 register ad-dress 84). At no time shall a module cause spurious assertion of the Interrupt pin. When a host initially applies power to a module with the P Down/RST signal asserted, a module comes up in power down mode. The module shall only assert the Interrupt signal pin to inform the host it has completed a reset. The completion of reset flag (see Table 39, bit 0 register address 84) shall be the only interrupt source flag set during power down mode. The host is expected to clear this interrupt before releasing the module from the power down mode. The transition from power down mode to normal mode will trigger a reset of the module and result in a 2nd module reset and a 2nd reset completion interrupt to the host

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2.5 LOW SPEED ELECTRICAL SPECIFICATIONS

Low speed signaling is based on Low Voltage TTL (LVTTL) operating at 2 Vcc3 at a nominal supply of $(3.3 \text{V} \pm 5\%)$. Hosts shall use a pull-up resistor $3 \text{ connected to a host_Vcc of } +3.3 \text{ volts} (3.15 \text{ to } 3.45 \text{ volts}) \text{ on the 2-wire in-} 4 \text{ terface SCL (clock), SDA (Data), and all low speed status outputs.}$

The XFP low speed electrical specifications are given in <u>Table 2</u>. This specification ensures compatibility between host bus masters and XFP SCL/SDA lines and compatibility with I^2C .

Table 2 Low speed control and sense signals, electronic characteristics **Symbol** Max. Unit **Conditions Parameter** Min. V Rpullup pulled to host_Vcc, measured at Vol 0.0 0.40 host side of connector. $I_{OL}(max) = 3 \text{ mA}$ XFP Interrupt, Mod_NR, RX_LOS VOH host_Vcc - 0.5 $host_Vcc + 0.3$ V Rpullup pulled to host_Vcc, measured at host side of connector. V -0.3 0.8 Rpullup pulled to VCC3, measured at XFP V_{IL} side of connector. $I_{II}(max) = -10 \text{ uA}$ XFP TX_Dis, P_Down/RST VCC3 + 0.3V Rpullup pulled to VCC3, measured at XFP 2.0 VIH side of connector. $I_{IH}(max) = 10 \text{ uA}$ 0.0 0.40 V Rpullup¹ pulled to host_Vcc, measured at VOL host side of connector. $I_{OL}(max) = 3 \text{ mA}$ XFP SCL and SDA Rpullup¹ pulled to host_Vcc, measured at host_Vcc - 0.5 $host_Vcc + 0.3$ V V_{OH} host side of connector. Vcc3*0.3 V Rpullup¹ pulled to Host_VCC, measured at V_{IL} -0.3 XFP side of connector. $I_{IL}(max) = -10 \text{ uA}$ XFP SCL and SDA V VIH Vcc3*0.7 VCC3 + 0.5Rpullup¹ pulled to Host_VCC, measured at XFP side of connector. $I_{IH}(max) = 10 \text{ uA}$ -10 10 Leakage Current I_l μA Capacitance for XFP SCL C_i 14 pF 10pF for XFP IC I/O pin, and SDA I/O Pin 4 pF for XFP PCB trace 100 pF At 400 KHz, 3.0 Kohms Rp, max Total bus capacitive load At 100 KHz, 8.0 Kohms Rp, max Cb for SCL and for SDA 400 pF At 400 KHz, 0.80 Kohms Rp, max At 100 KHz, 2.0 Kohms Rp, max 1. For combinations of Rpullup (Rp), bus capacitance and speed, see Philips I²C specification revision 2.1, figures 39 and 44. Rise and fall time measurement levels are defined in the XFP management interface ac electrical specifications. Active bus termination may be used by the host in place of a pullup resistor, as described in the Philips I2C specification

2.6 TIMING REQUIREMENT OF CONTROL AND STATUS I/O

The timing requirements of control and status I/O are defined in<u>Table 3</u>.

Table 3 Timing Parameters for XFP Management

Parameter	Symbol	Min.	Max.	Unit	Conditions
TX_DIS assert time	t_off		10	µsec	rising edge of TX_DIS to fall of output signal below 10% of nominal
TX_DIS negate time	t_on		2	msec	Falling edge of TX_DIS to rise of output sig- nal above 90% of nominal
Time to initialize	t_init		300	msec	From power on or hot plug after supply meet- ing <u>Table 4</u> or from falling edge of P_Down/RST.
Interrupt assert delay	Interrupt_on		200	msec	From occurrence of the condition triggering Interrupt
Interrupt negate delay	Interrupt_off		500	µsec	From clear on read Interrupt flags
P_Down/RST assert delay	P_Down/RST_on		100	µsec	From Power down initiation
Mod_NR assert delay	Mod_nr_on		1	msec	From Occurrence of fault to assertion of MOD_NR
Mod_NR negate delay	Mod_nr_off		1	msec	From clearance of signal to negation of MOD_NR
P-Down reset time		10		µsec	Min length of P-Down assert to initiate reset
RX_LOS assert delay	t_loss_on		100	µsec	From Occurrence of loss of signal to assertion of RX_LOS
RX_LOS negate delay	t_loss_off		100	µsec	From Occurrence of presence of signal to negation of RX_LOS

The 2-wire serial bus timing is described in <u>Chapter 4: XFP 2-Wire Inter-</u><u>face Protocol</u>.

2.7 XFP POWER REQUIREMENT

2.7 AFP POWER REQUIREMEN	I	1
	The XFP host has 3 power supplies +1.8 V, +3.3 V, +5.0 V and an optional -5.2 V supply. The +1.8 V and +3.3 V supplies have two designated power pins in the connector for each power supply rail. The +5 V and -5.2 supplies have one designated power pin each. The maximum continuous or peak current carrying capacity for each connector pin is 500 mA.	2 3 4 5 6 7
	The host system may alter the VCC2 supply to a voltage level lower that the nominal +1.8 V value. This mode of operation is <i>optional</i> and can be supported by modules and hosts that strive to meet lower power/current requirements. Modules supporting this optional lower power mode must be backwards compatible with modules and hosts supporting only 1.8 V on VCC2, i.e. modules implementing these optional modes must be able to operate normally with a voltage of +1.8 V applied on their VCC2 pins (albeit with higher power dissipation). For more details see section 5.7 .	8 9 10 11 12 13 14
	XFP module maximum power dissipation must meet one of the following classes:	15 16 17
	 Power Level 1 modules – Up to 1.5 W 	18
	 Power Level 2 modules – Up to 2.5 W 	19
	 Power Level 3 modules – Up to 3.5 W 	20
	 Power Level 4 modules – Greater than 3.5 W 	21
		22 23
	To avoid exceeding system power supply limits and cooling capacity, the module may be placed in the power down mode by pulling pin 21 High. This guarantees module operating in Low Power mode with maximum power dissipation of \leq 1.5W.	24 25 26 27 28
	A host board together with XFP module(s) forms an integrated power system. The host supplies stable power to the module. The module limits electrical noise coupled back into the host and limits inrush charge/current during hot plug insertion.	29 30 31 32
	All specifications shall be met at the maximum power supply current. No power sequencing of the power supplies is required of the host system.	33 34 35
2.7.1 Power Noise Output	To limit wide band noise power, the host system and module shall each meet a maximum of 2% peak-peak noise when measured with a 1MHz low pass filter. In addition, the host system and the module shall each meet a maximum of 3% peak-peak noise when measured with a high pass filter from 1MHz-10 MHz.	36 37 38 39 40 41 42

XFP Electrical Interface

13 14

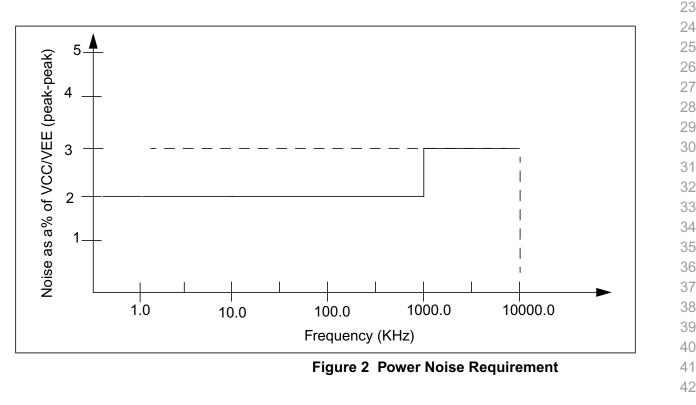
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The XFP port on a host board is tested with a resistive load in place of the XFP module, each voltage rail at maximum current supported by the host. Voltage is measured at the module side of the XFP connector. The test is performed with all other portions of the host board/system active. Hosts with multiple XFP modules shall test ports one at a time, with active XFPs in all the remaining ports.

The XFP module is tested with a high quality power supply connected 7 through the sample filter Figure 3. Voltage is measured at the host side of 8 the XFP connector, between the sample host filter network and the XFP. The module must pass this test in all operating modes. This test ensures 9 the module will not couple excessive noise from inside the module back 011 11 12

2.7.2 POWER NOISE SUSCEPTIBILITY

A module will meet all electrical requirements and remain fully operational in the presence of noise on all voltage inputs. The recommended susceptibility test is to sweep a sinuosidal waveform on each voltage input, with peak amplitude as described in <u>Figure 2</u>. This test applies at minimum and maximum DC setpoint levels. It is also desirable for a module and host to each tolerate a degree of random or semi-random noise on all voltage pins simultaneously, but the characteristics of this noise are beyond the scope of this document.



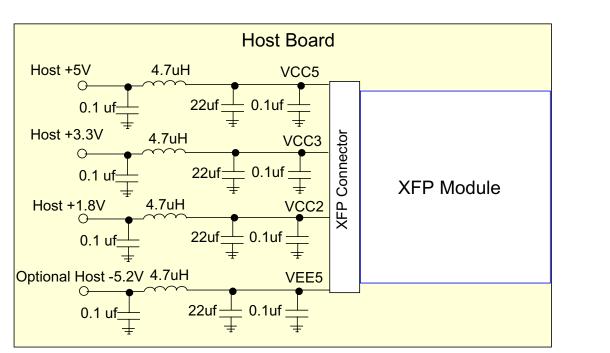
XFP MSA

For power supply noise susceptibility testing and methodology see <u>E.7</u>.

2.7.3 HOST FILTERING

The example host board power supply filtering shown in Figure 3 will meet the noise filtering requirements in most systems. Other filtering implementations or local regulation may be used to meet the power noise output requirements described in section 2.7.1.

Any voltage drop across a filter network on the host is counted against the Host DC setpoint accuracy specification in <u>Table 4</u>. For this reason, the example filter illustrated in Figure 3 may not be appropriate for a host powering multiple XFPs and/or other host components from a shared voltage supply.





Parameters	Symbol	Conditions	Min	Max	Units
VCC5 (5V)	/VEE5 (-5.2V) Pin				
Power Supply Noise including Ripple [peak-to-peak]	VCC5/VEE5	see <u>2.7.1</u>			%
Host DC set point accuracy			-5	+5	%
Module Maximum Current Inrush		Note 1		0.5	A
Module current ramp rate		Note 1		100	mA/µs
Maximum Power for the +5 and -5.2V Rail				2.5	W
Maximum Power for the +5 and -5.2V Rail During Power Down		Note 2		0.25	W
Host Bulk bypass capacitance for the module		Note 3	22		uF
VCC	3 (3.3V) Rail				
Power Supply Noise including Ripple [peak-to-peak]	VCC3	see <u>2.7.1</u>			%
Host DC set point accuracy			-5	+5	%
Module Maximum Current Inrush		Note 1		0.75	A
Module current ramp rate		Note 1		100	mA/μs
Maximum Power for the +3.3V Rail				2.5	W
Maximum Power for the +3.3V Rail During Power Down		Note 2		1	W
Host Bulk bypass capacitance for the module		Note 3	22		uF
VCC.	2 (1.8V) Rail		•		
Power Supply Noise including Ripple [peak-to-peak]	VCC2	see 4, <u>2.7.1</u>			%
Host DC set point accuracy			-5	+5	%
Module Maximum Current Inrush		Note 1		1	А
Module current ramp rate		Note 1		100	mA/µs
Maximum Power for the 1.8V Rail				1.8	W
Maximum Power for the 1.8V Rail During Power Down		Note 2		1	W
Host Bulk bypass capacitance for the module		Note 3	22		uF

2. Maximum module power dissipation shall not exceed 1.5 W.

3. Host provides bulk capacitance to suppress low frequency noise inside the XFP module. Host and module must each implement appropriate high frequency bypass to independently meet the noise requirement defined in section 2.7.1.

4. VCC2 can be optionally programmed to voltages less than 1.8V in modules supporting the Variable Power Supply 5.7.

2.8 ESD

	1
The XFP module and host XFI pins (High Speed Pins) shall withstand 500 V electrostatic discharge based on Human Body Model per JEDEC JESD22-A114-B.	2 3 4
The XFP module and all host pins with exception of the XFI pins (High Speed Pins) shall withstand 2KV electrostatic discharge based on Human Body Model per JEDEC JESD22-A114-B.	5 6 7 8
The XFP module shall meet ESD requirement given in EN61000-4-2, cri-	9
terion B test specification such that units are subjected to 15KV air dis-	10
charges during operation and 8KV direct contact discharges to the case.	11
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CHAPTER 3: HIGH SPEED ELECTRICAL SPECIFICATION XFI

3.1 INTRODUCTION

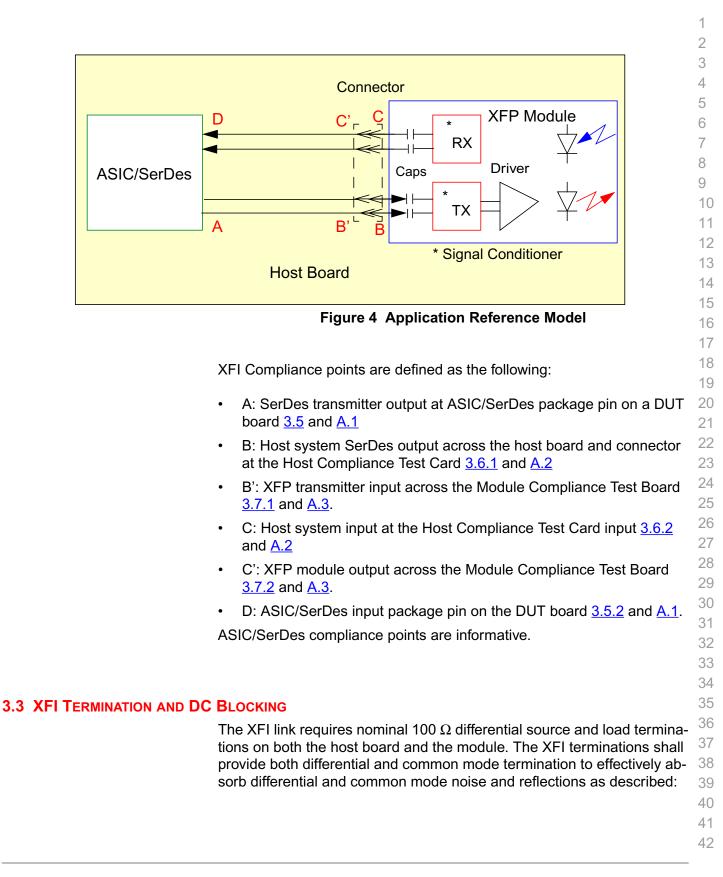
XFI signaling is based on high speed low voltage logic, with nominal 100 Ohms differential impedance and AC coupled in the module. XFI was developed with the primary goal of low power and low Electro-Magnetic-Interference (EMI). To satisfy this requirement the nominal differential signal levels are 500 mV p-p with edge speed control to reduce EMI.

3.2 XFI APPLICATIONS DEFINITION

The application reference model for XFI, which connects a high speed ASIC/SERDES to the XFP module is shown in Figure 4. The XFI interface is designed to support SONET OC-192, IEEE.Std-802.3ae, 10GFC and G.709(OTU-2) applications. The SERDES is required to meet the applica-tion requirements for jitter generation and transfer when interfaced with a compliant XFP module through an XFP compliant channel. Modules or hosts designed only for 10 Gigabit Ethernet or 10GFC are not required to meet more stringent Telecom jitter requirements. XFI supported data rates are listed in Table 5. XFP compliant module are not required to sup-port all the rates listed in Table 5 in simultaneously.

Standard	Description	Nominal Bit Rate	Units
OC-192/SDH-64	SONET	9.95	Gigabaud
IEEE std-802.3ae	10 Gb/s Ethernet LAN PHY	10.31	Gigabaud
INCITS/T11 Project 1413-D	10GFC	10.52	Gigabaud
ITU G.709(OTU-2)	OC-192 Over FEC	10.70	Gigabaud
Emerging	10Gb/s Ethernet Over G.709	11.09	Gigabaud

Table 5 XFI Supported Data Rates



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- ASIC/SerDes Table 8 and Table 10
- Host Table 12 and Table 14
- Module Table 17 and Table 18.

All XFI transmitters and receivers are AC coupled. XFP modules shall incorporate blocking capacitors on all XFI lines as shown in Figure 5. Re-6 sistor R_p and R_n each have a nominal 50 Ω value, together forming 100 Ω 7 differential input. Some implementation may also use a resistor Rt from 8 the common point to the termination voltage. 9

XFI differential reference impedance for driver, transmission line, and re-10 ceivers are defined as 100 Ohms. XFI common mode reference imped-11 ance for driver, transmission lines, and receivers are specified as 25 12 Ohms. 13

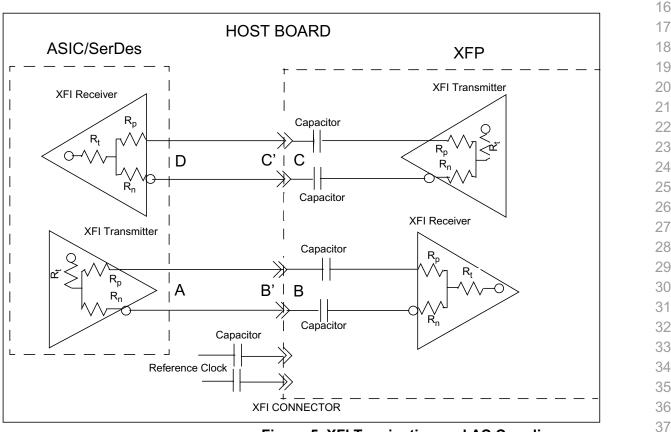


Figure 5 XFI Termination and AC Coupling

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3.4 XFI COMPLIANCE CHANNEL

The XFI compliance channel consists of PCB traces, Vias, and the XFP connector 6.9. The PCB traces differential impedance is recommended to meet $100 \pm 10\Omega$.

The XFI channel has a loss budget of 9.6 dB allocated as shown in <u>Table</u> <u>6</u>. Due to rounding, actual budgets may be slightly different than 9.6 dB.

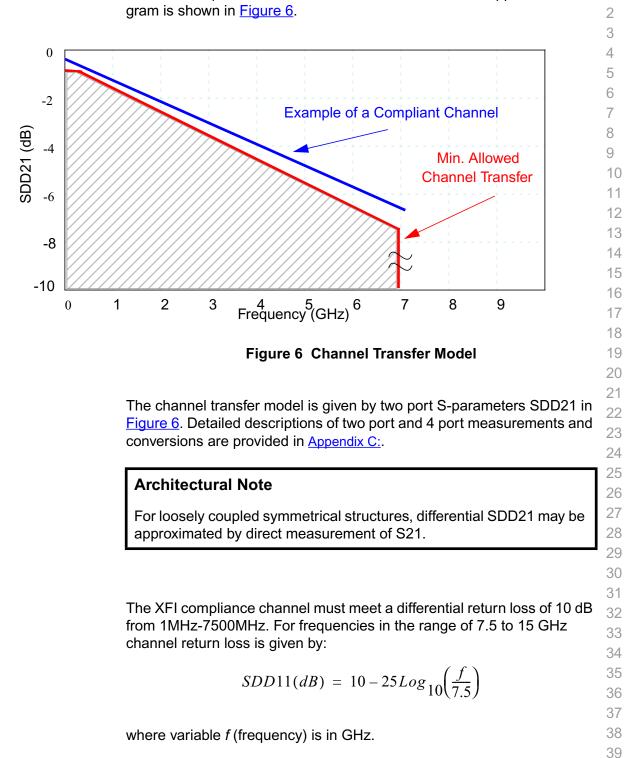
	Table	6)	KFI	Loss	Budget
--	-------	----	-----	------	---------------

Parameter	Symbol	Conditions	Max	Units
Channel Loss Including Connector ¹		at 5.5 GHz	6.0	dB
Channel Crosstalk and Reflection Margin			3.6	dB
Total Channel Loss				dB
1. Loss allocated to the connector is 0.5 dB at 5	5.5 GHz.		•	

Based on measurement and simulation of compliance channel, the worst case channel transfer SDD21 shall meet:

$$SDD21(dB) = (-0.1 - 0.78 \times \sqrt{f} - 0.74 \times f)$$

where the variable *f* (frequency) unit is in GHz. The above equation is specified in terms of two ports S-parameters assuming the channel meets XFI return loss, therefore differential coupling effects may be neglected for insertion loss S21. Please see <u>Appendix C:</u> for differential measurements and conversions.



The above equation is valid from 250MHz to 7 GHz. An approximate dia-1

A host board meeting the Channel Transfer Model given by Figure 6 may 1 be implemented with Microstrip or Stripline. A list of common host board 2 configurations with maximum recommended host PCB trace lengths are 3 listed in Table 7.

Table 7 Host Board Configuration

Туре	Material	Trace Width (mm)	Loss Tan	Copper (oz)	Trace Length (mm)
Microstrip	4000-6	0.3	0.025	1	200
	4000-13	0.3	0.016	1	300
Stripline	4000-6	0.125	0.025	1/2	150
	4000-13	0.125	0.016	1/2	200

Architectural Note

Use of lossy materials or finer traces may be beneficial for short channels since they introduce additional attenuation, which in turn, improves Return Loss.

3.5 XFI ASIC/SERDES SPECIFICATION

XFI ASIC/SerDes specifications are informative. XFI ASIC/SerDes Transmitter specifications at compliance point A are given in <u>3.5.1</u>. XFI ASIC/SerDes Receiver specifications at compliance point D are given in <u>3.5.2</u>.

3.5.1 XFI ASIC/SerDes TRANSMITTER OUTPUT SPECIFICATIONS AT A (INFORMATIVE)

The XFI driver is based on low voltage high speed driver logic with a nominal differential impedance of 100 Ω . The XFI transmitter electrical specifications at compliance point A are given in <u>Table 8</u>. The source must provide both differential and common mode termination for quality signal termination and low EMI.

Return loss at A is measured with the SerDes on a DUT board as shown in A.1.

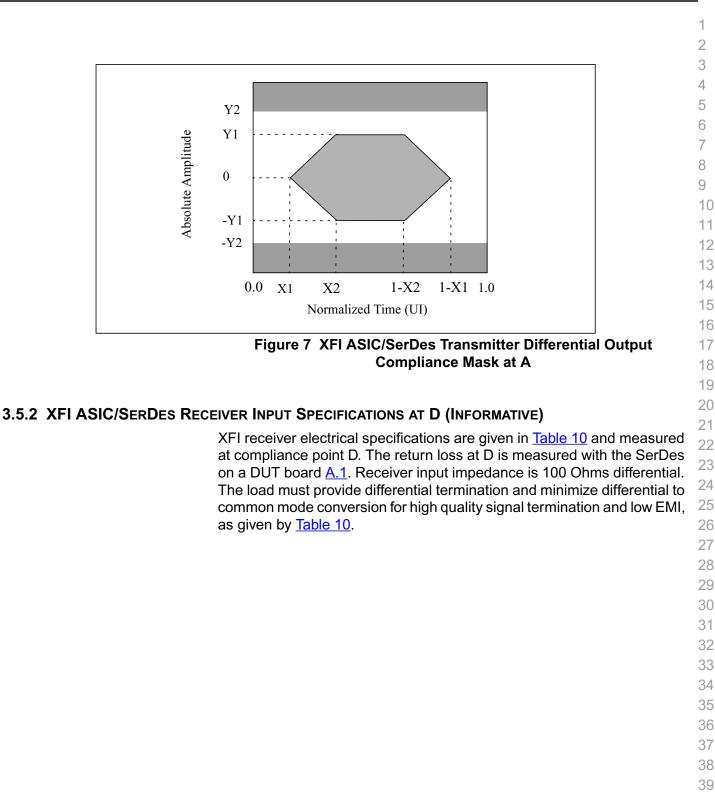
22 23 24

Parameter - A	Symbol	Conditions	Min	Тур	Max	Units
Reference Differential Impedance	Z _d	See Figure 5		100		Ω
Termination Mismatch	$\Delta R_{\rm M}$	See <u>E.6</u> , <u>Figure 5</u>			5	%
DC Common Mode Voltage	Vcm		0		3.6	v
Output Rise and Fall time (20% to 80%)	t _{RH} , t _{FH}		24			ps
Output AC Common Mode Voltage		See <u>E.5</u>			15	mV (RMS)
	CDD00	0.05-0.1 GHz	20			dB
Differential Output Return Loss ¹	SDD22	0.1-7.5 GHz	10			dB
		7.5-15 GHz	see 2			
Common Mode Output Return Loss ²	SCC22	0.1-15 GHz	6			dB
 Return Loss given by equation SDD22(dB) Common mode reference impedance is 25 S 	e		sorb reflecti	ons and n	oise for E	MI.

Table 9 XFI ASIC/SerDes Transmitter Output Jitter Specifications at A

compliance eye mask.

Transmitter - A	Symbol	Conditions	Min	Тур	Max	Units
Determinstic Jitter	DJ	See <u>E.1</u> , 1			0.15	UI (p-p)
Total Jitter	TJ	See <u>E.1</u> , 1			0.30	UI (p-p)
Eye Mask	X1				0.15	UI
Eye Mask	X2				0.4	UI
Eye Mask	Y1		180			mV
Eye Mask	Y2				385	mV
Jitter Generation for Telecom Applications		50KHz to 8 MHz see 2			6.5	mUI (RMS)
1. In loop timing mode, includes jitter that trans conditions.	fers through t	he ASIC from the receive	r during an	y valid op	erational i	nput
2. Measured with a 8 MHz low pass filter with a Optional Synchronous CMU clock, when used it		•	•		ost designe	ed with



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- 42

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Parameter - D	Symbol	Conditions	Min	Тур	Max	Units
Reference Differential Impedance	Z _d	See Figure 5		100		Ω
Termination Mismatch	$\Delta Z_{\rm M}$	See E.6, Figure 5			5	%
AC Common Mode Voltage		See <u>E.5</u>			25	mV (RMS)
		0.05-0.1 GHz	20			dB
Differential Input Return Loss	SDD11	0.1-7.5 GHz	10			dB
		7.5-15 GHz	see 1			
Common Mode Input Return Loss ²	SCC11	0.1-15 GHz	6			dB
Differential to Common Mode Input Conversion ²	SCD11	0.1-15 GHz	12			dB

1. Return Loss given be equation SDD11(dB)= 10 - 16.6 Log10(f/7.5), with f in GHz $\underline{C.4}$.

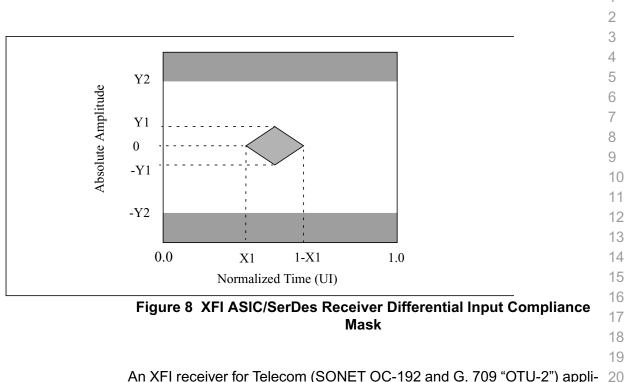
2. Common mode reference impedance is 25 Ω . SCD11 relates to conversion of differential to common mode and the associated generation of EMI C.4

> 20 The XFI jitter specifications at reference D are listed in Table 11 and the 21 compliance mask is shown in Figure 8. The XFI total jitter (TJ) consists of Random Jitter (RJ), Duty Cycle Distortion (DCD), Periodic Jitter (PJ), and 22 Inter symbol Interference (ISI), Total Non-DDJ Jitter is the TJ less the ISI. 23 Only a compliant transmitter passing through the XFI channel is guaran-24 teed for interoperablity. 25

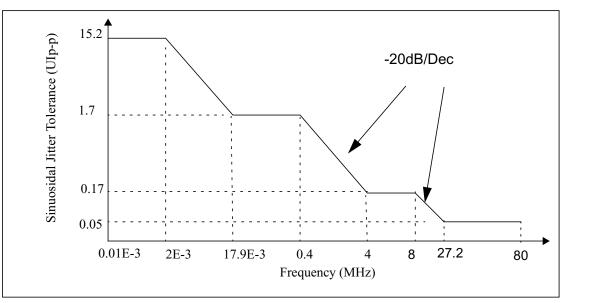
Table 11 XFI ASIC/SerDes Receiver Input Jitter Specifications at D

Receiver- D	Symbol	Conditions	Min	Тур	Max	Units
Total Jitter	TJ	See <u>E.1</u> , <u>E.2</u>			0.65	UI (p-p)
Total Non-DDJ Jitter ¹		See <u>E.1</u> , <u>E.2</u>			0.45	UI (p-p)
Sinusoidal Jitter Tolerance	SJ	<u>E.3</u>			see 2	
Eye Mask	X1	Note ³			0.325	UI
Eye Mask	Y1		55			mV
Eye Mask	Y2	Note ⁴			525	mV
1. Total Jitter less ISI.						
2. Sinuosidal jitter tolerance for Teleco	•	tively given by Figure 9	and Figure	<u>10</u> .		
3. Mask coordinate X1=0.225 if total	non-DDJ is measured.					

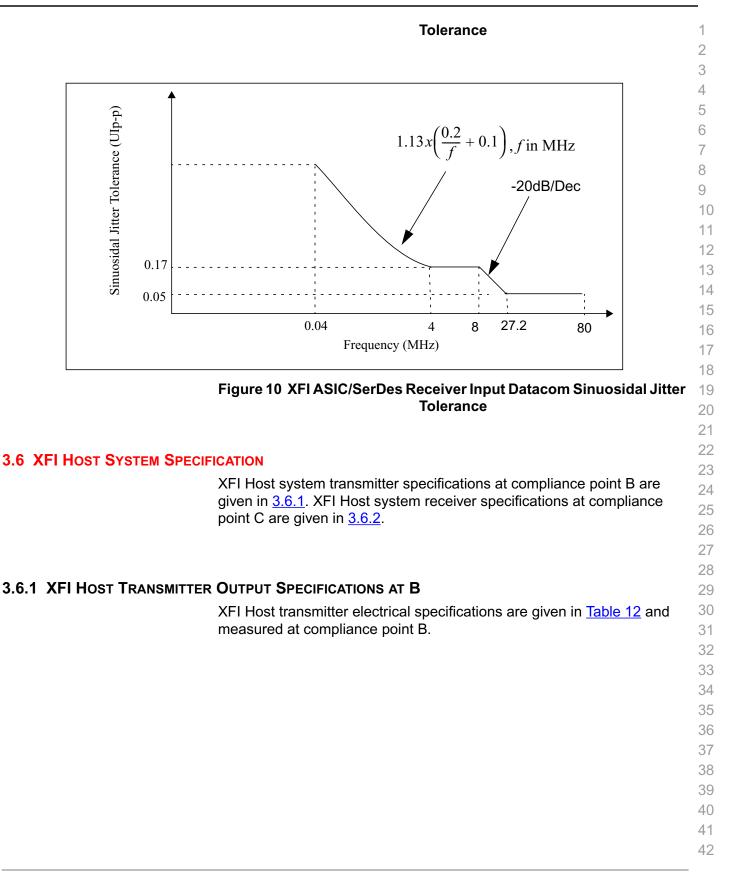
4. Out of 525 mV, 100 mV is allocated for multiple reflection.



An XFI receiver for Telecom (SONET OC-192 and G. 709 "OTU-2") appli-20 cations must meet jitter tolerance given by Figure 9 with the addition of input jitter given by Table 11. An XFI receiver for Datacom (Ethernet 802.3ae or Fibre Channel 10GFC) must meet the jitter tolerance given by Figure 10 with the addition of random and deterministic jitter given by Table 11. 22







Parameter - B	Symbol	Conditions	Min	Тур	Max	Units
Reference Differential Impedance	Z _d			100		Ω
Termination Mismatch	$\Delta Z_{\rm M}$	See <u>E.6</u> , <u>Figure 5</u>			5	%
DC Common Mode Voltage	Vcm		0		3.6	V
Output AC Common Mode Voltage		See <u>E.5</u>			25	mV (RMS)
		0.05-0.1 GHz	20			dB
Differential Output Return Loss	SDD22	0.1-5.5 GHz	8			dB
		5.5-12 GHz	see 1			
Common Mode Output Return Loss ²	SCC22	0.1-15 GHz	3			dB

2. Common mode reference impedance is 25Ω . Common Mode Input return loss helps absorb reflections and noise reducing EMI.

The XFI jitter specifications at reference point B are listed in <u>Table 13</u> and the compliance mask is shown in <u>Figure 11</u>. The XFI total jitter (TJ) consist of Random Jitter (RJ), Duty Cycle Distortion (DCD), Periodic Jitter (PJ), and Inter symbol Interference (ISI), Total Non-DDJ Jitter is the TJ less the ISI. Only a compliant transmitter passing through the XFI channel is guaranteed for interoperablity.

Table 13 XFI Host Transmitter Output Jitter Specifications at B

Receiver- B	Symbol	Conditions	Min	Тур	Max	Units
Total Jitter ^{1,}	TJ	See <u>E.1</u>			0.61	UI
Total Non-DDJ Jitter ^{1,2}		See <u>E.1</u> , <u>E.2</u>			0.41	UI
Eye Mask	X1	see 3			0.305	UI
Eye Mask	Y1		60			mV
Eye Mask	Y2	see 4			410	mV
Jitter Generation at B Telecom Applications		50KHz-8MHz			7	mUI (RMS)

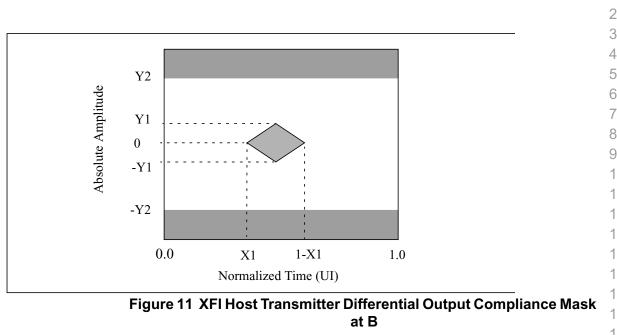
1. In loop timing mode, includes jitter that transfers through ASIC from the receiver during any valid operational input conditions.

2. Total jitter less the ISI.

3. Mask cordinate X1=0.205 if total non-DDJ is measured.

4. Out of 410 mV, 25 mV is allocated for multiple reflection.

5. Measured with a 8 MHz low pass filter with a -20 dB/Dec of rolloff up to 80 MHz. Does not apply to a host desinged with Optional Synchronous CMU clock, when used in conjunction with a Synchronous CMU Signal Conditioner module see <u>3.9.1</u>.



3.6.2 XFI HOST RECEIVER INPUT SPECIFICATIONS AT C

The XFI Host receiver electrical specifications at compliance point C are given in <u>Table 14</u>. The load must provide differential termination and minimize differential to common mode conversion for quality signal termination and low EMI, as given in <u>Table 14</u>.

Return loss at compliance point C is measured with the Host Test Board plugged into the host as shown in <u>A.2</u>.

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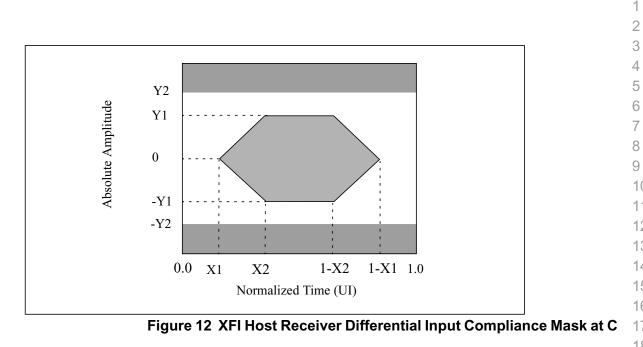
Parameter - C	Symbol	Conditions	Min	Тур	Max	Units
Reference Differential Impedance	Z _d	See Figure 5		100		Ω
Termination Mismatch	$\Delta Z_{\rm M}$	See <u>E.6</u> , <u>Figure 5</u>			5	%
Source to Sink DC Potential Difference	Vcm		0		3.6	V
Input AC Common Mode Voltage		See <u>E.5</u>			15	mV (RMS)
Input Rise and Fall time (20% to 80%)	t _{RH} , t _{FH}		24			ps
		0.05-0.1 GHz	20			dB
Differential Input Return Loss	SDD11	0.1-5.5 GHz	8			dB
		5.5-12 GHz	see 1			
Common Mode Return Loss ²	SCC11	0.1-15 GHz	3			dB
Differential to Common Mode Conversion ²	SCD11	0.1-15 GHz	10			dB

able 14 VEL Hest Bessiver Input Electrical Specifications at C

Transmitter jitter specifications are listed in Table 15. Figure 12 gives the host compliance eye mask.

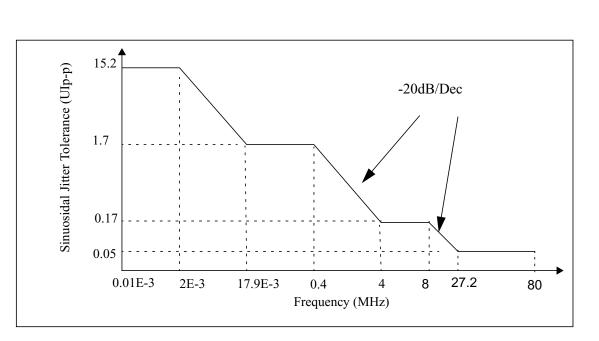
Table 15 XFI Host Receiver Input Jitter Specifications at C

Transmitter - C	Symbol	Conditions	Min	Тур	Max	Units
Determinstic Jitter	DJ	See <u>E.1</u>			0.18	UI (p-p)
Total Jitter	TJ	See <u>E.1</u>			0.34	UI (p-p)
Sinusoidal Jitter Tolerance	SJ	<u>E.3</u>			see 1	
Eye Mask	X1				0.17	UI
Eye Mask	X2				0.42	UI
Eye Mask	Y1		170			mV
Eye Mask	Y2	see 2			425	mV
1. Sinuosidal jitter tolerance for Telecom and I	Datacom respec	tively given by Figure 1	<u>3</u> and <u>Figure</u>	<u>• 14</u> .	1	1
2. Out of 425 mV, 25 mV is allocated for mult	iple reflections					



The XFI receiver for Telecom (SONET OC-192 and G. 709 "OTU-2") applications must meet the jitter tolerance with the addition of deterministic and random jitter given by <u>Table 15</u>. The XFI receiver for Datacom (Ethernet 802.3ae or Fibre Channel 10GFC) Host must meet jitter tolerance given by <u>Figure 14</u> with the addition of deterministic and random jitter given by <u>Table 15</u>.







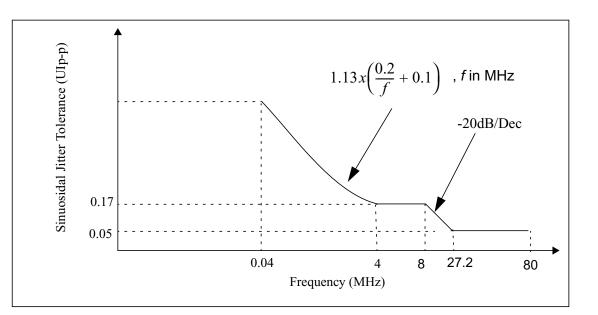


Figure 14 XFI Host Receiver Input Datacom Sinuosidal Jitter Tolerance

3.7 XFI MODULE SPECIFICATI	IONS	1
	XFI Module Transmitter specifications at compliance point B' are given in $3.7.1$. XFI Module Receiver specifications at compliance point C' are given in $3.7.2$.	2 3 4 5 6
3.7.1 XFI MODULE TRANSMIT	TER INPUT SPECIFICATIONS AT B'	7
	The XFI module transmitter electrical specifications are given in <u>Table 16</u> , measured at compliance point B' as shown in <u>A.3</u> . The receiver input impedance is 100 Ohms differential. The load must provide differential termination and minimize differential to common mode conversion for quality signal termination and low EMI, as given in <u>Table 16</u> . The XFI jitter specifications at reference point B' are listed in <u>Table 17</u> and the compliance mask is shown in <u>Figure 15</u> . The XFI total jitter (TJ) consists of Random Jitter (RJ), Duty Cycle Distortion (DCD), Periodic Jitter	8 9 10 11 12 13 14 15
	(PJ), and Inter symbol Interference (ISI), Total Non-DDJ Jitter is the TJ less the ISI. Only a compliant transmitter passing through the XFI channel is guaranteed for interoperability.	16 17 18 19
	Return loss at compliance point B' is measured with the Module Test Board plugged into the host as shown in <u>A.3</u> .	20 21
		22 23 24
		25 26
		27 28 29
		30 31 32 33
		34 35
		36 37 38
		39 40 41
		42

Parameter - B'	Symbol	Conditions	Min	Тур	Max	Units
Reference Differential Input Impedance	Z _d	See Figure 5		100		Ω
Termination Mismatch	$\Delta Z_{\rm M}$	See <u>E.6</u> , <u>Figure 5</u>			5	%
Source to Sink DC Potential Difference	Vcm		0		3.6	V
Input AC Common Mode Voltage		See <u>E.5</u>			25	mV (RMS)
		0.05-0.1 GHz	20			dB
Differential Input Return Loss	SDD11	0.1-5.5 GHz	8			dB
		5.5-12 GHz	see 1			
Common Mode Input Return Loss ²	SCC11	0.1-15 GHz	3			dB
Differential to Common Mode Conversion ²	SCD11	0.1-15 GHz	10			dB

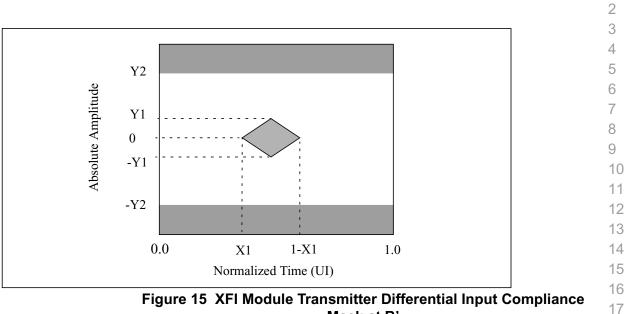
Table 17 XFI Module Transmitter Input Jitter Specifications at B'

Receiver- B'	Symbol	Conditions	Min	Тур	Max	Units
Total Non-DDJ Jitter ¹	0.41	See <u>E.1</u> , <u>E.2</u>			0.41	UI (p-p)
Total Jitter	TJ	See <u>E.1</u> , <u>E.2</u>			0.61	UI (p-p)
Sinusoidal Jitter Tolerance	SJ	<u>E.3</u>			see 2	
Eye Mask	X1	see 3			0.305	UI
Eye Mask	Y1		60			mV
Eye Mask	Y2	see 4			410	mV
1. Total Jitter less ISI.	II			1	1 1	
2. Sinuosidal jitter tolerance for Telecom	and Datacom respe	ctively given by Figure	<u>16</u> and <u>Figu</u>	<u>re 17</u> .		
3. Mask cordinate X1=0.205 if total non-	DDJ is measured.					
4. Out of 410 mV, 50 mV is allocated for	multiple reflection					

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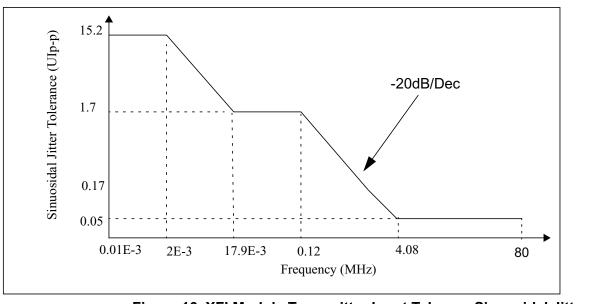
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Mask at B'

XFI Module for Telecom (SONET OC-192 and G. 709 "OTU-2") applications must meet the jitter tolerance given by Figure 16 with addition of input jitter given by Table 17. The XFI Module for Datacom (Ethernet 802.3ae and Fibre Channel 10GFC) must meet the jitter tolerance given by Figure 17 with the addition of random and deterministic jitter given in Table 17.





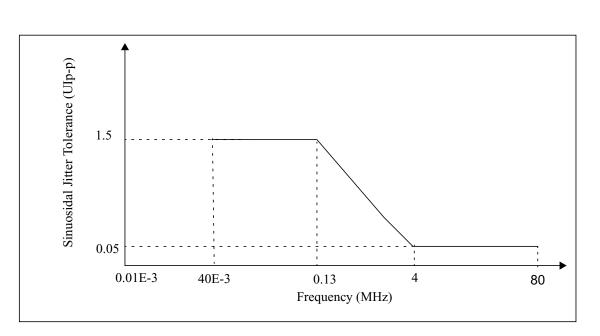


Figure 17 XFI Module Transmitter Input Datacom Margin Mask

3.7.2 XFI MODULE RECEIVER OUTPUT SPECIFICATIONS AT C'

The XFI transmitter electrical specifications at compliance point C' are given in <u>Table 18</u>. The source must provide differential termination and common mode termination for quality signal termination and low EMI, as given in <u>Table 18</u>.

Return loss at C' is measured with the module on a Module Compliance Test Board $\underline{A.3}$.

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Parameter - C	Symbol	Conditions	Min	Тур	Max	Units
Reference Differential Output Impedance	Z _d	See Figure 5		100		Ω
Termination Mismatch	$\Delta Z_{\rm M}$	See <u>E.6</u> , <u>Figure 5</u>			5	%
DC Common Mode Potential	Vcm		0		3.6	v
Output AC Common Mode Voltage		See <u>E.5</u>			15	mV (RMS)
Output Rise and Fall time (20% to 80%)	t _{RH} , t _{FH}		24			ps
		0.05-0.1 GHz	20			dB
Differential Output Return Loss	SDD22	0.1-5.5 GHz	8			dB
		5.5-12 GHz	see 1			dB
Common Mode Output Return Loss ²	SCC22	0.1-15 GHz	3			dB

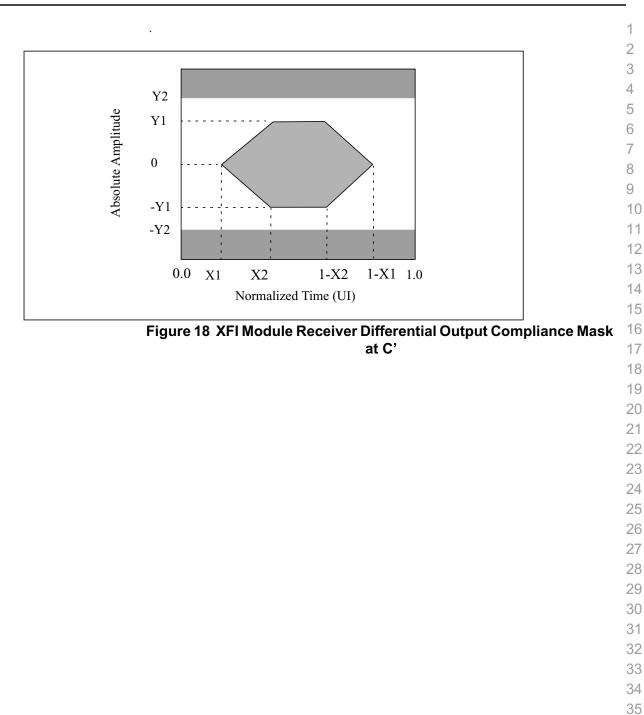
Transmitter jitter specifications are listed in Table 19. Figure 18 gives the compliance eye mask.

Table 19 XFI Module Receiver Output Jitter Specifications at C'

Transmitter - C	Symbol	Conditions	Min	Тур	Max	Units
Determinstic Jitter	DJ	See <u>E.1</u> , 1			0.18	UI (p-p)
Total Jitter	TJ	See <u>E.1</u> , 1			0.34	UI (p-p)
Eye Mask	X1				0.17	UI
Eye Mask	X2				0.42	UI
Eye Mask	Y1		170			mV
Eye Mask	Y2				425	mV
1. Includes jitter transfered from the opt	ical receiver during a	ny valid operational inpu	it condition.	1	1	1

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3.8 SIGNAL CONDITIONER		1
	The XFI Signal Conditioner is an active device that overcomes host board	2
	and connector signal degradations by reshaping, regenerating, and atten- uating jitter. The XFP module shall include a Signal Conditioner based on	3 4
	CDR (Clock Data Recovery) technology for complete regeneration. An	5
	optional CMU (Clock Multiplier Unit) based regenerator, which requires a clean frequency locked clock provided by the host XFI interface, is defined	6
	as well.	7
	The telecom XFI signal conditioner must meet SONET OC-192 and	8 9
	G.709 (OTU-2) specifications, while the datacom signal conditioner must	10
	meet IEEE 802.3ae and 10 GFC specifications. The following sections de-	
	fine the signal conditioner for each application. A common signal condi- tioner meeting telecom and datacom specifications is desirable, but not	12
	mandatory.	13 14
		15
3.8.1 TELECOM MODULE		16
	The XFP Telecom module must meet SONET OC-192 per GR-253 and G.	17
	709 (OTU-2) requirements.	18 19
	The XFP Telecom module transmitter shall meet the requirements of both	20
	SONET GR-253 and <u>Table 20</u> .	21
Table 20	XFP Telecom Module Transmitter Requirement	22
	· · · · · · · · · · · · · · · · · · ·	23

Module Transmitter B'	Symbol	Conditions	Min	Тур	Max	Units
Jitter Transfer Bandwidth	BW	PRBS 2 ^{^31} -1 Data, see 1			8	MHz
Jitter Peaking		Frequency <120 KHz see 2			0.03	dB
		Frequency >120 KHz see 3			1	dB
Module Jitter Generation at Optical Output		Measured 50KHz-80MHz see 4			10 100	mUI (RMS) mUI (p-p)
1. OC-192/SDH-64 Sinusoidal Jitter To	lerance Mask		•			
2. Only required for loop timing, see E	.4.					
3. Does not apply to the optional CMU		<u>L</u> .				
4. In the CDR mode the host is contributed	uting 7 mUI (F	RMS) and 50 mUI (p-p) jitter fro	m 50KHz-8	8 MHz <mark>Tabl</mark>	<u>e 13</u> . In Cl	MU mode it is

4. In the CDR mode the host is contributing 7 mUI (RMS) and 50 mUI (p-p) jitter from 50KHz-8 MHz <u>Table 13</u>. In CMU mode it is assumed that worst case phase noise given by <u>Table 25</u>. Jitter generation of an optical transmitter must include jitter that transfers from the host during any valid operational conditions.

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The XFP Telecom modules receiver shall meet the requirements of both SONET GR-253 and Table 21.

Table 21 XFP Telecom Module Receiver Requirement

Module Transmitter C'	Symbol	Conditions	Min	Тур	Max	Units
Jitter Transfer Bandwidth	BW	PRBS 2^{31} -1 Data, see 1			8	MHz
Jitter Peaking		Frequency <120 KHz see 2			0.03	dB
		Frequency >120 KHz			1	dB
1. OC-192/SDH-64 Sinusoidal Jitter Tole	rance Mask					
2. Only required for loop timing, see $\underline{E.4}$						

3.8.2 DATACOM MODULE

XFP Datacom module shall meet IEEE 802.3ae and 10 GFC requirement, in addition to the requirements given in Table 20 and Table 21.

Table 22 XFP Datacom Module Transmitter Requirement

Module Transmitter B'	Symbol	Conditions	Min	Тур	Max	Units	
Jitter Transfer Bandwidth	BW	PRBS 2 ^{^31} -1 Data or Scram- bled 64B/66B, see 1			8	MHz	
Jitter Peaking		Frequency >50 KHz			1	dB	
1. Based on IEEE 802.3ae Clause 52 Sinuosidal Jitter Tolerance Mask Figure 52-4.							

Table 23 XFP Datacom Module Receiver Requirement

Symbol	Conditions	Min	Тур	Max	Units
BW	PRBS 2 ^{^31} -1 Data or Scrambled 64B/66B, see 1			8	MHz
	Frequency >50 KHz			1	dB
inuosidal Jitte	er Tolerance Mask Figure 52-4.			1	
	BW	BW PRBS 2 ³¹ -1 Data or Scrambled 64B/66B, see 1	BW PRBS 2 ^{\lambda 31} -1 Data or Scrambled 64B/66B, see 1 Frequency >50 KHz	BW PRBS 2^{31}-1 Data or Scrambled 64B/66B, see 1 Frequency >50 KHz	BWPRBS 2^{31} -1 Data or Scrambled 64B/66B, see 18Frequency >50 KHz1

3.9 REFERENCE CLOCK SPECIFICATIONS

The host system shall supply a reference clock to the XFP module with a frequency of +/-100 PPM of Baudrate/64 with specifications listed in Table 24. The Signal Conditioners in the XFP module may use the reference clock for VCO centering. The reference clock is intended for VCO centering so jitter requirements are intentionally relaxed to allow implementation flexibility on the host board.

Parameter	Symbol	Conditions	Min	Тур	Max	Units
Clock Differential Input impedance	Z _d		80	100	120	Ω
Differential Input Clock Amplitude (p-p)		AC Coupled PECL	640		1600	mV
Reference Clock Duty Cycle			40		60	%
Reference Clock Rise/Fall Time	Tr/Tf	20%-80%	200		1250	ps
Reference Clock Frequency	f_0			Baud ¹ /64		MHz
RMS Jitter Random Jitter	σ	Up to 100 MHz			10	ps
Reference Clock Frequency Tolerance	Δf		-100		100	PPM
1. Reference clock frequency is not locked to	the data free	quency and may deviat	e by Δf.			

Table 24 Reference Clock Specifications

3.9.1 OPTIONAL SYNCHRONOUS CMU CLOCK

The host system may optionally supply a synchronous reference clock to the XFP module, with frequency exactly equal to the Baudrate/64 according to the specifications listed in <u>Table 25</u>. The transmitter Signal Conditioners in the XFP module may use the synchronous clock to retime the data.

In order to select Optional Synchronous CMU clock, bit 0 of Byte 1, in the two wire interface Table 34 must be set high. A CDR based module may be used in conjunction with a synchronous clock from the host see 5.3.

Architectural Note

In applications where the Host System uses the XFP module in the optional CMU mode, the Host must provide a synchronous low phase noise clock.

Parameter	Symbol	Conditions	Min	Тур	Max	Units
Clock Differential Input impedance	Z _d		80	100	120	Ω
Differential Input Clock Amplitude (p-p)		AC Coupled PECL	640		1600	mV
Reference Clock Duty Cycle			40		60	%
Reference Clock Rise/Fall Time	Tr/Tf	20%-80%	200		1250	ps
Reference Clock Frequency	f_0	see 1		Baud ¹ /64		MHz
CMU Reference Clock Skew	TD	Baud ²	-10		+10	UI
Single Side Band Phase Noise		@1KHz			-85	dBc/
		@10KHz			-108	Hz
		@100KHz			-128	
		@1MHz			-138	
		@10MHz			-138	
2. A UI defined by the serial Baudrate.						

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CHAPTER 4: XFP 2-WIRE INTERFACE PROTOCOL

4.1 INTRODUCTION

Low speed signaling is based on Low Voltage TTL (LVTTL) operating at Vcc3 at a nominal supply of $(3.3V \pm 5\%)$. Hosts shall use a pull-up resistor connected to a host_Vcc of +3.3 volts (3.15 to 3.45 volts) on the 2-wire interface SCL (clock) and SDA (Data) signals. Detailed electrical specification are given in section <u>2.5</u>.

4.2 XFP 2-WIRE TIMING DIAGRAM

XFP is positioned to leverage 2-wire timing (Fast Mode devices) to align the use of related cores on host ASICs. XFP 2-wire bus timing is shown in <u>Figure 19</u>. XFP AC specifications are given in <u>Table 26</u>.

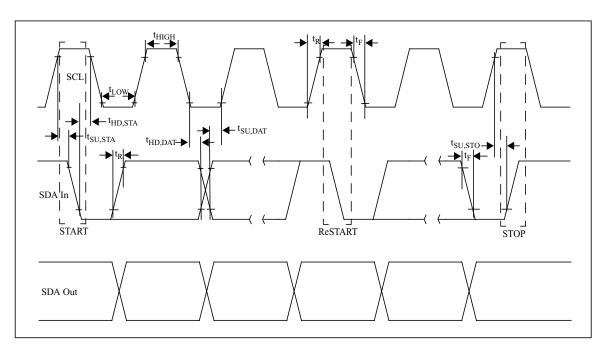


Figure 19 XFP Timing Diagram

Before initiating a 2-wire serial bus communication, the host shall provide setup time (Host select_setup - table 26) on the Mod_DeSel line of all modules on the 2-wire bus. The host shall not change the Mod_DeSel line of any module until the 2-wire serial bus communication is complete and the hold time requirement (Host_select_hold - <u>Table 26</u>) is satisfied.

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The 2-wire serial interface address of the XFP module is 1010000X (A0h). 1 In order to allow access to multiple XFP modules on the same 2-wire serial bus, the XFP pinout includes a Mod_DeSel or module deselect pin. This pin (which is pulled high or deselected in the module) must be held low by the host to select the module of interest and allow communication over the 2-wire serial interface. The module must not respond to or accept 2-wire serial bus instructions unless it is selected.

11 **Parameter Symbol** Min. Max. Unit **Conditions** 12 400 Clock Frequency 0 kHz f_{SCL} 13 Clock Pulse Width Low 1.3 14 μs tLOW 15 Clock Pulse Width High 0.6 μs t_{HIGH} 16 Time bus free before new trans-1.3 Between STOP and START μs t_{BUF} 17 mission can start 18 START Hold Time 0.6 μs t_{HD,STA} 19 START Set-up Time 0.6 μs t_{SU,STA} 20 21 Data In Hold Time 0 t_{HD.DAT} μs 22 0.1 Data In Set-up Time μs t_{SU.DAT} 23 From $(V_{IL,MAX} - 0.15)$ to $(V_{IH,MIN} + 0.15)$ Input Rise Time (100kHz) 1000 ns $t_{R,100}$ 24 Input Rise Time (400kHz) 300 ns From $(V_{IL,MAX} - 0.15)$ to $(V_{IH,MIN} + 0.15)$ 25 t_{R,400} 26 Input Fall Time (100kHz) 300 From $(V_{IH,MIN} + 0.15)$ to $(V_{IL,MAX} - 0.15)$ ns t_{F.100} 27 Input Fall Time (400kHz) 300 From $(V_{IH,MIN} + 0.15)$ to $(V_{IL,MAX} - 0.15)$ t_{F,400} ns 28 STOP Set-up Time 0.6 μs t_{SU,STO} 29 Host Supplied Module DeSe-2 Setup time on the select lines before start of a 30 Host_select_setup ms lect Setup Time host initiated serial bus sequence 31 Host Supplied Module DeSe-Host_select_hold 10 μs Delay from completion of a serial bus 32 lect Hold Time sequence to changes of transceiver select sta-33 tus 34 Aborted sequence - bus release Deselect_Abort 2 Delay from a host asserting Mod_DeSel (at ms 35 any point in a bus sequence), to the XFP mod-36 ule releasing SCL and SDA

Table 26 XFP 2-Wire Timing Specifications

4.3 MEMORY TRANSACTION TIMING

XFP memory transaction timings are given in <u>Table 27</u>. Single Byte writable memory blocks are given in <u>Table 28</u>. Multiple Byte writable memory blocks are given in <u>Table 29</u>.

Table 27 XFP Memory Specifications

			- , - 1			-
Parameter	Symbol	Min.	Max.	Unit	Conditions	8
Serial Interface Clock Holdoff "Clock Stretching"	T_clock_hold		500	μs	Maximum time the XFP module may hold the SCL line low before continuing with a read or write operation	
Complete Single or Sequential Write	t _{WR}		10	ms	Complete (up to) 4 Byte Write	
Endurance (Write Cycles)		50 k		cycles	70 °C	
			1	1	1	

Table 28 Single Byte Writable Memory Blocks

Byte Address	Volatile or NV	Description	
1	V	Signal Conditioner Control Register	
110	V	General Control Bits	
118	V	Packet Error Checking Control	
127	V	Table Select Byte	

Table 29 Multiple Byte Writable Memory Blocks

Byte Address	# Bytes	Volatile or NV	Description	
72-73	2	V	Wavelength Control Registers	
76 – 77	2	V	FEC Control Registers	
88 - 93	6	V	Interrupt Masking Bits	
119-122	4	V	Password Change Entry	
123-126	4	V	Password Entry	
128 - 255	128	NV	Table 02h – Customer Writable	
		1		

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4.4 DEVICE ADDRESSING AND OPERATION 2 Serial Clock (SCL): The host supplied SCL input to XFP transceivers is used to positively edge clock data into each XFP device and negative clock data out of each device. The SCL line may be pulled low by an XFP 4 module during clock stretching. 5 6 Serial Data (SDA): The SDA pin is bi-directional for serial data transfer. 7 This pin is open-drain or open-collector driven and may be wire-ORed 8 with any number of open-drain or open collector devices. 9 Master/Slave: XFP transceivers operate only as slave devices. The host 10 must provide a bus master for SCL and initiate all read/write communica-11 tion. 12 13 **Device Address:** Each XFP is hard wired at the device address A0h. See 14 XFP MSA Chapter 5: Management interface for memory structure within 15 each transceiver. 16 Multiple Devices per SCL/SDA: While XFP transceivers are compatible 17 with point-to-point SCL/SDA, they can also be paralleled on a single 18 SCL/SDA bus by using the XFP Mod_DeSel line. See section 2.4.2 and 19 Table 26 for more information. 20 21 Clock and Data Transitions: The SDA pin is normally pulled high with an 22 external device. Data on the SDA pin may change only during SCL low time periods. Data changes during SCL high periods indicate a START or 23 STOP condition. All addresses and data words are serially transmitted to 24 and from the XFP in 8-bit words. Every byte on the SDA line must be 8-25 bits long. Data is transferred with the most significant bit (MSB) first. 26 27 START Condition: A high-to-low transition of SDA with SCL high is a 28 START condition, which must precede any other command. 29 STOP Condition: A low-to-high transition of SDA with SCL high is a 30 STOP condition. 31 32 Acknowledge: After sending each 8-bit word, the transmitter releases the 33 SDA line for one bit time, during which the receiver is allowed to pull SDA 34 low (zero) to acknowledge (ACK) that it has received each word. Device 35 address bytes and write data bytes initiated by the host shall be acknowledged by XFP transceivers. Read data bytes transmitted by XFP trans-36 ceivers shall be acknowledged by the host for all but the final byte read. 37 for which the host shall respond with a STOP instead of an ACK. 38 39 Memory (Management Interface) Reset: After an interruption in pro-40 tocol, power loss or system reset the XFP management interface can be 41 reset. Memory reset is intended only to reset the XFP transceiver man-

XFP Spec Revison 3			X	FP 2-Wire In	terface Proto	col		April 2, 2003		
			-	agement interface (to correct a hung bus). No other transceiver functio ality is implied.						
			1) (Clock up to	9 cvcles.					
			,	ook for SD	•	ach cycle w	hile SCL is	hiah.		
				Create a ST	-	-				
			following address	a start cor word consi	dition to en sts of a ma	able a read ndatory on	d or write op e zero sequ	evice address word peration. The device uence for the first to all XFP devices	Э	
			Tabl	e 30 XFP	Device Ad	dress				
	1	0	1	0	0	0	0	R/W		
	MSB			I	1	1	1	LSB		
			A read of initiated Mod_De	peration is if this bit is	initiated if t set low. Up ow state) th	his bit is se on compar ne XFP tran	et high and te of the devisceiver sha	operating select bit a write operation is vice address (with all output a zero		
	-	Functiona								
I.5.1 P	ACKET ER	ROR CHECH		on to the ba	sic 120 rea	d/write fund	rtionality al	I XFP modules sha	1	
								s below. The packet		

support packet error checking defined in the sections below. If 29 error checking system may be enabled or disabled by the host system, and will default to being disabled on power-up or reset. Packet error 30 checking allows the host system to confirm the validity of any read data 31 including the address from which the read originated. Packet error 32 checking also allows the XFP module to determine the validity of write 33 data and to reject write commands with errors. Finally, the host may use 34 the system to determine if a write communication was successful. All 35 packet error checking operations involve the calculation of a CRC-8 value by the module and host. The CRC-8 value is the cyclical redundancy 36 check as defined in the SMBUS 2.0 standard. 37

4.5.2 XFP MEMORY ADDRESS COUNTER (READ AND WRITE OPERATIONS)

XFP devices maintain an internal data word address counter containing40the last address accessed during the latest read or write operation, incre-41mented by one. The address counter is incremented whenever a data42

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word is received or sent by the transceiver. This address stays valid between operations as long as XFP power is maintained. The address "roll 2 over" during read and write operations is from the last byte of the 128 byte 3 memory page to the first byte of the same page.

4.5.3 READ OPERATIONS (CURRENT ADDRESS READ)

A current address read operation requires only the device address read word (10100001) be sent, Figure 20. Once acknowledged by the XFP, the current address data word is serially clocked out. The host does not respond with an acknowledge, but does generate a STOP condition once the data word is read.

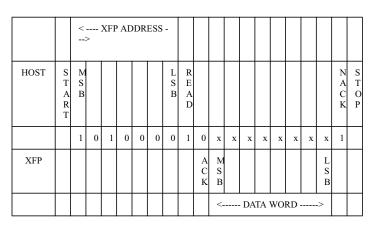


Figure 20 XFP Current Address Read Operation

4.5.4 READ OPERATIONS (RANDOM READ)

A random read operation requires a "dummy" write operation to load in the target byte address Figure 21. This is accomplished by the following sequence: The target 8-bit data word address is sent following the device address write word (10100000) and acknowledged by the XFP. The host then generates another START condition (aborting the dummy write without incrementing the counter) and a current address read by sending a device read address (10100001). The XFP acknowledges the device address and serially clocks out the requested data word. The host does not respond with an acknowledge, but does generate a STOP condition once the data word is read.

		<		XFI	P AE	DDR	ESS	5 -			<	N	1EN	10R	ΥA	DDF	RES	s			<		XFP	AĽ	DDR	ESS	-													
			>									.>									>	>																		
HOST	s	М						L	W		N							L		s	М						L	R										N	S	-
	TA	S						S B	R		S							S B		T A	S						S B	E A										A	T O	
	R	Б							I									D		R	Б						Б	D										ĸ	P	
	T								Т											Т																				
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		1	0	1	0	0	0	0	0	0	x	x	x	x	x	x	x	x	0		1	0	1	0	0	0	0	1	0	x	x	x	x	x	x	x	x	1		
XFP										A									А										А								L]
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																		Fig	gu	re	21		XF	Ρ	Ra	ind	lo	m	Re	eac	k									

4.5.5 READ OPERATIONS (SEQUENTIAL READ)

Sequential reads are initiated by either a current address read Figure 22 or a random address read Figure 23. To specify a sequential read, the 20 host responds with an acknowledge (instead of a STOP) after each data word. As long as the XFP receives an acknowledge, it shall serially clock 21 out sequential data words. The sequence is terminated when the host re- 22 sponds with a NACK and a STOP instead of an acknowledge. 23

																																							25
																																							26
		< ;	 >	XFI	PAE	DDR	ESS	5 -																															27
HOST	s	М						L	R										A									А									N	s	28
	T A	S B						S B											C K									C K									A C	T O	29
	R T								D																												K	Р	30
																																							31
		1	0	1	0	0	0	0	1	0	х	x	x	х	x	х	X	x	0	х	x	x	X	х	x	x	x	0	х	x	X	x	x	x	X	x	1		32
XFP										A C	M S							L S		M S	1						L S		M S							L S			33
										ĸ								B		B							B		B							B			34
											<		DAT	ΆV	VOR	D n		>		<	I	DAT			D n-	+1 -			<.]	DAT		VOR	D n	+x -				35
																							-	>								-	>						36

37 Figure 22 Sequential Address Read Starting at XFP Current Address

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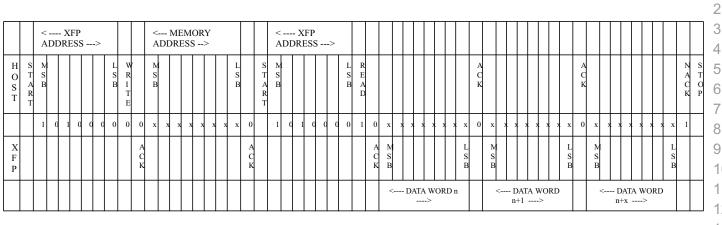


Figure 23 Sequential Address Read Starting with Random XFP Read

4.5.6 READ OPERATION PACKET ERROR CHECKING

Only Random Read and Random Sequential Read will be supported for packet error checking. The XFP CRC-8 calculation requires an explicit starting memory address be incorporated as the first byte processed by the algorithm, followed by all data bytes. After the host signals the end of a read operation with a NACK, the CRC-8 value will be sent by the XFP module. The host will follow with another NACK and STOP to complete the READ operation. XFP read operation with packet error checking is illustrated in Figure 24. The CRC-8 value is calculated on the starting memory address (MSB first) followed by the Read Bytes in the order they are sent. The host may then verify the CRC-8 value and reject the read if the CRC-8 value does not correspond to the received data and desired Read address. Note the XFP address itself is not included in the CRC-8 calculation.

		< - AI				>								MO SS								DD			>																							
H C S F	S T A R T	M S B						L S B	R		N S E							L S B		S T A R T	S B	[L S B	R E A D										A C K									A C K	
		1	0	1	0	0	0	0	0	C	x	x	x	××	x	x	x	x	0		1	0	1	0	0	0	0	1	0	x	x	x	x	x	x	x	x	0	x	x	x	x	x	x	x	x	0	C o n t - >
X F P										 (A C K										A C K	M S B							L S B		M S B							L S E		
																														<-	I	DAT	4 W ->		D n		-		<]	DAT	ΓΑ V		RD	0 n+1	1		
H C S T									N A C K									N A C K	T O																													
	x	x	x	x	x	x	x	x	1	x	x	x	x	x	x	x	x	1																														
X F P	M S B							L S B		I S E							N S B																															
-	<	I	DAT	ΆV		RD	n+ :	ĸ		<	ا	- Cl		8 V.	ALU	JЕ -																																

Figure 24 XFP READ OPERATION PACKET ERROR CHECKING

4.5.7 WRITE OPERATIONS (BYTE WRITE)

A write operation requires an 8-bit data word address following the device address write word (10100000) and acknowledgement Figure 25. Upon receipt of this address, the XFP shall again respond with a zero (ACK) to acknowledge and then clock in the first 8 bit data word. Following the re-34 ceipt of the 8 bit data word, the XFP shall output a zero (ACK) and the host master must terminate the write sequence with a STOP condition for the 35 write cycle to begin. If a START condition is sent in place of a STOP con-36 dition (i.e. a repeated START per the I²C specification) the write is aborted 37 and the data received during that operation is discarded. Upon receipt of 38 the proper STOP condition, the XFP enters an internally timed write cycle, t_{WR} , to internal memory. The XFP disables it's management interface input during this write cycle and shall not respond or acknowledge subse-41 quent commands until the write is complete. Note that I²C "Combined

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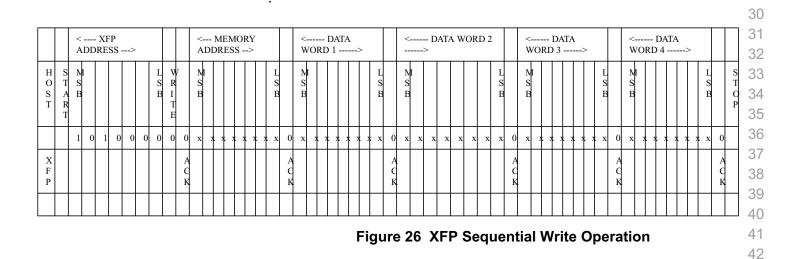
Format" using repeated START conditions is not supported on XFP write 1 commands. 2

		<		XFF	P AE	DDR	ESS	-			<-		1EN	IOR	Y A	DDF	RES	8		<- ->		D	ATA	W	ORE)				5 6
HOST	S T A R T	M S B						L S B	W R I T E		M S B							L S B		M S B							L S B		S T O P	7 8 9 1(
		1	0	1	0	0	0	0	0	0	x	x	x	x	x	x	x	x	0	x	x	x	x	x	x	x	x	0		1
XFP										A C K									A C K									A C K		12
																														14

Figure 25 XFP Write Byte Operation

4.5.8 WRITE OPERATIONS (SEQUENTIAL WRITE)

XFP's shall support up to a 4 sequential byte write without repeatedly sending XFP address and memory address information. A "sequential" write is initiated the same way as a single byte write, but the host master does not send a stop condition after the first word is clocked in. Instead, after the XFP acknowledges receipt of the first data word, the host can transmit up to three more data words. The XFP shall send an acknowledge after each data word received. The host must terminate the sequen- 25 tial write sequence with a STOP condition or the write operation shall be aborted and data discarded. Note that I2C "combined format" using repeated START conditions is not supported on XFP write commands."



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4.5.9 WRITE OPERATION PACKET ERROR CHECKING

2 All types of Write operations will use the same packet error checking technique (when enabled) as follows.

The form of the write transfer for packet error checking will include the number of bytes to be transferred as shown in Figure 27. After the host transmits the 1 to 4 Bytes of data during a Write operation and receives an ACK from the module, the host will further transmit a CRC-8 value. The CRC-8 value is calculated based on the starting memory address followed by the number of bytes and then the 1 to 4 Bytes in the order they are received.

The XFP module will calculate the validity of the received Write data and 12 Address based on the CRC-8. If the CRC-8 data is correct, the write will 13 be accepted and the module will respond with an ACK after which the host 14 will issue a STOP. If the CRC-8 data is incorrect, the module shall reject 15 the write and respond with a NACK after which the host will issue a STOP. 16

A CRC-8 should not be appended to a Dummy Write used in a Random 17 Read since the subsequent Read will confirm the address in its CRC-8.

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Figure 27 XFP Write Operation Packet Error Checking

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4.5.10 WRITE OPERATIONS (A	CKNOWLEDGE POLLING)	1
	Once the XFP internally timed write cycle has begun (and inputs are being	2
	ignored on the bus) acknowledge polling can be used to determine when	3
	the write operation is complete. This involves sending a START condition	4
	followed by the device address word. Only if the internal write cycle is complete shall the XFP respond with an acknowledge to subsequent com-	5
	mands, indicating read or write operations can continue.	6
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CHAPTER 5: MANAGEMENT INTERFACE

This chapter defines the operation of the XFP 2-wire serial interface which is used for serial ID, digital diagnostics, and certain control functions. The 2-wire serial interface is mandatory for all XFP modules. It is modeled largely after the digital diagnostics monitoring interface proposed for the SFP and GBIC optical transceivers and defined in SFF draft document SFF-8472 Rev 9.3, which in turn is an extension of the original serial ID systems defined for the GBIC and SFP transceivers. One major difference, however, is that the memory structure is changed to use a single 2wire interface address.

The structure of the memory map is shown in Figure 28. The normal 256 Byte I2C address space is divided into lower and upper blocks of 128 Bytes. The lower block of 128 Bytes is always directly available and is used for the diagnostics and control functions described in this document that must be accessed repeatedly. One exception to this is that the standard module identifier Byte defined in the GBIC and SFP is located in Byte 0 of the memory map (in the diagnostics space) to allow software developed for multiple module types to have a common branching decision point. This Byte is repeated in the Serial ID section so that it also appears in the expected relationship to other serial ID bits.

Multiple blocks of memories are available in the upper 128 Bytes of the address space. These are individually addressed through a table select Byte which the user enters into a location in the lower address space. Thus, there is a total available address space of 128 * 256 = 32Kbytes in this upper memory space.

The upper address space tables are used for less frequently accessed functions such as serial ID, user writable EEPROM, reserved EEPROM and diagnostics and control spaces for future standards definition, as well as ample space for vendor specific functions. These are allocated as follows:

- Table 00h: Reserved for future diagnostic and control functions
- Table 01h: Serial ID EEPROM
- Table 02h: User writable EEPROM
- Table 03h 7Fh:Vendor specific functions
- Table 80h FFh:Reserved

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The details of each memory space are described in the sections that follow. All 2-Wire registers are read with bit 7 the MSB first.

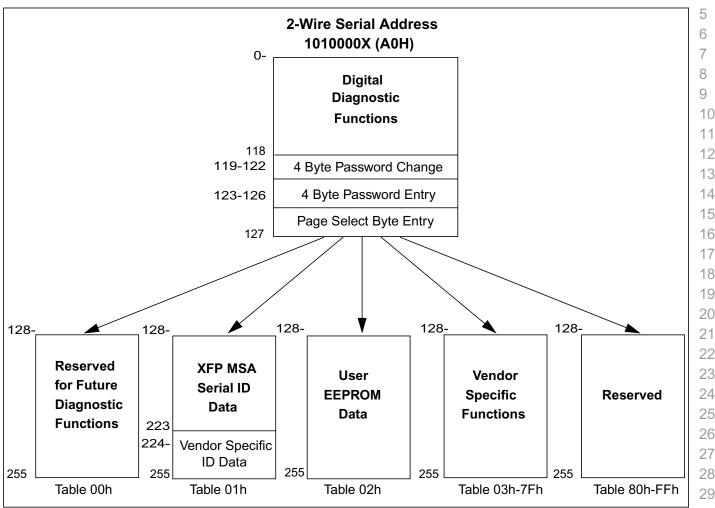


Figure 28 2-wire Serial Digital Diagnostic Memory Map

The memory structure also provides for an optional password entry location in the lower memory space that may be used to protect vendor internal functions or user writable memory. Passwords shall not be required to read any serial ID or diagnostics information in the lower memory address space or in Tables 00h – 02h. Nor shall passwords be required to write any controls defined in the digital diagnostic functions described in this document. Passwords may be used by vendors to control write access to MSA defined read only data for factory setup, or to OEMs to limit write access in the User EEPROM Table (02h). Finally, passwords may be used to control read or write access to the vendor specific tables 03h – 7Fh.

	Separate Passwords value ranges will be defined for host vendor pass- words and module vendor passwords to prevent accidental writing into critical module control areas by the host vendor. Details are defined in <u>5.5</u> .	1 2 3
	Note: Unless specifically noted, all informative ID fields must be filled out. Using a value of 0 to indicate a field is unspecified (as is common in the SFP definition) is not permitted.	4 5 6 7
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5.0.1 APPLICABLE DOCUMENT	'S	9 10
	Digital Diagnostic Monitoring Interface for Optical Transceivers SFF doc-	11
	ument number: SFF-8472, rev. 9.3 August 4, 2002.	12
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5.1 DESCRIPTION OF LOWER MEMORY MAP: CONTROL FUNCTIONS, DIAGNOSTICS, TABLE ACCESS

The lower 128 Bytes of the 2-wire serial bus address space is used to access a variety of measurements and diagnostic functions, to implement a set of control functions, and finally to select which of the various upper memory map tables are accessed on subsequent reads. This portion of the address space is always directly addressable and thus is chosen for diagnostics and control functions that may need to be repeatedly accessed. 2 2 3 3 4 5 6 7 7 8

Table 31shows the general memory map of the lower 128 Byte address9space.1

Address	Description
0	Identifier (1 Byte)
1	Signal Conditioner Control
2 - 57	Threshold Values used for Alarm and Warning Flags (56 Bytes)
58-59	Optional VPS Control Registers(2 Byte)
60 - 69	Reserved (10 Bytes)
70 - 71	BER Reporting
72 - 75	Wavelength Control Registers (4 Bytes)
76 - 79	FEC control Registers (4 Bytes)
80 - 95	Flags and Interrupt Control (16 Bytes)
96 - 109	A/D readout (14 Bytes)
110 - 111	General Control/Status bits (2 Bytes)
112 - 117	Reserved (6 Bytes)
118	Serial Interface Read/Write Error Checking (1 Bytes)
119 - 122	Password Change Entry Area (Optional) (4 Bytes)
123 - 126	Password Entry Area (optional) (4 Bytes)
127	Page Select Byte

Table 31 Lower Memory Map

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5.2 IDENTIFIER

Byte 0 of the lower memory map contains the module identifier value. The 2 identifier value specifies the physical device described by the serial ID in-3 formation. This value is also included in the serial ID data table (01h). The 4 defined identifier values are shown in <u>Table 32</u>. The XFP transceiver should use identifier 06h.

Value	Description of Physical Device	
00h	Unknown or unspecified	
01h	GBIC	
02h	Module/connector soldered to motherboard	
03h	SFP	
04h	300 pin XBI	
05h	XENPAK	
06h	XFP	
07h	XFF	
08h	XFP-E	
09h	ХРАК	
0Ah	X2	
0A-7Fh	Reserved	
80-FFh	Vendor specific	

Table 32 Identifier values Byte 128

5.3 SIGNAL CONDITIONER CONTROL

32 The XFP MSA defines two modes of transmitter signal conditioner operation. The default mode, which must be included in all XFP implementa-33 tions, uses a REFCLK which need not be synchronous with the data and 34 with relatively loose jitter requirements. This mode is generally intended 35 for Clock and Data Recovery techniques for retiming the transmitter data. 36 An optional mode is defined whereby the host system provides a synchro-37 nous REFCLK with relatively tight frequency and jitter requirements. This 38 mode is intended to allow the use of a Clock Multiplication (CMU) based retiming scheme. The electrical requirements for these modes are defined 39 in Section 3.9. 40

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bo sha no	order to select between these modes in modules which oth, a control bit is defined in Byte 1, bit 0, as shown in <u>Tak</u> all power up with a value of 0 corresponding to the defau ous clock mode. The host system may switch the XFP mod ronous clock mode by writing a value of 1 into this bit.	<u>ole 34</u> . This bit ult asynchro-	1 2 3 4 5
Se me	n identifier bit indicating the availability of this capability is erial ID Page in Byte 221, Bit 0 Page 01h. XFP modules enting the optional REFCLK mode shall not have a writab tion and should report a value of 0 when read.	not imple-	6 7 8 9
rar da	order to accommodate signal conditioner devices with lin nge, host system shall inform the XFP module of the dat ta rate is written into the upper 4 bits of Byte 01h. The va itered are given by:	a rate. The	10 11 12 13
	Byte $01h[bits 7-4] = INT((Data Rate(Gb/s) - 9.5)/0.$.2))	14 15
	nis covers a range of 9.5-12.5 Gb/s. Thus for example, for ² 4 are 0100b.	10.3 Gb/s, Bits	16 17 18
	ne signal conditioner may optionally support two different odes which may be useful for various diagnostics needs.	•	19 20
is s inp pin XF	ne first of these modes is known as XFI Loopback. In this set by writing a 1 into Bit 1 of Byte 1 of the lower memor out on the TX pins of the XFP module are retimed and out ons of the module. Optical data is not transmitted or receive FI Loopback mode. This control bit will power up and rese normal operation.	ry map, data tput on the RX ed when in the	 21 22 23 24 25 26 27
wh da tra this	ne second loopback mode is known as Lineside Loopback hich is set by writing a 1 into Bit 2 of Byte 1 of the lower r ata received on the XFP module receiver is retimed and ou ansmitter. This optical data is not present on the electrica is mode. This control bit will power up and reset to 0 resu peration.	memory map, Itput on optical al interface in	 27 28 29 30 31 32 33
ma	upport for these loopback modes is indicated in the seria ap in Byte 164 (CDR Support). Simultaneous operation o lock modes are not supported.	-	 33 34 35 36 37 38 39 40 41 42

Management interface

5.4 2-WIRE SERIAL INTERFACE CHECKSUM

XFP modules shall support selectable packet error checking. Packet error checking is defined in Section <u>4.5.6</u> and <u>4.5.9</u>. Packet error checking is enabled by setting Bit 0 of Byte 118 to 1 (see <u>Table 43</u>), and disabled by setting it to 0. Bit 0 will default to 0 on power-up or reset.

5.5 TABLE SELECTION AND PASSWORD ENTRY (TABLE 44)

Access to information in the various upper memory address tables is provided by the use of a Table Select Byte in Byte 127 of the lower memory map. The Table Select Byte is both readable and writable and shall default on power-up or reset to 01h [Serial ID memory space]. The user may write other table numbers into Byte 127 before subsequent read/writes into those spaces. The current Table Select Byte value will be retained until power down, reset, or rewritten by host.

If the host attempts to write a table select value which is not supported in a particular module, the table select byte will revert to 01h.

Bytes 123-126 are reserved for an optional password entry function. The Password entry bytes are write only and will be retained until power down, reset, or rewritten by host.

This function may be used to control read/write access to vendor specific tables 03h - 7Fh. Additionally, module vendors may use this function to implement write protection of Serial ID and other MSA read only information. Passwords may be supplied to and used by Host manufacturers to limit write access in the User EEPROM Table (02h).

Password access shall not be required to access MSA defined data in the lower memory space or in Tables 00h – 02h. Note that multiple module manufacturer passwords may be defined to allow selective access to read or write to various sections of memory as allowed above.

Host manufacturer and module manufacturer passwords shall be distinguished by the high order bit (bit 7, Byte 123). All host manufacturer passwords shall fall in the range of 00000000h to 7FFFFFFh, and all module manufacturer passwords in the range of 80000000h to FFFFFFFh. Host manufacturer passwords shall be initially set to 00001011h in new modules. Host manufacturer passwords may be changed by writing a new password in Bytes 119-122 when the correct current Host manufacture password has been entered in 123-126, with the high order bit being ignored and forced to a value of 0 in the new password.

The password entry field shall be set to 00000000h on power up and reset.

5.6 BASIC MONITORING FUNCTIONS

The basic measured quantities are transceiver temperature, TX bias current, TX output power, received optical power, and two additional quantities which are defined in Byte 222 of the Serial ID table (Table 01h).

5 Measured parameters are reported in 16 bit data fields, i.e., two concate-6 nated bytes. These are shown in Table 41. The 16 bit data fields allow for 7 wide dynamic range. This is not intended to imply that a 16 bit A/D system 8 is recommended or required in order to achieve the accuracy goals stated 9 below. The width of the data field should not be taken to imply a given level of precision. It is conceivable that the accuracy goals herein can be 10 achieved by a system having less than 16 bits of resolution. It is recom-11 mended that any low-order data bits beyond the system's specified accu-12 racy be fixed at zero. Overall system accuracy and precision will be vendor 13 dependent. 14

To guarantee coherency of the diagnostic monitoring data, the host is required to retrieve any multi-byte fields from the diagnostic monitoring data structure (IE: Rx Power MSB – byte 104, Rx Power LSB – byte 105) by the use of a single two-byte read sequence across the 2-wire serial interface. 18

19 The transceiver is required to insure that any multi-byte fields that are up-20 dated with diagnostic monitoring data (IE: Rx Power MSB - byte 104, Rx 21 Power LSB – byte 105) must have this update done in a fashion that guar-22 antees coherency and consistency of the data. In other words, the update of a multi-byte field by the transceiver must not occur such that a partially 23 updated multi-byte field can be transferred to the host. Also, the trans-24 ceiver shall not update a multi-byte field within the structure during the 25 transfer of that multi-byte field to the host, such that partially updated data 26 would be transferred to the host. 27

Accuracy requirements specified below shall apply to the operating signal range specified in the relevant standard. The manufacturer's specification should be consulted for more detail on the conditions under which the accuracy requirements are met.

Measurements are calibrated over vendor specified operating temperature and voltage and should be interpreted as defined below. Alarm and warning threshold values should be interpreted in the same manner as real time 16 bit data.

 Internally measured transceiver temperature. Represented as a 16 bit signed twos complement value in increments of 1/256 degrees Celsius valid between –40 and +125C. Temperature accuracy is vendor specific but must be better than +/-3 degrees Celsius over specified operating temperature and voltage. Please see vendor

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specification for details on location of temperature sensor. Temperature in degrees Celsius is given by the signed two's complement value with LSB equal to 1/256 C.

- Measured TX bias current in μA. Represented as a 16 bit unsigned integer with the current defined as the full 16 bit value (0 – 65535) with LSB equal to 2 μA, yielding a total measurement range of 0 to 131 mA. Accuracy is vendor specific but must be better than +/-10% of the manufacturer's nominal value over specified operating temperature and voltage.
- 9 Measured TX output power in mW. Represented as a 16 bit unsigned 10 integer with the power defined as the full 16 bit value (0 - 65535) with 11 LSB equal to 0.1 μ W, yielding a total measurement range of 0 to 12 6.5535 mW (~ -40 to +8.2 dBm). Data is assumed to be based on measurement of laser monitor photodiode current. It is factory cali-13 brated to absolute units using the most representative fiber output 14 type. Accuracy is vendor specific but must be better than +/- 2dBover 15 specified temperature and voltage. Reported measurement values 16 must maintain +/-1dB relative accuracy over the specified tempera-17 ture and voltage range over the life of the product into a fixed mea-18 surement system.Data is not valid when the transmitter is disabled.
- 19 Measured RX received optical power in mW. Value can represent ei-20 ther average received power or OMA depending upon how bit 3 of 21 byte 220 (Table 01h) is set. Represented as a 16 bit unsigned integer with the power defined as the full 16 bit value (0 - 65535) with LSB 22 equal to 0.1 μ W, yielding a total measurement range of 0 to 6.5535 23 mW (~ -40 to +8.2 dBm). Absolute accuracy is dependent upon the 24 exact optical wavelength. For the vendor specified wavelength, accu-25 racy shall be better than +/-2 dB over specified temperature and volt-26 age. This accuracy shall be maintained for input power levels up to 27 the lesser of maximum transmitted or maximum received optical power per the appropriate standard. It shall be maintained down to the 28 minimum transmitted power minus cable plant loss (insertion loss or 29 passive loss) per the appropriate standard. Absolute accuracy be-30 yond this minimum required received input optical power range is 31 vendor specific. Reported measurement values must maintain +/-32 1dB relative accuracy over the above received power range and 33 specified temperature and voltage ranges over the life of the product 34 using a fixed test source fiber.
- Up to two Auxiliary Measurements may be implemented by the vendor. The auxiliary monitoring channels, if any, are defined in Byte 222 of Table 01h. That table also details the units which should be used in reporting the corresponding values.
 35 36 37 38
- Internally measured transceiver supply voltage. Represented as a 16 39 bit unsigned integer with the voltage defined as the full 16 bit value (0 40 65535) with LSB equal to 100 μVolt, yielding a total measurement range of 0 to +6.55 Volts. Practical considerations to be defined by 42

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transceiver manufacturer will tend to limit the actual bounds of the supply voltage measurement. Accuracy is vendor specific but must be better than $\pm 3\%$ of the manufacturer's nominal value over specified operating temperature and voltage.

Each A/D quantity has a corresponding high alarm, low alarm, high warning and low warning threshold. These factory-preset values allow the user to determine when a particular value is outside of "normal" limits as determined by the transceiver manufacturer. It is assumed that these values will vary with different technologies and different implementations. These values are stored in read-only memory in Bytes 2-57 as shown in Table 35.

The values reported in the Alarm and Warning Thresholds area may be typical values at some chosen nominal operating conditions and may be temperature compensated or otherwise adjusted when setting warning and/or alarm flags. Any compensation or adjustment is vendor specific and completely optional. If temperature compensation or other adjustment takes place, the corresponding alarm and warning flags may not match the result of a comparison performed by the host using the reported Auxiliary Measurement diagnostic data and thresholds.

A set of alarm and warning flags are implemented. The flags are latched and detailed in the Interrupt Control Descriptions. These flags indicate when the various monitored quantities are above or below the thresholds. For users who do not wish to set their own threshold values or read the values in locations 2 - 57, the flags alone can be monitored. Two flag types are defined:

1) Alarm flags associated with transceiver temperature, supply voltage, TX bias current, TX output power and received optical power as well as reserved locations for future flags. Alarm flags indicate conditions likely to be associated with a faulty link and cause for immediate action.

2) Warning flags associated with transceiver temperature, supply voltage, TX bias current, TX output power and received optical power as well as reserved locations for future flags. Warning flags indicate conditions outside the normally guaranteed bounds but not necessarily causes of immediate link failures. Certain warning flags may also be defined by the manufacturer as end-of-life indicators (such as for higher than expected bias currents in a constant power control loop).

5.7 OPTIONAL VARIABLE POWER SUPPLY (VPS) CONTROL

To facilitate the power/current savings of deep-submicron CMOS processes, the XFP specification defines modules that optionally support a38VCC2 supply lower than 1.8-V. These modules are intended for use in40systems employing a variable power supply (VPS). In the default mode,41which must be included in every XFP compliant implementation, the42

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module is supplied and can operate normally with a 1.8-V voltage on its VCC2 pins. 2

An XFP module might include a discrete or integrated regulator, which supplies the CMOS ICs with a voltage lower than 1.8-V by stepping down the VCC2 supply. The module powers up in the default mode of operation capable of operating normally with 1.8-V on the VCC2 pins.

In the first optional mode ("operational LV regulator mode") the regulator 8 is still operational but the host system supplies the module with a VCC2 9 voltage lower than +1.8-V. In the second optional mode ("bypassed regu-10 lator mode") the regulator is bypassed and the CMOS ICs are connected 11 directly to the VCC2 pins of the module. Serial ID Byte 221 (Table 01h), 12 bit 7 indicates if optional VPS is implemented. VPS control registers are 13 located in Bytes 58-59 as defined in the Table 33.

Byte	Bit	Name	Description
58	7-4	Lowest Voltage Supported with an Operational LV Regulator	Read Only See Note 1, 2
58	3-0	Voltage Supplied on the VCC2 Pins.	Read Write. Powers up to 0000b. See Note 1.
59	7-4	Voltage Supported with a Bypassed Regulator.	Read Only. See Note 1.
59	3-1	Reserved	
59	0	Regulator bypass mode	0b = Mode disabled. Powers up to 0b. 1b = Mode enabled

Table 33 VPS Fields

1. The values in these fields are unsigned 4-bit binary integers (INT[3:0]. To translate to absolute voltage use: V[absolute] = (1.8 V)-(INT[3:0])*(0.1-V).

2. Any XFP compliant module supporting the optional LV regulator mode should be operational with any power supply voltage between 1.8 V and the value signified on Byte58, Bits 7-4.

> Modules which implement an optional voltage mode must monitor the VCC2 rail as part of the Auxiliary Monitoring described in sections 5.42.

When a host selects one of the optional voltage modes, the module will automatically adjust the appropriate threshold and alarm register values described in Table 35. The module will issue an Interrupt if the Vcc2 voltage is ever outside the acceptable range.

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hen a host selects one of the optional voltage modes, power and current quirements of the module should scale <i>at least linearly</i> with voltage (<i>this sumption is made to simplify the specification - in most cases power wings will be larger than linear</i>). Implementing these optional modes enoles a module to fall into two classes of power dissipation according to e mode of operation. However, when a module is switched to one of the optional modes it will not change the values in <u>Table 54</u> . The host can use e default values in <u>Table 54</u> to calculate the minimum power savings of e optional modes.	1 2 3 4 5 6 7 8
I voltage setting changes should take place when the module is in the w power, stand-by mode (i.e. P_Down pin is held high). The 2-wire serial is and XFP interface signals must remain fully functional during voltage etting changes, and the falling edge of P_Down should not reset these hanges. To achieve the lowest power operation under any condition a best supporting an optional voltage mode should hold the P_Down pin gh on empty module sockets.	9 10 11 12 13 14 15
enable the "operational LV regulator mode" the following sequence ust occur:	16 17 18
Host sets the module into the stand-by mode by holding the P_Down/RST pin asserted. During stand-by mode the module trans- mitter should be disabled.	19 20 21
Host reads the content of Byte 58 and 59 to determine the most de- sirable setting for VPS and changes the voltage on VCC2 pins of the XFP connector.	22 23 24
Host then writes Bits 3-0 of Byte58 to indicate the new voltage and module updates settings in <u>Table 35</u> .	25 26
When P_Down is de-asserted module verifies the voltage on VCC2 is within range. If voltage is within range, module enables all circuitry within the module and resumes with normal operation. If voltage is not within range, module sets the appropriate voltage monitoring Interrupt bit to inform the host and asserts Mod_NR.	27 28 29 30 31
enable the "bypassed regulator mode" the host should follow the se- uence described above, with the only difference that bit 0 of Byte 59 is ritten to 1b in step 3.	32 33 34
o return the module to the default mode (VCC2=1.8-V) the host must as- ert P_Down and return the R/W fields of Bytes 58 and 59 to their default lues.	35 36 37 38
modules that implement both optional modes the value written in Byte 3 takes precedence over the value written in Byte 59, i.e. if both of Byte 3, bits 3-0 and Byte 59, bit 0 are non-zero the module will be in "opera- onal LV regulator mode".	39 40 41 42

Management interface

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Two identifier bits indicating the availability of these optional modes are defined in the Serial ID Page in Byte 221, Bits 3-4 Page 01h. Bit 4 corre-2 sponds to the availability of the "operational LV regulator mode". Bit 3 cor-3 responds to the availability of the "bypassed regulator mode". XFP 4 modules not implementing these optional modes will return 0 from these 5 locations as well as from all fields of bytes 58-59. 6

5.8 SYSTEM BER REPORTING

10 A host system implementing a forward error correction device can report receive BER. The 2-Wire host management interface can transfer FEC re-11 ported BER data to the XFP module. The module may use this information 12 to improve system BER. Implementation of BER Reporting functions is in-13 dicated in Serial ID Byte 220 (Table 01h), bit 4. Control registers are lo-14 cated in Bytes 70 and 71 (see Table 36). 15

16 Byte 70 requests the desired level of BER from the XFP module. Byte 71 reports the FEC actual BER to the XFP module. The data format for Byte 17 70 it is given by: 18

$$BER = \left[\frac{Byte(70(MSB - 4bits))}{16}\right] \times 10^{-[Byte(70(LSB - 4bits))]}$$

Similarly for byte 71 is given by:

$$BER = \left[\frac{Byte(71(MSB-4bits))}{16}\right] \times 10^{-[Byte(71(LSB-4bits))]}$$

MSB-Octet is the decimal value of the 4 MSB bits. LSB-Octet is the decimal value of the 4 LSB bits. If byte 71 reports Hexadecimal value of 4C then the BER would be 0.25x10E-12. 34

5.9 WAVELENGTH CONTROL

38 This section of memory includes registers (Table 37) that allow the imple-39 mentation of a wavelength tunable XFP module. Implementation of 40 wavelength tunability is indicated in Serial ID Byte 221 (Table 01h), bit 1. 41 Bytes 72-73 are used to input the desired wavelength setpoint in the same

XFP Specification REVISON 3.1	Management interface	April 2, 2003
	format described for XFP center wavelength in th	-
	(units of 0.05 nm). For a wavelength tunable more for wavelength and tolerance will define the allow	
	to tuning control bytes 72-73 which are outside t to the allowed tuning range as defined in the ser	•
	Bytes 74 and 75 are optional monitor values that on measured error between the actual wavelength a lt is a 16 bit signed 2's complement value in units	and the entered setpoint.
	Reported Error [Bytes 74,75] =(Meas. Waveleng 72,73])*(0.005nm)	th – Setpoint [Bytes
	Finally, the latched flag in Byte 85 bit 5 may be used length error exceeding the manufacturer's tolerate may be configured by the user on an interrupt triangle of the second se	nce, and this condition
	may be configured by the user as an interrupt trig	gger as described in the
5.10 FEC CONTROL	In some forward error correction schemes, the ho	ost system may optimize
	the sensitivity of an optical link or minimize the en phase and amplitude threshold for data quantiza	rror rate by adjusting the
	fier section of the module receive path. Impleme functions is indicated in Serial ID Byte 221 (Table isters are located in Bytes 76 and 77 (see <u>Table</u>	ntation of FEC control e 01h), bit 2. Control reg-
	Byte 76 is used to set the amplitude threshold of tion. It is a 2's complement 7 bit value (-128 - +12	· ·
	is given by:	
	Amplitude Threshold = 50% + [Byte(76))/256] *100%
	Similarly, Byte 77 is used to set the phase point quantization, and is set in terms of unit interval r	
	Phase setpoint = 0.5 UI + [Byte(7	7)/256] UI

5.11 INTERRUPT SYSTEM LOGIC			1
t t	he host system to any cor	al time hardware Interrupt pin (see 2.4) to alert ndition outside normal operating conditions. In- e triggered and latched by a set of flags. These	2 3 4 5
	toring Functions. These	gs as described in the section on Basic Moni- e correspond to monitored quantities going nmed threshold values.	6 7 8
	 Flags corresponding to 	basic module status conditions including:	9 10 11
	TX_NR:	Any condition leading to invalid data on the TX path	12 13 14
	TX_Fault	Laser fault condition (same as TX_Fault in SFP and GBIC)	15 16
	TX CDR Unlocked:	Unlocked:Loss of Lock of TX side CDR	17 18
	RX_NR:	Any condition leading to invalid data on the RX path	19 20
	RX_LOS:	RX Loss of Signal (mirroring hardware output pin)	21 22 23
	RX_CDR Unlocked:	Unlocked:Loss of Lock of RX side CDR	24
	MOD_NR:	Module Not Ready (mirroring hardware output pin)	25 26 27
	Flag indicating comple power up or P_Down/F	tion of the XFP Module Reset (as initiated by RST pin)	28 29
·	 Flags corresponding to APD Supply Fault TEC Fault Wavelength Unlock 	o optional extended capabilities including:	30 31 32 33 34 35
	5	conditions shall lead to a latched flag. These 30 – 87 and are detailed in <u>Table 39</u> .	36 37
Ī	nterrupt output pin (active system to a latched flag co	ues in Bytes $80 - 87$ will assert the hardware low). When the Interrupt pin alerts the host ndition, the host may query the latched flag bits ned flags are cleared on the read of the corre-	38 39 40 41 42

	sponding Byte. Thus a read of all Bytes from $80 - 87$ can be used to reset all latched flags and deassert the hardware Interrupt output pin.	1 2
	Because of the bytewise nature of the 2-wire serial bus reads, it is not pos- sible to clear individual flag bits. It is recommended that all latched flag bits be read and cleared in the same operation.	3 4 5
	The host system may control which flags result in an Interrupt by setting high individual bits from a set of masking bits in Bytes 88-95, and described in <u>Table 40</u> . A 1 value in a masking bit prevents the assertion of the hardware Interrupt pin by the corresponding latched flag bit.	6 7 8 9 10
	Masking bits should be volatile and startup with all unmasked (masking bits 0).	11 12 13
	Hardware Interrupt Pin = Logical NOR of all (Latched Flag Bit AND NOT Masking Bit)	14 15
	The mask bits may be used to prevent continued interruption from on- going conditions, which would otherwise continually reassert the hard- ware Interrupt pin.	16 17 18 19
5.11.1 GENERAL CONTROL AN	D STATUS BITS	20
	In order to allow virtually complete operation of the XFP module via the 2- wire serial interface, a set of control and status bits are provided to mirror the operation of key status and control pins. These are provided in Bytes 110-111 and are detailed in <u>Table 42</u> . All status bits except soft bits in this set are dynamic (not latched)	21 22 23 24 25
	The bits fall into three categories:	26 27
	 Bits mirroring hardware status lines: TX-DIS, MOD_NR, P_Down/RST, Interrupt, RX_LOS 	28 29
	 Bits providing more specific information: TX_NR, RX_NR, TX and RX CDR Loss of Lock, and TX Fault. 	30 31
	• A set of read/write bits which can be used to implement the optional "soft" control of TX-Disable and the Power-Down functions. (Described fully in <u>Table 42</u>). Availability of this option is defined in Byte 221 (Table 01h).	32 33 34 35
		36 37 38
		39
		40
		41
		42

5.12 TIMING FOR SOFT CONTROL AND STATUS FUNCTIONS Detail timing for soft control and status functions are described in Table 45 accessible with the 2-wire Serial interface Chapter 4:. Table 34 Signal Conditioner Control Field Bit **Byte** Name **Description** 4-7 Data Rate Control Data Rate=9.5Gb/s + 0.2 * Value Reserved Lineside Loopback **0b=Normal Operation** 1b=Loopback Module Optical Input to Output XFI Loopback **0b=Normal Operation** 1b=Loopback Module XFI Input to Output Signal Conditioner Control 0b = Normal Asynchronous REFCLK mode 1b = Optional Synchronous REFCLK mode

		ble 35 Alarm and Warning	-	
Address	# Bytes	Name	Description	
02-03	2	Temp High Alarm	MSB at low address	
04-05	2	Temp Low Alarm	MSB at low address	
06-07	2	Temp High Warning	MSB at low address	
08-09	2	Temp Low Warning	MSB at low address	
10-17	8	Reserved A/D Flag Thresholds	Reserved A/D Flag Thresholds	
18-19	2	Bias High Alarm	MSB at low address	
20-21	2	Bias Low Alarm	MSB at low address	
22-23	2	Bias High Warning	MSB at low address	
24-25	2	Bias Low Warning	MSB at low address	
26-27	2	TX Power High Alarm	MSB at low address	
28-29	2	TX Power Low Alarm	MSB at low address	
30-31	2	TX Power High Warning	MSB at low address	
32-33	2	TX Power Low Warning	MSB at low address	
34-35	2	RX Power High Alarm	MSB at low address	
36-37	2	RX Power Low Alarm	MSB at low address	
38-39	2	RX Power High Warning	MSB at low address	
40-41	2	RX Power Low Warning	MSB at low address	
42-43	2	AUX 1 High Alarm	MSB at low address	
44-45	2	AUX 1 Low Alarm	MSB at low address	
46-47	2	AUX 1 High Warning	MSB at low address	
48-49	2	AUX 1 Low Warning	MSB at low address	
50-51	2	AUX 2 High Alarm	MSB at low address	
52-53	2	AUX 2 Low Alarm	MSB at low address	
54-55	2	AUX 2 High Warning	MSB at low address	

- 38 39
- 40
- 41
- 42

Table 36 BER Control Fields

Byte	Bit	Name	Description
70	All	Acceptable BER	Acceptable BER Reported by the FEC to the Module
71	All	Actual BER	Actual BER Reported by the FEC to the Module

Table 37 Wavelength Control Fields

Byte	Bit	Name	Description
72	All	Wavelength Set MSB	User input of Wavelength setpoint. (Units of 0.05 nm)
73	All	Wavelength Set LSB	
74	All	Wavelength Error MSB	Monitor of Current Wavelength Error (Units of 0.005nm)
75	All	Wavelength Error MSB	[Signed 2's complement value]

Table 38 FEC Control Fields

Byte	Bit	Name	Description
76	All	Amplitude Adjustment	Relative amplitude of receive quantization threshold
77	All	Phase Adjustment	Phase of receive quantization relative to 0.5 UI.
78-79	All	Reserved	
		-	

Address	# Bit	Name	Description
80	7	L- Temp High Alarm	Latched high Temperature alarm.
80	6	L- Temp Low Alarm	Latched low Temperature alarm.
80	5	Reserved	
80	4	Reserved	
80	3	L- TX Bias High Alarm	Latched high TX Bias alarm.
80	2	L- TX Bias Low Alarm	Latched low TX Bias alarm.
80	- 1	L- TX Power High Alarm	Latched high TX Power alarm.
80	0	L- TX Power Low Alarm	Latched low TX Power alarm.
81	7	L- RX Power High Alarm	Latched high RX Power alarm.
81	6	L- RX Power Low Alarm	Latched low RX Power alarm.
81	5	L- AUX 1 High Alarm	Latched high AUX1 monitor alarm.
81	4	L- AUX 1 Low Alarm	Latched low AUX1 monitor alarm.
81	3	L- AUX 2 High Alarm	Latched high AUX2 monitor alarm.
81	2	L- AUX 2 Low Alarm	Latched low AUX2 monitor alarm.
81	1	Reserved	
81	0	Reserved	
82	7	L- Temp High Warning	Latched high Temperature warning.
82	6	L- Temp Low Warning	Latched low Temperature warning.
82	5	Reserved	
82	4	Reserved	
82	3	L- TX Bias High Warning	Latched high TX Bias warning.
82	2	L- TX Bias Low Warning	Latched low TX Bias warning.
82	1	L- TX Pow. High Warning	Latched high TX Power warning.
82	0	L- TX Pow. Low Warning	Latched low TX Power warning.
83	7	L- RX Pow. High Warning	Latched high RX Power warning.
83	6	L- RX Pow. Low Warning	Latched low RX Power warning.
83	5	L- AUX 1 High Warning	Latched high AUX1 monitor warning.
83	4	L- AUX 1 Low Warning	Latched low AUX1 monitor warning.
83	3	L- AUX 2 High Warning	Latched high AUX2 monitor warning.
83	2	L- AUX 2 Low Warning	Latched low AUX2 monitor warning.

Address # Bit		Name	Description
83	0	Reserved	
84	7	L- TX_NR	Latched TX_NR Status
84	6	L- TX_Fault	Latched Laser Fault condition. Generated by laser safety system.
84	5	L- TX CDR not Locked	Latched TX CDR Loss of Lock
84	4	L- RX_NR	Latched RX_NR Status
84	3	L- RX_LOS	Latched mirror of RX_LOS pin (Receiver loss of optical signal)
84	2	L- RX CDR not Locked	Latched RX CDR Loss of Lock
84	1	L- MOD_NR	Latched Mirror of MOD_NR pin
84	0	L- Reset Complete	Latched Reset Complete Flag
85	7	L- APD Supply Fault	Latched APD Supply Fault
85	6	L- TEC Fault	Latched TEC Fault
85	5	L- Wavelength Unlocked	Latched Wavelength Unlocked Condition
85	0-4	Reserved	
86	7	L-VCC5 High Alarm	VCC5 High Alarm Flag
86	6	L-VCC5 Low Alarm	VCC5 Low Alarm Flag
86	5	L-VCC3 High Alarm	VCC3 High Alarm Flag
86	4	L-VCC3 Low Alarm	VCC3 Low Alarm Flag
86	3	L-VCC2 High Alarm	VCC2 High Alarm Flag
86	2	L-VCC2 Low Alarm	VCC2 Low Alarm Flag
86	1	L-Vee5 High Alarm	Vee5 High Alarm Flag
86	0	L-Vee5 Low Alarm	Vee5 Low Alarm Flag
87	7	L-VCC5 High Warning	VCC5 High Warning Alarm Flag
87	6	L-VCC5 Low Warning	VCC5 Low Warning Flag
87	5	L-VCC3 High Warning	VCC3 High Warning Flag
87	4	L-VCC3 Low Warning	VCC3 Low Warning Flag
87	3	L-VCC2 High Warning	VCC2 High Warning Flag
87	2	L-VCC2 Low Warning	VCC2 Low Warning Flag
87	1	L-Vee5 High Warning	Vee5 High Warning Flag
87	0	L-Vee5 Low Warning	Vee5 Low Warning Flag

		Table 40 Interrupt Mas	
Address	# Bit	Name	Description
88	7	M- Temp High Alarm	Masking bit for high Temperature alarm.
88	6	M- Temp Low Alarm	Masking bit for low Temperature alarm.
88	5	Reserved	
88	4	Reserved	
88	3	M- TX Bias High Alarm	Masking bit for high TX Bias alarm.
88	2	M- TX Bias Low Alarm	Masking bit for low TX Bias alarm.
88	1	M- TX Power High Alarm	Masking bit for high TX Power alarm.
88	0	M- TX Power Low Alarm	Masking bit for low TX Power alarm.
89	7	M- RX Power High Alarm	Masking bit for high RX Power alarm.
89	6	M- RX Power Low Alarm	Masking bit for low RX Power alarm.
89	5	M- AUX 1 High Alarm	Masking bit for high AUX1 monitor alarm.
89	4	M- AUX 1 Low Alarm	Masking bit for low AUX1 monitor alarm.
89	3	M- AUX 2 High Alarm	Masking bit for high AUX2 monitor alarm.
89	2	M- AUX 2 Low Alarm	Masking bit for low AUX2 monitor alarm.
89	1	Reserved	
89	0	Reserved	
90	7	M- Temp High Warning	Masking bit for high Temperature warning.
90	6	M- Temp Low Warning	Masking bit for low Temperature warning.
90	5	Reserved	
90	4	Reserved	
90	3	M- TX Bias High Warning	Masking bit for high TX Bias warning.
90	2	M- TX Bias Low Warning	Masking bit for low TX Bias warning.
90	1	M- TX Pow. Hi Warning	Masking bit for high TX Power warning.
90	0	M- TX Pow. Low Warning	Masking bit for low TX Power warning.
91	7	M- RX Pow. Hi Warning	Masking bit for high RX Power warning.
91	6	M- RX Pow. Low Warning	Masking bit for low RX Power warning.
91	5	M- AUX 1 High Warning	Masking bit for high AUX1 monitor warning
91	4	M- AUX 1 Low Warning	Masking bit for low AUX1 monitor warning.
91	3	M- AUX 2 High Warning	Masking bit for high AUX2 monitor warning
91	2	M- AUX 2 Low Warning	Masking bit for low AUX2 monitor warning.

Table 40 Inter	rupt Mas	king Bits
----------------	----------	-----------

Address # Bit		Name	Description
91	1	Reserved	
91	0	Reserved	
92	7	M- TX_NR	Masking bit for TX_NR Status
92	6	M- TX_Fault	Masking bit for Laser Fault condition.
92	5	M- TX CDR not Locked	Masking bit for TX CDR Loss of Lock
92	4	M- RX_NR	Masking bit for RX_NR Status
92	3	M- RX_LOS	Masking bit for mirror of RX_LOS pin (Receiver optical loss of signal)
92	2	M- RX CDR not Locked	Masking bit for RX CDR Loss of Lock
92	1	M- MOD_NR	Masking bit for Mirror of MOD_NR pin
92	0	M- Reset Complete	Masking bit for Reset Complete Flag
93	7	M- APD Supply Fault	Masking bit for APD Supply Fault
93	6	M- TEC Fault	Masking bit for TEC Fault
93	5	M- Wavelength Unlocked	Masking bit for Wavelength Unlocked Condi- tion
93	0-4	Reserved	
94	7	M-VCC5 High Alarm	VCC5 High Alarm Flag
94	6	M-VCC5 Low Alarm	VCC5 Low Alarm Flag
94	5	M-VCC3 High Alarm	VCC3 High Alarm Flag
94	4	M-VCC3 Low Alarm	VCC3 Low Alarm Flag
94	3	M-VCC2 High Alarm	VCC2 High Alarm Flag
94	2	M-VCC2 Low Alarm	VCC2 Low Alarm Flag
94	1	M-Vee5 High Alarm	Vee5 High Alarm Flag
94	0	M-Vee5 Low Alarm	Vee5 Low Alarm Flag
95	7	M-VCC5 High Warning	VCC5 High Waring Alarm Flag
95	6	M-VCC5 Low Warning	VCC5 Low Warning Flag
95	5	M-VCC3 High Warning	VCC3 High Warning Flag
95	4	M-VCC3 Low Warning	VCC3 Low Warning Flag
95	3	M-VCC2 High Warning	VCC2 High Warning Flag
95	2	M-VCC2 Low Warning	VCC2 Low Warning Flag
95	1	M-Vee5 High Warning	Vee5 High Warning Flag
95	0	M-Vee5 Low Warning	Vee5 Low Warning Flag

Table 41 A/D Values

Byte	Bit	Name	Description			
Converted analog values. Calibrated 16 bit data.						
96	All	Temperature MSB	Internally measured module temperature.			
97	All	Temperature LSB				
98-99	All		Reserved			
100	All	TX Bias MSB	Internally measured TX Bias Current.			
101	All	TX Bias LSB				
102	All	TX Power MSB	Measured TX output power.			
103	All	TX Power LSB				
104	All	RX Power MSB	Measured RX input power.			
105	All	RX Power LSB				
106	All	AUX 1 MSB	Auxiliary measurement 1 defined in Byte 222 Page 01h			
107	All	AUX 1 LSB				
108	All	AUX 2 MSB	Auxiliary measurement 2 defined in Byte 222 Page 01h			
109	All	AUX 2 LSB				

Byte	Bit	Name	Description	
110	7	TX Disable State	Digital state of the TX Disable Input Pin. Updated within 100msec of change on pin.	
110	6	Soft TX Disable	Optional read/write bit that allows software disable of laser. Writing 'l' dis- ables laser. Turn on/off time is 100 msec max from acknowledgement of serial byte transmission. This bit is "OR"d with the hard TX_DISABLE pin value. Note, per SFP MSA TX_DISABLE pin is default enabled unless pulled low by hardware. If Soft TX Disable is not implemented, the trans- ceiver ignores the value of this bit. Default power up value is 0.	
110	5	MOD_NR State	Digital state of the MOD_NR Pin. Updated within 100msec of chan pin.	
110	4	P_Down State	Digital state of the P_Down Pin. Updated within 100msec of change on pin.	
110	3	Soft P_Down	Optional read/write bit that allows the module to be placed in the power down mode. This is identical to the P_Down hardware pin function exce that it does not initiate a system reset.	
110	2	Interrupt	Digital state of the Interrupt output pin.	
110	1	RX_LOS	Indicates Optical Loss of Signal (per relevant optical link standard). Upd within 100msec of change on pin.	
110	0	Data_Not_Ready	Indicates transceiver has achieved power up and A/D data is ready. Bit remains high until data is ready to be read at which time the device sets bit low.	
111	7	TX_NR State	Identifies Not Ready condition as specific to the TX path	
111	6	TX_Fault State	Identifies Laser fault condition (Generated by laser safety system)	
111	5	TX_CDR not Locked	Identifies Loss of Lock in TX path CDR	
111	4	RX_NR State	Identifies Not Ready condition as specific to the TX path	
111	3	RX_CDR not Locked	Identifies Loss of Lock in RX path CDR	

The Data_Not_Ready bit is high during module power up and prior to the first valid A/D reading. Once the first valid A/D reading occurs, the bit is 36 set low until the device is powered down. The bit must be set low within 1 second of power up.

37 38

33 34

- 39
- 40 41
- 42

Table 43 Packet Error Checking

Byte	Bit	Name	Description
118	0	Error Checking	0 b = Disable Packet Error Checking 1b = Enable Packet Error Checking (see Section <u>4.5.6</u> and <u>4.5.9</u>)
118	1-7	Reserved	

Table 44 Password and Table Select Entry Bytes

.

Byte	Bit	Name	Description
119-122	All	New Password Entry	Location of Entry of New Optional Password
123-126	All	Password Entry	Location for Entry of Optional Password
127	All	Table Select	Entry Location for Table Select Byte

Table 45 I/O Timing for Soft Control & Status Functions

Parameter	Symbol	Min	Max	Unit	Conditions
TX_DISABLE assert time	t_off		100	ms	Time from TX_DIS bit set ¹ until optical output falls below 10% of nominal
TX_DISABLE deassert time	t_on		100	ms	Time from TX_DISABLE bit cleared ¹ until optical output rises above 90% of nominal
P_Down assert time	T_Pdown		100	ms	Time from P_Down bit set ¹ until module dissi- pation falls below 1.5W
P_Down deassert time	T_Pup		300	ms	Time from P_Down bit cleared ¹ until module returns to normal operation.
RX_LOS assert time	t_los_on		100	ms	Time from RX_LOS state to RX_LOS bit set
RX_LOS deassert time	t_los_off		100	ms	Time from non-LOS state to RX_LOS bit cleared
MOD_NR assert time	t_NR_on		100	ms	Time from TX_NR or RX_NR state to corre- sponding bit set
MOD_NR deassert time	t_NR_off		100	ms	Time from non-TX_NR or RX_NR state to corresponding bit set
Analog parameter data ready	t_data		1000	ms	From power on to data ready, bit 0 of byte 110 set

Descrii	PTION OF		TABLE 00H – FUTURE DIAGNOSTICS FUNCTIONS eserved for future diagnostics functions.
DESCRI	PTION OF	UPPER MEMORY MAP	TABLE 01H – SERIAL ID MEMORY MAP
			nemory map located in Table 01h in the upper address for read only identification information.
		Table 46 Serial	l ID: Data Fields - Page 01h
Address	Size (Bytes)	Name	Description
			Base ID Fields
128	1	Identifier	Type of serial transceiver (see <u>Table 32</u>)
129	1	Ext. Identifier	Extended identifier of type of serial transceiver (see Table 47)
130	1	Connector	Code for connector type (see <u>Table 48</u>)
131-138	8	Transceiver	Code for electronic compatibility or optical compatibility (see <u>Table 49</u>)
139	1	Encoding	Code for serial encoding algorithm (see <u>Table 50</u>)
140	1	BR-Min	Minimum bit rate, units of 100 MBits/s.
141	1	BR-Max	Maximum bit rate, units of 100 MBits/s.
142	1	Length(SMF)-km	Link length supported for SMF fiber in km
143	1	Length (E-50µm)	Link length supported for EBW 50/125 μ m fiber, units of 2 m
144	1	Length (50 µm)	Link length supported for 50/125 µm fiber, units of 1 m
145	1	Length (62.5 µm)	Link length supported for $62.5/125 \mu\text{m}$ fiber, units of 1 m
146	1	Length (Copper)	Link length supported for copper, units of 1m
147	1	Device Tech	Device technology (see <u>Table 51</u> , <u>Table 52</u>)
148-163	16	Vendor name	XFP vendor name (ASCII)
164	1	CDR Support	CDR Rate Support (see <u>Table 53</u>)
165-167	3	Vendor OUI	XFP vendor IEEE company ID
168-183	16	Vendor PN	Part number provided by XFP vendor (ASCII)
184-185	2	Vendor rev	Revision level for part number provided by vendor (ASCII)
186-187	2	Wavelength	Nominal laser wavelength (Wavelength = value / 20 in nm)

Address Size (Bytes)		Name	Description
188-189	2	Wavelength Tolerance	Guaranteed range of laser wavelength (+/- value) from Nominal wave- length. (Wavelength Tol. = value/200 in nm)
190	1	Max Case Temp	Maximum Case Temperature in Degrees C.
191	1	CC_BASE	Check code for Base ID Fields (addresses 120-190)
		Ext	tended ID Fields
192-195	4	Power Supply	Power supply current requirements and max power dissipation (see <u>Table 54</u>)
196-211	16	Vendor SN	Serial number provided by vendor (ASCII)
212-219	8	Date code	Vendor's manufacturing date code (see <u>Table 55</u>)
220	1	Diagnostic Monitoring Type	Indicates which type of diagnostic monitoring is implemented (if any) in the transceiver (see <u>Table 56</u>) Bit 1, 0 Reserved
221	1	Enhanced Options	Indicates which optional enhanced features are implemented (if any) in the transceiver (see <u>Table 57</u>)
222	1	Aux Monitoring	Defines quantities reported by Aux. A/D channels (see <u>Table 58 Table 59</u>)
223	1	CC_EXT	Check code for the Extended ID Fields (addresses 192 to 222)
		Vendo	r Specific ID Fields
224-255	32	Vendor Specific	Vendor Specific EEPROM

5.15 IDENTIFIER

Byte 0 of the lower memory map contains the module identifier value. The identifier value specifies the physical device described by the serial ID information. This value is also included in the serial ID data table (01h). The defined identifier values are shown in Table 32. The XFP transceiver should use identifier 06h.

5.16 EXTENDED IDENTIFIER

The extended identifier value provides additional information about the basic transceiver types <u>Table 47</u>.

This field existed in the GBIC specification to identify the various module definitions. These definitions do not apply to the XFP. The space is used to identify whether the transceiver contains a CDR function and identifies its power dissipation class it belongs.

Bit	Description of device type
6-7	 00: Power Level 1 Module (1.5 W max. power dissipation.) 01: Power Level 2 Module (2.5W Max) 10: Power Level 3 Module (3.5W max. power dissipation.) 11: Power Level 4 Module (>3.5W max. power dissipation.)
5	0: Module with CDR function 1: Non-CDR version of XFP
4	0: TX Ref Clock Input Required 1: TX Ref Clock Input Not Required
0-3	Reserved

Table 47 Extended Identifier values Byte 129

5.17 CONNECTOR

The Connector value indicates the external connector provided on the interface. This value shall be included in the serial data. The defined connector values are shown in <u>Table 48</u>. Note that some connectors in this table are mechanically incompatible with the XFP dimensions. This full list is included for compatibility with GBIC and SFP standards in the selection of potential future connector codes.

Register

00h01h02h03h 04h 05h

06h 07h 08h 09h 0Ah 0Bh0C-1Fh 20h 21h 22h-7Fh 80-FFh

Description of connector	4 5
Unknown or unspecified	
SC	7
Fibre Channel Style 1 copper connector	8
Fibre Channel Style 2 copper connector	9
BNC/TNC	1(1 ′
Fibre Channel coaxial headers	12
FiberJack	13
LC	14
MT-RJ	
MU	17
SG	18
Optical pigtail	
Reserved	20 21
HSSDC II	22
Copper Pigtail	23
Reserved	24
Vendor specific	28
	27
	2
	29
	30

Tab

5.18 INTERFACE SPECIFICATION

The following bit significant indicators define the electronic or optical interfaces that are supported by the transceiver Table 49. At least one bit shall be set in this field. This table is not backward compatible with the GBIC/SFP serial ID definition.

- 31 32 33 34 35 36 37 38 39
- 40
- 41
- 42

Addr	Bit	Description of transceiver	Addr	Bit	Description of transceiver
10 Gigabit Ethernet Compliance				SONET/S	SDH Codes - Interconnect
131	7	10GBASE-SR	135	7	I-64.1r
131	6	10GBASE-LR	135	6	I-64.1
131	5	10GBASE-ER	135	5	I-64.2r
131	4	Reserved	135	4	I-64.2
131	3	10GBASE-SW	135	3	I-64.3
131	2	10GBASE-LW	135	2	I-64.5
131	1	10GBASE-EW	135	1	Reserved
131	0	Reserved	135	0	Reserved
	10 Gigab	it Fibre Channel Compliance		SONET/	SDH Codes – Short Haul
132	7	1200-MX-SN-I	136	7	S-64.1
132	6	1200-SM-LL-L	136	6	S-64.2a
132	5	Extended Reach 1550 nm	136	5	S-64.2b
132	4	Intermediate Reach 1300 nm FP	136	4	S-64.3a
132	3	Reserved	136	3	S-64.3b
132	2	Reserved	136	2	S-64.5a
132	1	Reserved	136	1	S-64.5b
132	0	Reserved	136	0	Reserved
	. 10	Gigabit Copper Links		SONET/	SDH Codes – Long Haul
133	7	Reserved	137	7	L-64.1
133	6	Reserved	137	6	L-64.2a
133	5	Reserved	137	5	L-64.2b
133	4	Reserved	137	4	L-64.2c
133	3	Reserved	137	3	L-64.3
133	2	Reserved	137	2	Reserved
133	1	Reserved	137	1	Reserved
133	0	Reserved	137	0	Reserved
		Lower Speed Links		SONET/SL	OH Codes – Very Long Haul
134	7	1000BASE-SX / 1xFC MMF	138	7	V-64.2a

Addr	Bit	Description of transceiver	Addr	Bit	Description of transceiver
134	6	1000BASE-LX/1xFC SMF	138	6	V-64.2b
134	5	2xFC MMF	138	5	V-64.3
134	4	2xFC SMF	138	4	Reserved
134	3	OC 48-SR	138	3	Reserved
134	2	OC-48-IR	138	2	Reserved
134	1	OC-48-LR	138	1	Reserved
134	0	Reserved	138	0	Reserved

Table 49 Transceiver codes

5.19 ENCODING

The encoding bits indicate the serial encoding mechanisms that are supported by the particular transceiver. A one in a given bit position indicates support of that encoding mechanism. The defined encoding support bits are shown in <u>Table 50</u>.

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Table 50 Encoding Support Byte 139

Bit	Description of encoding mechanism	25 26
7	64B/66B	27
6	8B10B	28
5	SONET Scrambled	29 30
4	NRZ	31
3	RZ	32
2	Reserved	33
1	Reserved	34 35
0	Reserved	36

- 37 38
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5.20 BR, MINIMUM		1
	The minimum bit rate (BR, minimum) is specified in units of 100 Megabits per second, rounded off to the nearest 100 Megabits per second. The bit rate includes those bits necessary to encode and delimit the signal as well as those bits carrying data information. A value of 0 indicates that the min- imum bit rate is not specified and must be determined from the transceiver technology. The actual information transfer rate will depend on the en- coding of the data, as defined by the encoding value. Specific CDR rate support is indicated in Byte 164.	2 3 4 5 6 7 8 9
5.21 BR, MAXIMUM		10
	The maximum bit rate (BR, maximum) is specified in units of 100 Mega- bits per second, rounded off to the nearest 100 Megabits per second. The bit rate includes those bits necessary to encode and delimit the signal as well as those bits carrying data information. A value of 0 indicates that the maximum bit rate is not specified and must be determined from the trans- ceiver technology. The actual information transfer rate will depend on the encoding of the data, as defined by the encoding value. Specific CDR rate support is indicated in Byte 164.	11 12 13 14 15 16 17 18
5.22 LENGTH (STANDARD SI	INGLE MODE FIBER)-KM	19
	This value specifies the link length that is supported by the transceiver while operating in compliance with the applicable standards using single mode fiber. The value is in units of kilometers. A value of 255 means that the transceiver supports a link length greater than 254 km. A length field value of 0 for XFP modules indicates that the length should be the operating length specified by the supported standard <u>Table 49</u> .	 20 21 22 23 24 25 26
	ANDWIDTH 50 MM MULTIMODE FIBER)	27 28

5.23 LENGTH (EXTENDED BANDWIDTH 50 MM MULTIMODE FIBER)

This value specifies the link length that is supported by the transceiver while operating in compliance with the applicable standards using 2000 MHz*km (850nm) extended bandwidth 50 micron core multimode fiber. The value is in units of 2 meters. A value of 255 means that the transceiver supports a link length greater than 508 m. A length field value of 0 for XFP modules indicates that the length should be the operating length specified by the supported standard <u>Table 49</u>.

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Management interface

5.24 LENGTH (50 UM MULTIMODE FIBER)

This value specifies the link length that is supported by the transceiver while operating in compliance with the applicable standards using 500 MHz*km (850 and 1310nm) 50 micron core multimode fiber. The value is in units of meters. A value of 255 means that the transceiver supports a link length greater than 254 m. A length field value of 0 for XFP modules indicates that the length should be the operating length specified by the supported standard <u>Table 49</u>.

5.25 LENGTH (62.5 UM MULTIMODE FIBER)

This value specifies the link length that is supported by the transceiver while operating in compliance with the applicable standards using 200 MHz*km (850 nm) / 500 MHz*km (1310 nm) 62.5 micron core multimode fiber. The value is in units of meters. A value of 255 means that the transceiver supports a link length greater than 254 m. A length field value of 0 for XFP modules indicates that the length should be the operating length specified by the supported standard <u>Table 49</u>.

5.26 LENGTH (COPPER)

This value specifies the minimum link length that is supported by the transceiver while operating in compliance with the applicable standards using copper cable. The value is in units of meters. A value of 255 means that the transceiver supports a link length greater than 254 meters. A value of zero means that the transceiver does not support copper cables or that the length information must be determined from the transceiver technology. Further information about the cable design, equalization, and connectors is usually required to guarantee meeting a particular length requirement. This also specifies the total cable length of copper cable assemblies with integrated XFP's.

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5.27 DEVICE TECHNOLOGY

This byte contains information about the laser, detector and any cooling2technology. The defined identifier values are shown in Table 51 and Table 352.4

Table 51 Device Technology (Value of lower 4bits of Byte 147)

Bits	Description of physical device	
4-7	Transmitter technology (see <u>Table 52</u>)	
3	0: No wavelength control 1: Active wavelength control	
2	0: Uncooled transmitter device 1: Cooled transmitter	
1	Detector Type 0: PIN detector 1: APD detector	
0	0: Transmitter not Tunable 1: Transmitter Tunable	

Table 52 Transmitter Technology (Value of top 4bits of Byte 147)

Value	Description of physical device	
0000b	850 nm VCSEL	
0001b	1310 nm VCSEL	
0010b	1550 nm VCSEL	
0011b	1310 nm FP	
0100b	1310 nm DFB	
0101b	1550 nm DFB	
0110b	1310 nm EML	
0111b	1550 nm EML	
1000b	Copper or others	
001-1111b	Reserved	

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5.28 VENDOR NAME

The vendor name is a 16 character field that contains ASCII characters, left-aligned and padded on the right with ASCII spaces (20h). The vendor name shall be the full name of the corporation, a commonly accepted abbreviation of the name of the corporation, the SCSI company code for the corporation, or the stock exchange code for the corporation. At least one of the vendor name or the vendor OUI fields shall contain valid serial data. 7

5.29 CDR SUPPORT

The nominal XFP design has CDR technology on both the transmit and receive path. Individual XFP devices may or may not support all the standard 10G bit rates. This Byte indicates which rates are supported by the CDR. A value of 0 indicates no CDR support. <u>Table 53</u> defines the CDR support bits.

This Byte is also used to indicate which if any of the loopback modes are supported. A 1 in bit 0 indicates that XFI loopback is supported (controlled by the bits listed in <u>Table 34</u>). A 1 in bit 1 indicates that lineside (optical to optical) loopback is supported.

24 **Bits Description of physical device** 25 7 CDR support for 9.95 Gb/s 26 6 CDR support for 10.3 Gb/s 27 5 28 CDR support for 10.5 Gb/s 29 4 CDR support for 10.7 Gb/s 30 3 CDR support for 11.1 Gb/s 31 2 Reserved 32 33 1 Lineside Loopback Mode Supported 34 0 XFI Loopback Mode Supported 35

Table 53 CDR Support Byte 164

5.30 VENDOR OUI

The vendor organizationally unique identifier field (vendor OUI) is a 3-byte39field that contains the IEEE Company Identifier for the vendor. A value of40all zero in the 3-byte field indicates that the Vendor OUI is unspecified.41

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		2
5.31 VENDOR PN		2 3
	The vendor part number (vendor PN) is a 16-byte field that contains ASCII	4
	characters, left-aligned and padded on the right with ASCII spaces (20h),	5
	defining the vendor part number or product name. A value of all zero in	6
	the 16-byte field indicates that the vendor PN is unspecified.	7
		8
		9
5.32 VENDOR REV		10
	The vendor revision number (vendor rev) is a 2-byte field that contains	11
	ASCII characters, left-aligned and padded on the right with ASCII spaces	12
	(20h), defining the vendor's product revision number. A value of all zero in	13
	the 2-byte field indicates that the vendor PN is unspecified.	14
		15
		16 17
5.33 LASER WAVELENGTH		18
	Nominal transmitter output wavelength at room temperature. 16 bit value	19
	with byte 186 as high order byte and byte 187 as low order byte. The laser	20
	wavelength is equal to the 16 bit integer value divided by 20 in nm (units	04
	of 0.05nm). This resolution should be adequate to cover all relevant wave- lengths yet provide enough resolution for all expected DWDM applica-	22
	tions. For accurate representation of controlled wavelength applications,	23
	this value should represent the center of the guaranteed wavelength	24
	range.	25
		26
		27
5.34 LASER WAVELENGTH TO	LERANCE	28
	The guaranteed +/- range of transmitter output wavelength under all	29
	normal operating conditions. 16 bit value with byte 188 as high order byte	30
	and byte 189 as low order byte. The laser wavelength is equal to the 16	31
	bit integer value divided by 200 in nm (units of 0.005nm). Thus, the fol-	32
	lowing two examples:	33
		34
		35
	Example 1:	36
	10GBASE-LR Wavelength Range = 1260 to 1355 nm	37
	Nominal Wavelength in Bytes 186 - 187 = 1307.5 nm.	38 39
	Represented as INT(1307.5 nm $*$ 20) = 26150 = 6626h	39 40
		40
		42
		74

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April 2, 2003

XFP Specification

REVISON 3.1

5.37 POWER SUPPLY REQUIREMENTS

2 Bytes 192-195 contain information on the maximum current requirement of each of the four power supplies, as well as the maximum power dissipation of the modules. This information allows system vendors to do more 4 careful power supply and thermal dissipation management. The data 5 format for this information is described in Table 54 6

data address	bits	Description of Fields	
192	7-0	Maximum Power Dissipation Max power is 8 bit value * 20 mW.	
193	7-0	Maximum Total Power Dissipation in Power Down Mode Max Power is 8 bit value * 10 mW.	
194	7-4	Maximum current required by +5V Supply. Max current is 4 bit value * 50 mA. [500 mA max]	
194	3-0	Maximum current required by +3.3V Supply. Max current is 4 bit value * 100 mA.	
195	7-4	Maximum current required by +1.8V Supply Max current is 4 bit value * 100 mA.	
195	3-0	Maximum current required by -5.2V Supply. Max current is 4 bit value * 50 mA. [500 mA max]	

Table 54 Power Supply Related Fields

5.38 VENDOR SN

28 The vendor serial number (vendor SN) is a 16 character field that contains ASCII characters, left-aligned and padded on the right with ASCII spaces (20h), defining the vendor's serial number for the transceiver. A value of all zero in the 16-byte field indicates that the vendor SN is unspecified.

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5.39 DATE CODE

The date code is an 8-byte field that contains the vendor's date code in
ASCII characters. The date code is mandatory. The date code shall be in
the format specified by Table 55.243

Table 55 Date Code

Data Address	Description of field
212-213	ASCII code, two low order digits of year. $(00 = 2000)$.
214-215	ASCII code, digits of month ($01 = Jan$. through $12 = Dec$.)
216-217	ASCII code, day of month (01 - 31)
218-219	ASCII code, vendor specific lot code, may be blank

5.40 DIAGNOSTIC MONITORING TYPE

"Diagnostic Monitoring Type" is a 1 byte field with 8 single bit indicators describing how diagnostic monitoring is implemented in the particular transceiver. Bit indicators are detailed in <u>Table 56</u>.

Digital diagnostic monitors received power, transmitted power, bias current, supply voltage, and temperature. Additionally, alarm and warning thresholds must be written as specified in this document at locations 02 – 57 (see <u>Table 35</u>). Auxiliary monitoring fields are optional extensions to Digital Diagnostics

Unlike the system described in SFF-8472, the XFP digital diagnostics definition does not allow for the possibility of "external calibration". All digital diagnostic values must be internally calibrated and reported in the units defined in this document.

Bit 3 indicates whether the received power measurement represents average input optical power or OMA. If the bit is set, average power is monitored. If it is not, OMA is monitored.

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	Table 56	Diagnostic Monitoring Type	2
Data Address	Bits	Description	4
220	5-7	Reserved	
220	4	Module Respond to FEC BER 0= No BER Support, 1=BER Support	7
220	3	Received power measurement type 0 = OMA, 1 = Average Power	9 1
220	2	Reserved	1
220	0-1	Reserved	1

5.41 ENHANCED OPTIONS

"Enhanced Options" is a 1 byte field with 8 single bit indicators which describe the optional digital control and diagnostic features implemented in the transceiver, as well as optional operating modes (see <u>Table 57</u>).

The optional digital controls are the Soft TX Disable and Power down functions which allow the functions to be actuated via the 2-wire serial control bus.

The optional operating modes indicate the ability of the module to perform active FEC and wavelength tunability functions, as well as the ability to support the optional Synchronous REFCLK mode.

		E Contraction of the second seco	30
Data Address	Bits	Description	31
221	7	Module Supports Optional VPS	32
221	6	Optional Soft TX_DISABLE implemented	33
221	5	Optional Soft P_down implemented	35
221	4	Supports VPS LV regulator mode	36
221	3	Supports VPS bypassed regulator Mode	37
221	2	Active FEC control functions implemented	39
221	1	Wavelength tunability implemented	40
221	0	Optional CMU Support Mode	41
		*	42

Table 57 Enhanced Options

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5.42 AUXILIARY MONITORING

This standard defines two flexible auxiliary A/D monitoring channels. This2Byte, defined in Table 58 and Table 59 describes which quantities are3monitored by each auxiliary A/D channel.4

Table 58 Auxiliary A/D Types Byte 222

Bits	A/D Input	7
4-7	Aux A/D Input 1 (see <u>Table 59</u>)	9
0-3	Aux A/D Input 2 (see Table 59)	1
		1

Table 59 Auxiliary Input Types

Value	Description of physical device	
0000b	Auxiliary monitoring not implemented	
0001b	APD Bias Voltage (16 bit value is Voltage in units of 10 mV)	
0010b	Reserved	
0011b	TEC Current (mA) (16 bit value is Current in units of 100 uA)	
0100b	Laser Temperature (Same encoding as module temperature)	
0101b	Laser Wavelength (same Encoding as Bytes 58-59)	
0110b	+5V Supply Voltage (Encoded as described in section <u>5.6</u>)	
0111b	+3.3V Supply Voltage (Encoded as described in section <u>5.6</u>)	
1000b	+1.8V Supply Voltage (Encoded as described in section <u>5.6</u>)	
1001b	-5.2V Supply Voltage (Absolute Value Encoded as primary Voltage Monitor)	
1010b	+5V Supply Current (16 bit Value is Current in 100 uA)	
1101b	+3.3V Supply Current (16 bit Value is Current in 100 uA)	
1110b	+1.8V Supply Current (16 bit Value is Current in 100 uA)	
1111b	-5.2V Supply Current (16 bit Value is Current in 100 uA)	

		2
5.43 CC_EXT		2
	The check code is a one byte code that can be used to verify that the first	4
	31 bytes of extended serial information in the XFP is valid. The check	5
	code shall be the low order 8 bits of the sum of the contents of all the bytes	6
	from byte 192 to byte 222, inclusive.	7
		8
		9
5.44 VENDOR SPECIFIC ID FIE	LD	10
	Bytes 224-255 of Table 01h may be used for Vendor Specific ID functions.	11
		12
5.45 DESCRIPTION OF UPPER	MEMORY MAP TABLE 02H – USER EEPROM DATA	13
	Table 02h is provided as user writable EEPROM. The host system may	14
	read or write this memory for any purpose.	15
		16 17
		18
5.46 DESCRIPTION OF UPPER	MEMORY MAP TABLES 03H – 7FH – VENDOR SPECIFIC FUNCTIONS	19
	Tables 03h-7Fh are reserved for Vendor Specific functions.	20
		21
		22
	MEMORY MAP TABLES 80H – FFH – RESERVED	23
5.47 DESCRIPTION OF OPPER		24
	Tables 80h-FFh are reserved.	25
		26
		27
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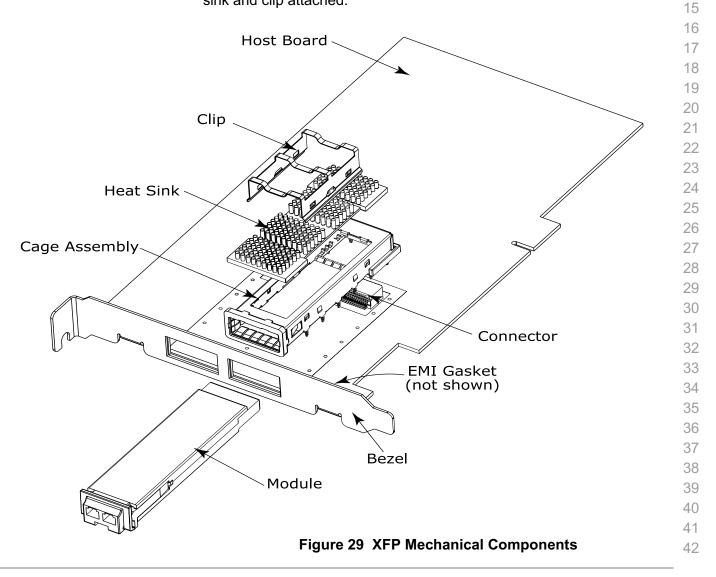
14

CHAPTER 6: MECHANICAL AND BOARD DEFINITION

6.1 INTRODUCTION

The mechanical components defined in this section are illustrated in Figure 29. The module, clip and connector dimensions are constant for all applications. While the bezel, cage assembly, EMI gasket and heat sink can be designed and/or adjusted for the individual application.

The relatively small form factor of the XFP module combined with an adaptable heatsink option allows host system design optimization of module location, heatsink shape/dimension/fins design, and airflow control. The module can be inserted and removed from the cage with the heat sink and clip attached.



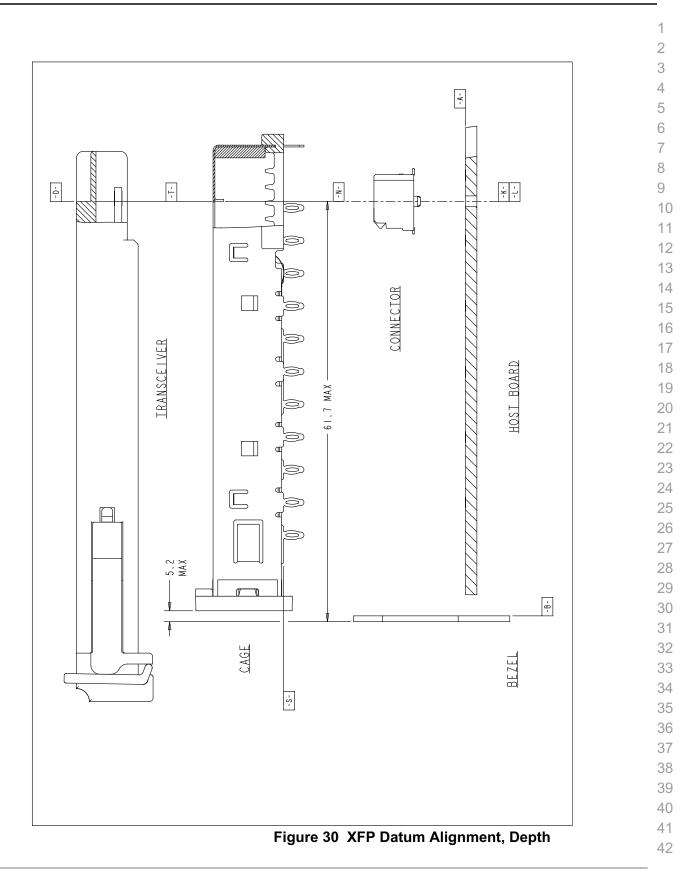
6.2 XFP DATUMS AND COMPONENT ALIGNMENT

2 A listing of the datums for the various components is contained in Table 60 The alignments of some of the datums are noted. The relationship of 3 the Transceiver, Cage, and Connector relative to the Host Board and 4 Bezel is illustrated in Figure 30 by the location of the key datums of each 5 of the components. 6

Table 60 Definition of Datums

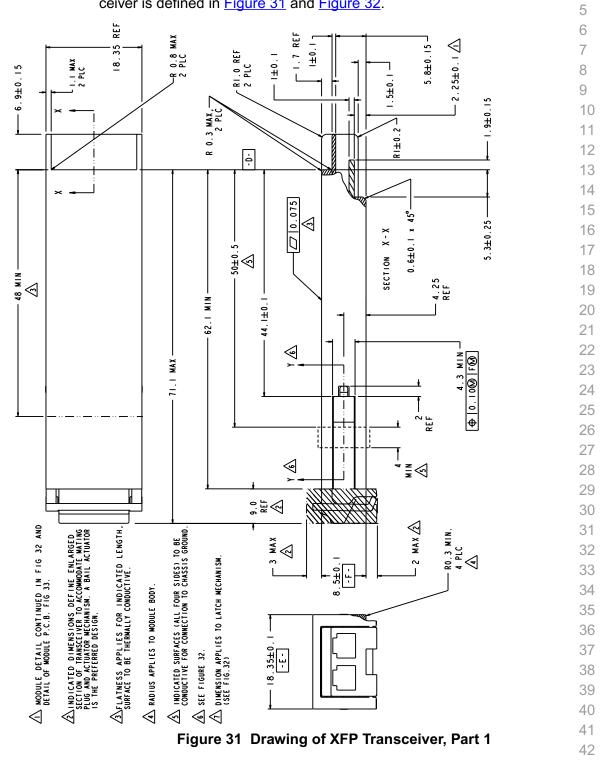
Datum	Description	Figure #	
А	Host Board Top Surface	Figure 35	
В	Back surface of bezel (See Section 6.8)	Figure 37 & Figure 38	
С	Distance between Connector alignment post thru holes on host board ¹	Figure 36	
D	Hard stop on transceiver ²	Figure 31	
Е	Width of transceiver ¹	Figure 31	
F	Height of transceiver housing	Figure 31	
G	Width of transceiver pc board ¹	Figure 33	
Н	Leading edge of transceiver pc board	Figure 33	
J	Top surface of transceiver pc board	Figure 33	
K	Host Board thru hole #1 to accept Connector alignment post ²	Figure 35 & Figure 36	
L	Host Board thru hole #2 to accept Connector alignment post ²	Figure 35 & Figure 36	
М	Width of bezel cut out ¹	Figure 37 & Figure 38	
Ν	Connector alignment pin ²	Figure 39	
Р	Width of inside of cage at EMI gasket (when fully compressed) ¹	Width of inside of cage at EMI gasket (when fully compressed) 1 Figure 41	
R	Height of inside of cage at EMI gasket (when fully compressed)	Figure 41	
S	Seating plane of cage on host board	Figure 41	
Т	Hard stop on cage ²	Figure 41	
U	Length of opening at top of cage to accept heat sink Datum Z	Figure 41	
V	Length of clip	Figure 42	
W	Surface of keep out area that clip contacts on heat sink	Figure 43	
X & Y	Host board horizontal and depth datums established by customers' fiducials	Figure 35	
Z	Length of boss on heat sink that fits inside of cage Datum U	Figure 43	
AA	Width of heat sink surface that fits into clip ¹	Figure 43	
	f datums C, E, G, M, P and AA are aligned on the same vertical axis , L, N and T are aligned when assembled (see <u>Figure 30</u>)		

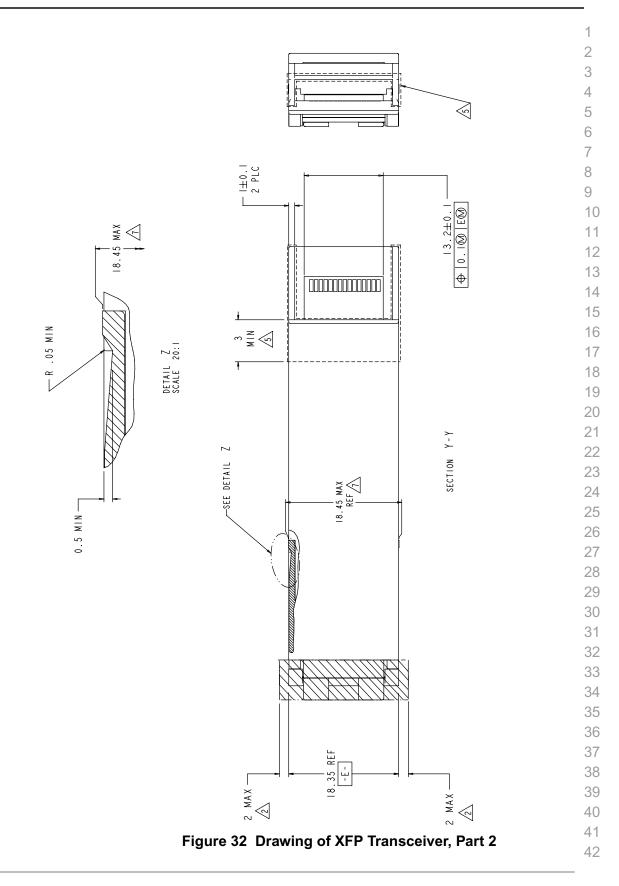
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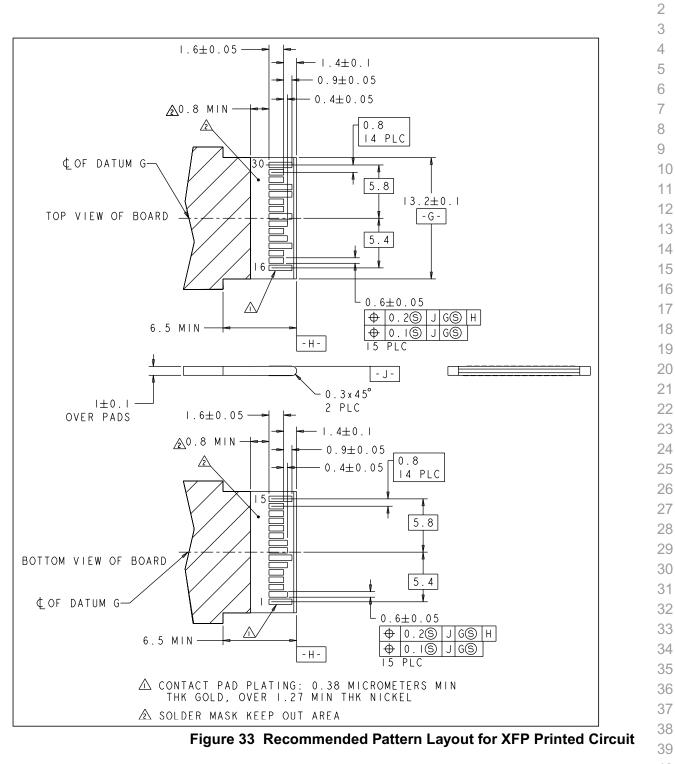
6.3 XFP TRANSCEIVER PACKAGE DIMENSIONS

A common mechanical outline is used for all XFP transceivers. The preferred method of removing the transceiver from the cage assembly is by a bail type actuation method. The package dimensions for the XFP transceiver is defined in Figure 31 and Figure 32.

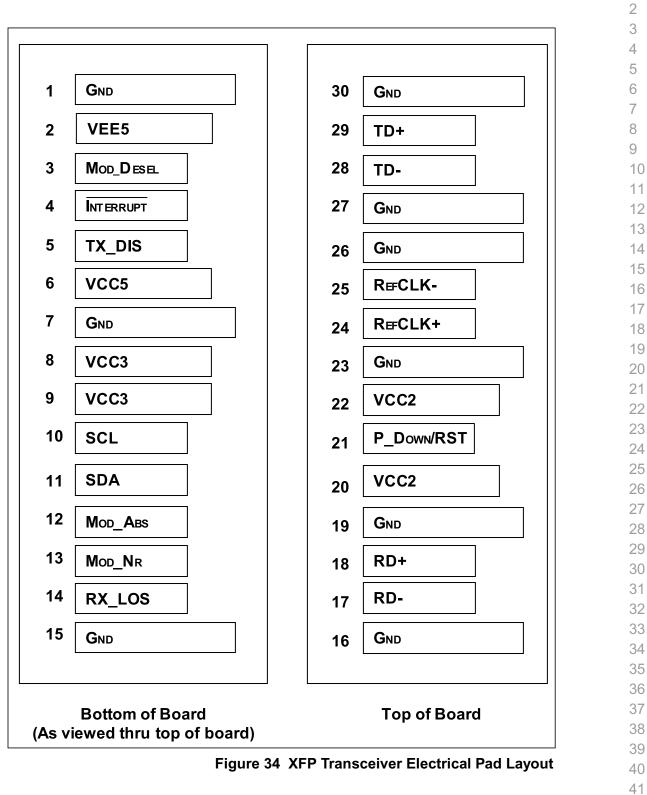




6.4	MATING OF XFP TRANSCEIVER PCB TO XFP ELECTRICAL CONNECTOR	1
	The XFP transceiver contains a printed circuit board that mates with the	2
	XFP electrical connector. The pads are designed for a sequenced mating:	3
	First mate – ground contacts	4
	-	5
	Second mate – power contacts	6 7
	Third mate – signal contacts	7 8
	The design of the mating portion of the transceiver printed circuit board is	9
	illustrated in <u>Figure 33</u> and the electrical pad layout is illustrated in <u>Figure</u> . <u>34</u> . The recommended contact pad plating for the printed circuit board is	10
	0.38 micrometers minimum gold over 1.27 micrometers minimum thick	11
	nickel.	12
		13
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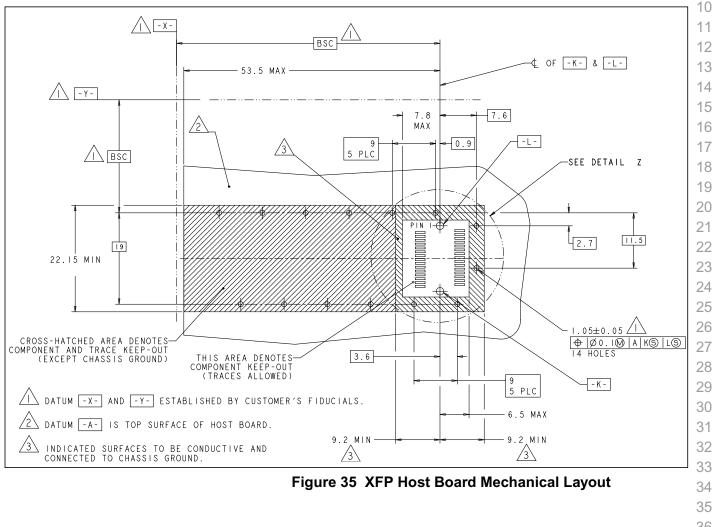


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6.5 HOST BOARD LAYOUT

Host board should be laid out in accordance with the specific connector2Mfg. specifications. A typical host board mechanical layout for attaching3the XFP Connector and Cage System is shown in Figure 35 and Figure436. The location of the pattern can vary relative datums selected by the
customers. Location of the pattern on the host board is application spe-
cific. See section 6.8 for further details.6



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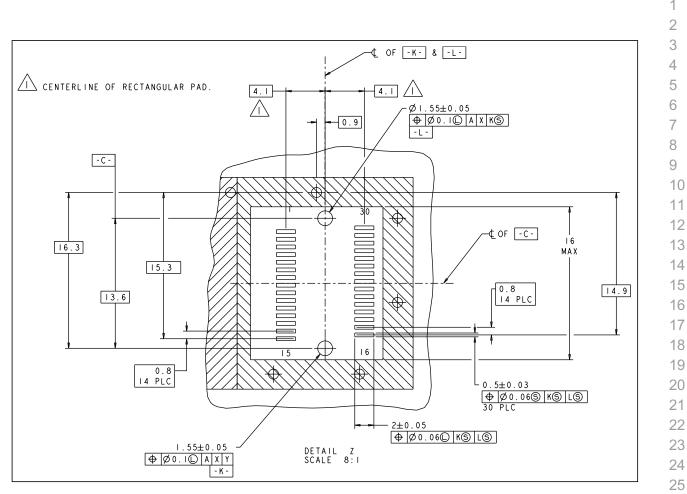


Figure 36 XFP Detail Host Board Mechanical Layout, Detail Z

6.6 INSERTION, EXTRACTION AND RETENTION FORCES FOR XFP TRANSCEIVERS

The requirement for insertion forces, extraction forces and retention forces are specified in <u>Table 61</u>.

Architecture Note

The XFP cage and module design combination must ensure excessive force applied to a cable does not damage the XFP cage. If any part is damaged by excessive force, it should be the cable or the media module and not the cage which is part of the host system. 26 27 28

Table 6	1 Insertion,	Extraction, a	nd Retentio	n Forces
Measurement	Minimum	Maximum	Units	Comments
XFP transceiver insertion	0	40	Newtons	
XFP transceiver extraction	0	30	Newtons	
XFP transceiver retention	90	N/A	Newtons	No damage to transceiver below 90N
Cage retention (Latch strength)	180	N/A	Newtons	No damage to the latch below 180N
Cage retention in Host Board	133	N/A	Newtons	Force to be applied in a vertical direction with no damage to the cage.
Insertion / removal cycles, connec- tor/cage	100	N/A	cycles	
Insertion / removal cycles, XFP Transceiver	50	N/A	cycles	

6.7 COLOR CODING AND LABELING OF XFP TRANSCEIVERS

An exposed feature of the XFP transceiver (a feature or surface extending outside of the bezel) shall be color coded as follows:

- Beige for 850nm •
- Blue for 1310nm
- White for 1550nm

Each XFP transceiver shall be clearly labeled. The complete labeling need not be visible when the XFP transceiver is installed and the bottom of the device is the recommended location of the label. Labeling shall include:

- Appropriate manufacturing and part number identification •
- Appropriate regulatory compliance labeling
- A manufacturing traceability code

Also the label should include clear specification of the external port characteristics such as:

- Optical wavelength
- Required fiber characteristics
- Operating data rate
- Interface standards supported
- Link length supported.

The labeling shall not interfere with the mechanical, thermal and EMI features.

6.8 BEZEL AND EMI GASKET DESIGN FOR SYSTEMS USING XFP TRANSCEIVERS

Host enclosures that use XFP devices should provide appropriate clearances between the XFP transceivers to allow insertion and extraction without the use of special tools and a bezel enclosure with sufficient mechanical strength. For most systems a nominal centerline to centerline spacing of 23.5 mm (0.925") is sufficient. See Figure 37 and Figure 38 for the recommended bezel designs. Figure 37 illustrates the single sided mounting and Figure 38 illustrates the double sided mounting method. The minimum recommended host board thickness for double sided mounting of the assemblies is 3.0 mm minimum.

There are many options for a bezel EMI gasket that functions as a seal between the bezel and the front of the cage. The design of the bezel EMI gasket and the materials used for the gasket are application specific. The preferred method is to fasten the gasket to the back of the bezel with a pressure sensitive adhesive. Assembly of the host board to the bezel will compress the gasket to the recommended range specified by the bezel EMI gasket manufacturer. The surface in the back of the bezel that is in contact with the bezel EMI gasket must be low resistance and connected to ground.

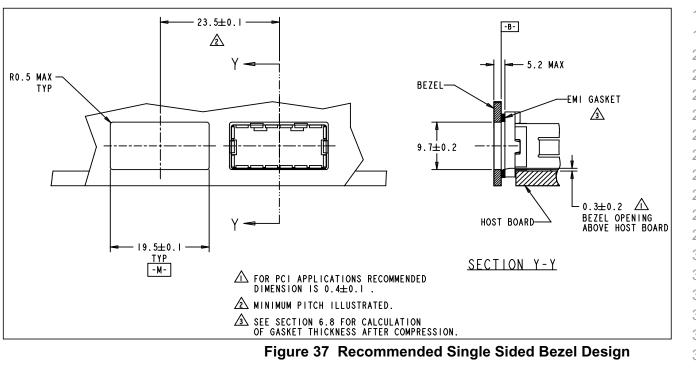
The gasket thickness after compression can be calculated as follows:

GT = BKL - 56.3 ± 0.2mm.

Where:

- GT is gasket thickness in the compressed state.
- BKL is the distance from the back of the bezel Datum B to the centerline of Datums K & L. See Figure 35 and Figure 36 (Note: dimension from front of bezel to centerline of Datums K & L must not exceed 61.7mm, see Figure 30).
- The 56.3 \pm 0.2mm dimension is the distance from the front of the cage to the hard stop, Datum T. See Figure 41.

The XFP transceiver insertion slot should be clear of nearby moldings and covers that might block convenient access to the latching mechanisms, the XFP transceiver, or the cables connected to the XFP transceiver.



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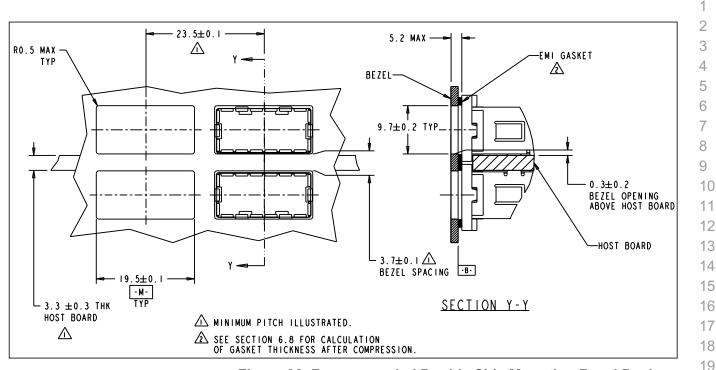


Figure 38 Recommended Double Side Mounting Bezel Design

6.9 XFP CONNECTOR MECHANICAL SPECIFICATIONS

The XFP Connector is a 30-contact, right angle surface mount connector24and available from several manufacturers¹. An example connector such25as 788862-2 manufactured by Tyco is shown in Figure 39. Newer versions26of this connector are available from Tyco, Molex, and Harting with improved electrical performance.27

1. 788862C (Standard PT) and 1367500-1 (New Improved PT Version), Mfg. by39Tyco Electronics, www.tycoelectronics.com.40Parecon 30 Mfg. by Harting-Electro-Optics, www.Harting-Electro-Optics.com.4174441, Mfg. by Molex Inc., www.molex.com.42

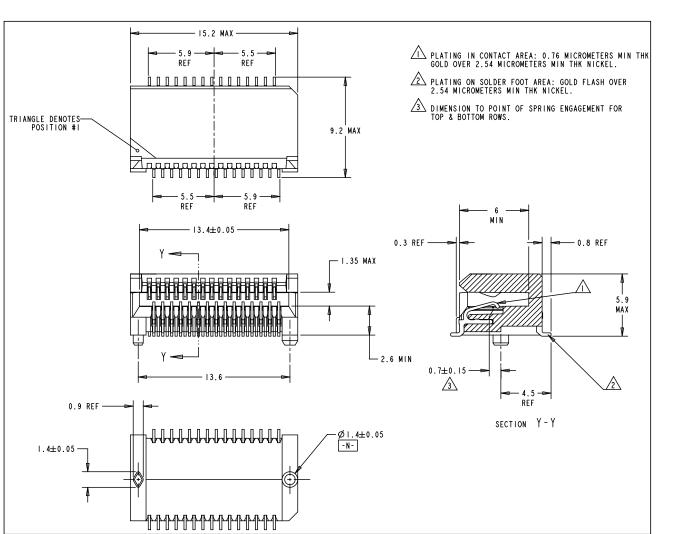


Figure 39 XFP Transceiver Connector Illustration

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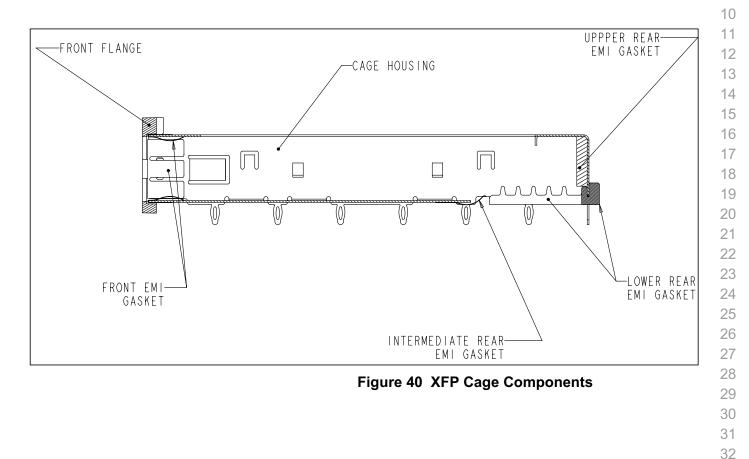
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6.10 XFP CAGE ASSEMBLY DIMENSIONS

The Cage Assembly requires EMI shielding capability for both front and back portions of the cage along with providing guidance for the connector, retention of the transceiver and features for heat sink attachment. The location of the EMI gaskets for a reference design is illustrated in Figure 40 and a description of each EMI gasket is described in the sections below. The dimensional requirements for the cage are illustrated in Figure 41.



6.10.1 XFP CAGE HOUSING

The metal cage has compliant leads for assembly to the host board. The 34 cage material is copper alloy and the recommended plating options are: 35

- Tin-lead plate 2.54 micrometers minimum over copper flash
- Tin plate 2.54 micrometers minimum over 0.76 micrometers minimum nickel

or the equivalent materials.

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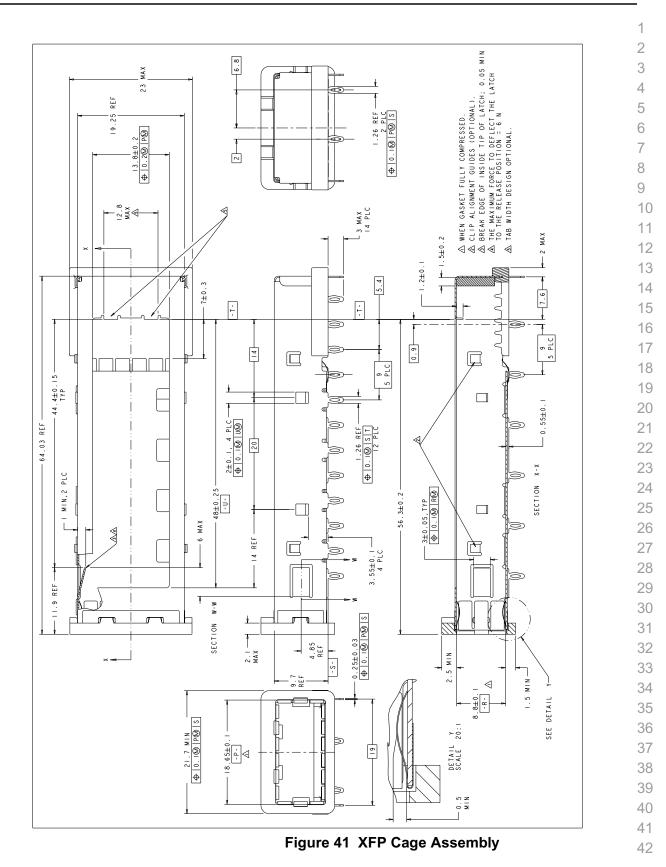
6.10.2 XFP CAGE REAR EMI	GASKETS	1
	The purpose of the rear EMI Gaskets is to block any emissions that are	2
	emanating from the rear of the transceiver and carry them to chassis	3
	ground in the Host Board by directly contacting the transceiver.	4
		5
		6
6.10.2.1 XFP UPPER REAR EMI	GASKET	7
	The Upper Rear EMI Gasket is fastened to the rear inside surface of the	8
	cage with pressure sensitive adhesive. The recommended material for	9
	this gasket is conductive foam.	10 11
		12
		13
6.10.2.2 LOWER REAR EMI GAS	;KET	14
	The Lower Rear EMI Gasket is fastened to the bottom of the cage and	15
	contacts the bottom surface of the transceiver skirt. The recommended	16
	material for this gasket is a conductive elastomer.	17
6 10 2 3 XEP INTERMEDIATE RE	AR CAGE EMI GASKET (FINGER STOCK)	18
	The Intermediate Rear EMI Gasket is fastened to the bottom of the cage	19
	and simultaneously contacts the transceiver and Host Board. The pre-	20
	ferred design is illustrated as a series of metal springs consisting of a	21
	copper alloy material. The recommended plating options are:	22
	Tip load plate 2.54 migrometers minimum over conner fleeb	23
	Tin-lead plate 2.54 micrometers minimum over copper flash	24
	Tin plate 2.54 micrometers minimum over copper flash	25 26
	or equivalent materials.	20
		28
6 10 3 YED CAGE EPONT CA	GE EMI GASKET (FINGER STOCK)	29
0.10.3 AFF CAGE FRONT CA		30
	The purpose of the Front EMI Gasket is to create a seal between the transceiver and the inside surface of the cage. The preferred design is il-	0.4
	lustrated as a series of metal springs that are fastened to the front of the	
	cage and held in place by the front flange. The Front EMI Gasket material	
	is copper alloy and the recommended plating options are:	34
	Tin-lead plate 2.54 micrometers minimum over copper flash	35
	 Tin plate 2.54 micrometers minimum over copper flash 	36
	 or equivalent materials. 	37
		38
		39 40
		40
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6.10.4 XFP FRONT FLANGE

The purpose of the front flange is to provide a flat surface to contact the Bezel EMI Gasket (customer supplied) that is mounted on the back side of the bezel. It also serves as a collar to retain the Front EMI Gasket and to provide strength to the cage housing. The front flange material is zinc alloy and the recommended plating options are:

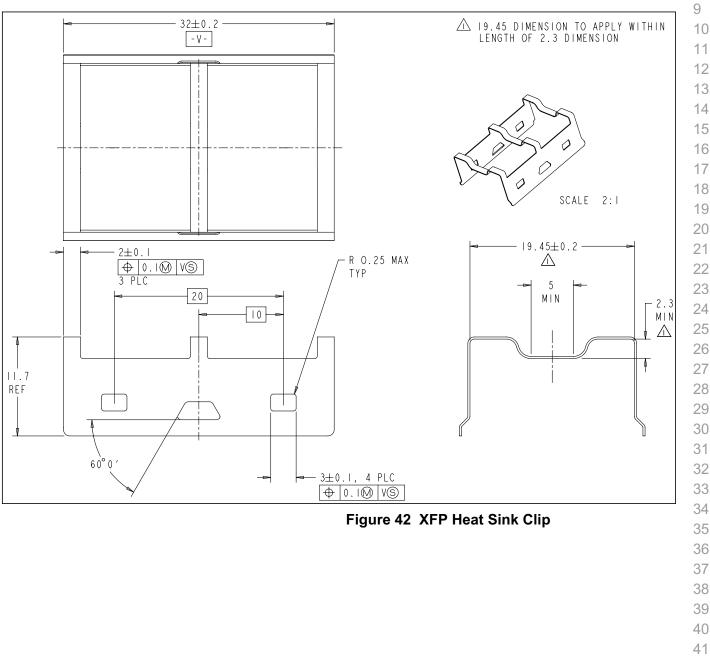
- Tin-lead plate 2.54 micrometers minimum over copper flash
- Tin plate 2.54 micrometers minimum over 0.76 micrometers mini 11
 mum nickel
 12

or equivalent materials.



6.11 XFP HEAT SINK CLIP DIMENSIONS

The heat sink clip is defined in Figure 42. When fastened to the cage, the clip will provide a minimum force of 5 Newtons at the interface of the heat sink and XFP transceiver. The clip is designed to permit a heat sink to be fastened to the cage and to expand slightly during transceiver insertion in order to maintain a contact force between the transceiver and heat sink.

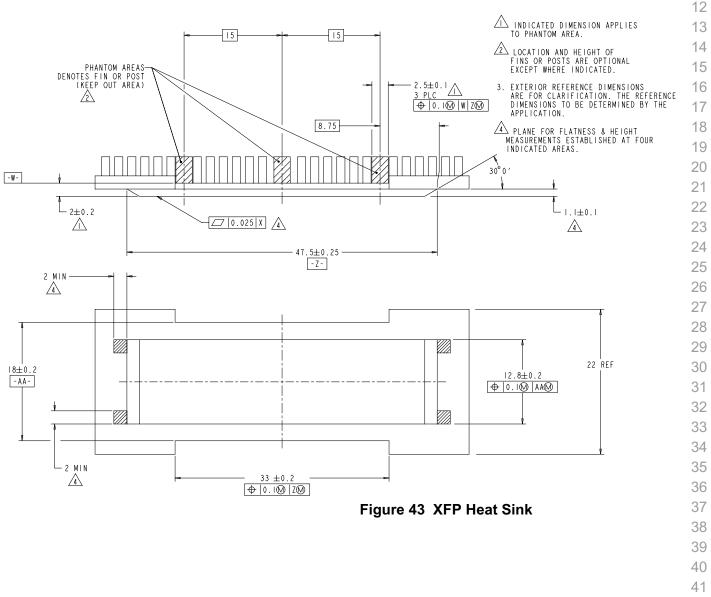


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6.12 AN EXAMPLE XFP HEAT SINK

The heat sink is illustrated in Figure 43. Critical dimensions to insure that 4 the heat sink will be compatible with the Heat Sink Clip are defined. The 5 configuration of the fins or posts is application specific along with the outside envelope. The heat sink includes a beveled edge which "rides up" the leading edge of the transceiver as the transceiver is inserted into the cage assembly. The recommended material for the heat sink is aluminum and the surface treatment for the transceiver contacting surface can be 9 anodizing or nickel plating.



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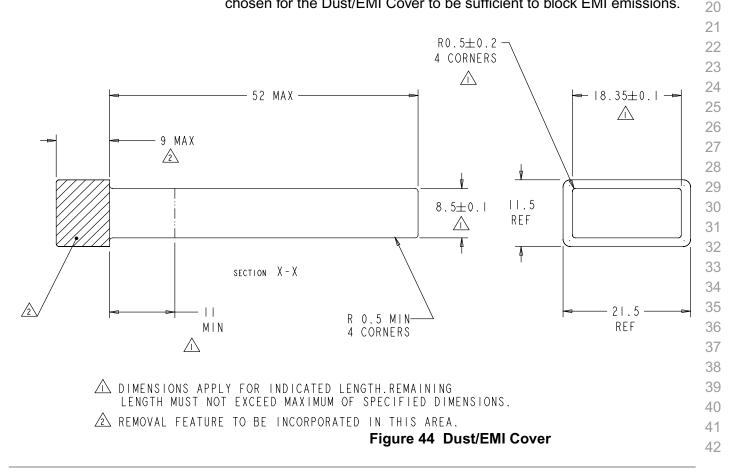
6.13 ENVIRONMENTAL AND THERMAL The XFP module electrical specifications shall be met at least from 0-70 degree C case temperature with an altitude range 0-3km. The system designer is responsible for ensuring the maximum tempera-

The system designer is responsible for ensuring the maximum temperatures do not exceed requirements of IEC 60950 section 4.5.1 and table 4B. If case temperatures of the transceiver, cage, or heatsink exceed 70C, appropriate labeling must be attached per table 4B note 6.

See <u>Appendix F</u>: for recommended test parameters and guidelines used in characterization of module thermal performance.

6.14 DUST/EMI COVER

In order to prevent contamination of the internal components and to optimize EMI performance, it is recommended that a Dust/EMI Cover be inserted into cage assemblies when no transceiver is present. See Figure 44 for the recommended design. During installation, the front flange on the cover shall be seated against the front surface of the bezel to prevent dust from entering the equipment. The conductivity of the materials chosen for the Dust/EMI Cover to be sufficient to block EMI emissions.



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APPENDIX A: APPLICATION REFERENCE MODEL

Application reference model defines a set of overlapping compliance and measurements point to validate components and system. The reference model objective are:

- Satisfy the need for interoperablity at the electrical level.
- Allow for independent validation of host board, Module, and ASIC/SerDes.

A.1 ASIC/SERDES COMPLIANCE TESTING

ASIC/SerDes transmitter and receiver are tested on a DUT board Figure 45 with minimum trace length to avoid degradation due to traces¹. The compliance point are as the following:

- A: the ASIC/SerDes Output. The applicable measurements are:
 - Eye Mask
 - Output Jitter
 - Return Loss S22.
- D: the ASIC/SerDes Input. The applicable measurement are:
 - Input stress sensitivity
 - Jitter tolerance
 - Return Loss S11.

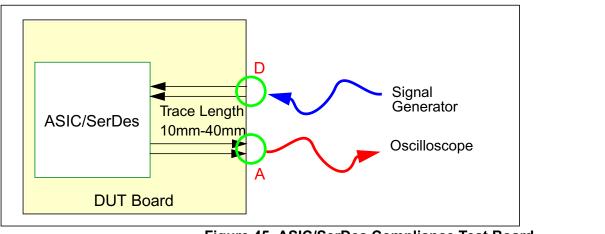


Figure 45 ASIC/SerDes Compliance Test Board

1. DUT board may use superior material to eliminate excess loss, but the construction should be manufacturable by standard PCB process. Trace length are recommended to be shorter than 40 mm and greater than 10mm.

A.2	Ноѕт	Sys	TEM COMPLIANC		1
				Board ¹ Figure 46 in place of the XFP module. The compliance point are as the following:	2 3 4 5
				B: Host system Output. The applicable measurements are:Eye Mask	6 7 8
				• Oulput Siller	9
				Return Loss S22.	10
					11
					12
					13
					14 15
					16
				Connector	17 18
			ASIC/SerDes	Signal Generator	19 20 21 22
					23
				D	24 25
				Figuro 16 Host System Compliance Test Diagram	26
					27 28
					20 29
A.3	XFPI	VIODI	ULE COMPLIANC		30
				XFP modules are validated by testing them with a Module Compliance	31
				Test Board ² Figure 47 with 30 position XFP connector. The compliance points are as the following:	32
				points are as the following.	33
				B': Host system Output. The applicable measurement are:	34
					35
				Jitter tolerance	36
				Poturn Loss S11	37 38
					39
				1. Those reserved is a passive of active device that can be inserted in place of	40
				2. Module Compliance Test Board is test board with XFP 30 position connector	41
				and 10 mm-40mm of traces on low loss dielectric material.	42

• C: XFP module output. The applicable measurements are:

- Eye Mask
- Jitter output
- Return Loss S22.

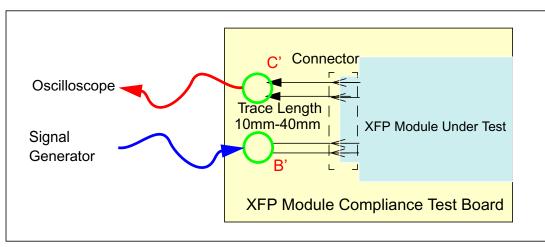


Figure 47 XFP Module Compliance Test Diagram

A.4 HOST SYSTEM COMPLIANCE TEST BOARD

Testing compliance to specifications in a high-speed system is delicate and requires thorough consideration. The measurement point must be low impedance and in many cases high impedance probing is prohibited and would result in unreliable results. Using a common Host Test Board that allows predictable, repeatable and consistent results among system vendors will help to assure consistency and true compliance in the testing of Host Systems. Host Compliance board provided courtesy of Intel Corporation.

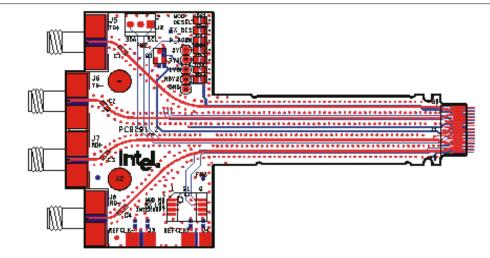


Figure 48 Host System compliance Test Board

A.4.1 HOST SYSTEM COMPLIANCE BOARD MATERIAL AND LAYER STACK-UP

Test board stack-up based on Nelco Roger3003/ FR4-6 with six layer shown below.

1. Layer	Primary Side	
0.010" Ro	gers 3003	
2. Layer	Ground	
0.006" FR4-6 Prepreg		
3. Layer	Signal 1	
0.008" FR-4 Laminate		
4. Layer	Signal 2	
0.006" FR4	4-6 Prepeg	
5. Layer	Power	
0.010" Ro	gers 3003	
6. Layer	Secondary Side	

Host System based on Roger3003 help reduce PCB loss, alternatively a 1 short FR4-6 terminated in coaxial cable may be used. 2

A.4.2 HOST SYSTEM COMPLIANCE TEST BOARD PARTLIST

The host system compliance test board part list is given below.

Table 62 Host System Compliance Test Board Part List

Qty	RefDes	Value	Description
4	C1, C2, C3, C4, C5, C6, C7, C8	100nF	Capacitor Ceramic SMA 0603 10% 16V X7R
3	DS1, DS2, DS7		SMA LED Green
4	DS3, DS4, DS5, DS6		SMA LED Blue
1	J1		Non Component (30 Poled XFP Edge Connector)
1	J2		Molex Square Pin Header with friction lock 3 pin pitch 2.54 mm
2	J3, J4,		SMA Connector Edge SMD
4	J5, J6, J7, J8		SMA Connector Straight on RPC footprint, short center pin
1	Q1		General Purpose Silicon NPN BJT
3	R1, R2, R3	100R	Resistor SMD 0603 5%
3	R4, R7, R8	1K	Resistor SMD 0603 5%
1	R5	10R	Resistor SMD 0603 5%
1	R9	10K	Resistor SMD 0603 5%
1	S1		Dil SMD switch 4x2 pol spacing 1.27mm

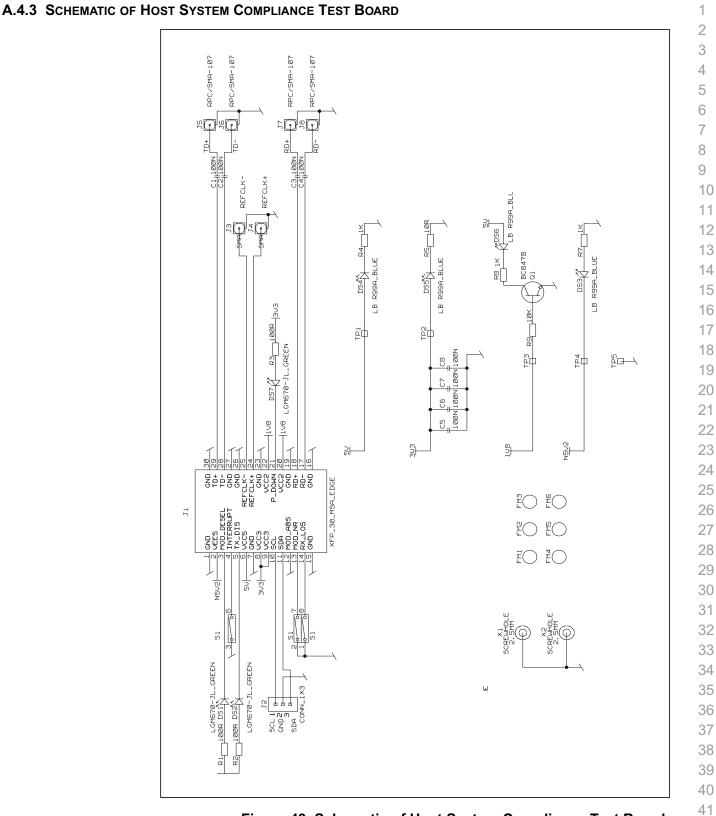


Figure 49 Schematic of Host System Compliance Test Board

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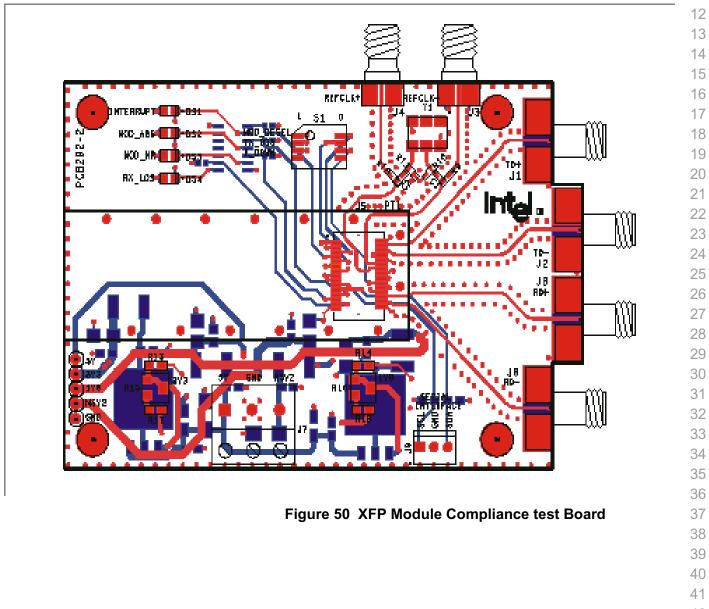
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A.4.4 GERBER FILE AND S PARAMETER MEASUREMENTS

Please see http://www.xfpmsa.org.

A.5 XFP MODULE COMPLIANCE TEST BOARD

The Module Compliance Test Board allows predictable, repeatable and consistent results among Module vendors and will help to assure consistency and true compliance in the testing of modules. Module Compliance Test provided courtesy of Intel Corporation.



A.5.1 XFP MODULE BOARD MATERIAL AND LAYER STACK-UP

XFP module compliance test board based on a four layer Rogers 3003 / 2 FR4-6 material shown below: 3

1. Layer	Primary Side		
0.010" Rogers 3003			
2. Layer	Ground		
0.040" FR4-6 Prepreg			
3. Layer	Power		
0.010" Rogers 3003			
4. Layer	Secondary side		

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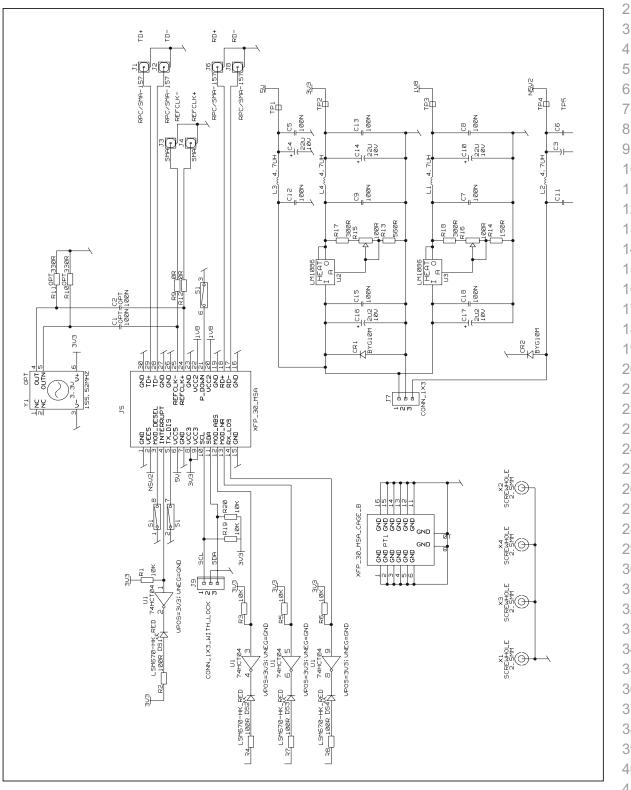
A.5.2 XFP MODULE COMPLIANCE BOARD PARTLIST

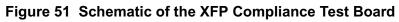
Component part list for the XFP compliance test board is given below.

Table 63 XFP Module Compliance Test Board Part List

Q ty	RefDes	Value	Description
4	C3, C4, C10, C14	22µF	Capacitor Tantalum SMD B 10% 10V
10	C5, C6, C7, C8, C9, C11, C12,	100 nF	Capacitor Ceramic SMA 0603 10% 16V X7R
2	C16, C17	2.2µF	Capacitor Tantalum SMD B 10% 10V
2	CR1, CR2		General Purpose Silicon Rectifier SMD Diode
3	DS1, DS2, DS3, DS4		SMA LED RED
4	J1, J2, J6, J8		SMA Connector Straight on RPC footprint, short center pin
2	J3, J4,		SMA Connector Edge SMD
1	J6		30 Pos XFP Right Angle SMD Host Connector with 0.8 mm Pitch
1	J7		Terminal Block PCB 3 Way
1	J9		Molex Square Pin Header with friction lock 3 pin pitch 2.54 mm pin
4	L1, L2, L3, L4	4.7µF	Inductor SMD 2220 4.7 µH 10%
1	PT1		XFP Cage for 30 Position PT Connector
4	R1, R3, R5, R6	10K	Resistor SMD 0603 5%
2	R9, R12	0R	Resistor SMD 0603 5%
1	R13	560R	Resistor SMD 0603 5%
1	R14	150R	Resistor SMD 0603 5%
2	R15, R16	100R	Resistor SMD 0603 5%
2	R17, R18	300R	Resistor SMD 0603 5%
2	R19, R20	10K	Resistor SMD 0603 5%
4	R2, R4, R7, R8	100R	Resistor SMD 0603 5%
5	TP1, TP2, TP3, TP4, TP5		Test pin 1mm Black
1	U1		74HCT04 Hex Inverting Gates SMD
2	U2, U3		1.5A Low Dropout Positive Regulator SMD
1	S1		Dil SMD switch 4x2 pol spacing 1.27mm
		Option	nal Components
2	C1, C2	100nF	Capacitor Ceramic SMA 0603 10% 16V X7R
2	R10, R11	330R	Resistor SMD 0603 5%
1	Y1		155.52 Crystal Oscillator (XO) Small SMD







Application Reference Model

A.5.4 GERBER FILES AND MEASURED S-PARAMETERS	1
Please see http://WWW.xfpmsa.org.	2
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APPENDIX B: XFI CHANNEL MEASUREMENTS AND MODELING

B.1 SYSTEM OVERVIEW

6 This Appendix provides design guidelines for the high-speed electrical in-7 terfaces found in XFP applications. A fundamental feature of the XFP 8 specification is that the electrical transceiver ASIC is positioned on the 9 system (Host) printed circuit board (PCB) rather than within the optical 10 transceiver module. Figure 52 depicts a typical system block diagram of 11 an end-to-end electrical channel for XFP applications. The block diagram includes a transceiver board that exists within the XFP module, a 30-pin 12 hot swappable connector, a host board, and a BGA package. Although 13 most host board designers will not have any direct control over the trans-14 ceiver ASIC BGA package, it is nevertheless important to mention that the 15 package can be simulated, designed, and included in channel simulations 16 at 10Gb/s speeds. 17

Simulations and measurements of this electrical channel are discussed to provide guidelines on XFI design. Broadcom Corporation provided the transceiver board, host board, and electrical measurements; ASAT provided the BGA package model; Ansoft Corporation performed simulations.

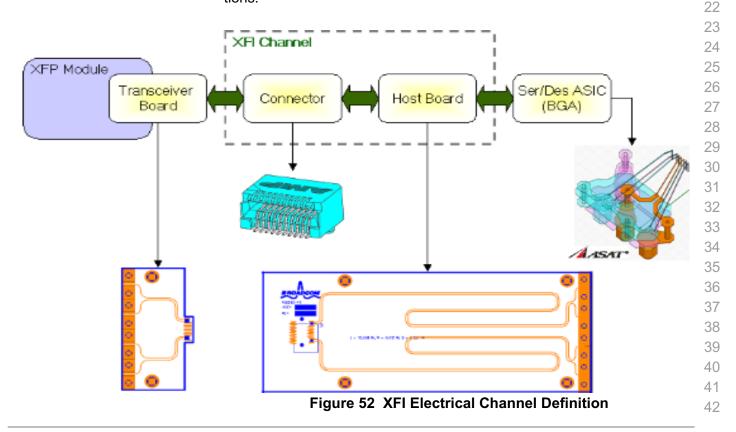


Figure 53depicts the stack up for the Broadcom reference board. Total1board thickness is 36mils and the board material is Nelco FR4-13 with ε r2= 4.0 and a loss tangent of 0.016. All traces are 1/2 oz. copper.3

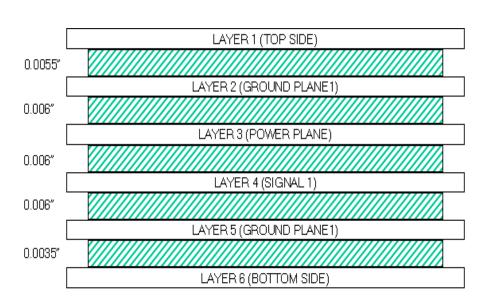
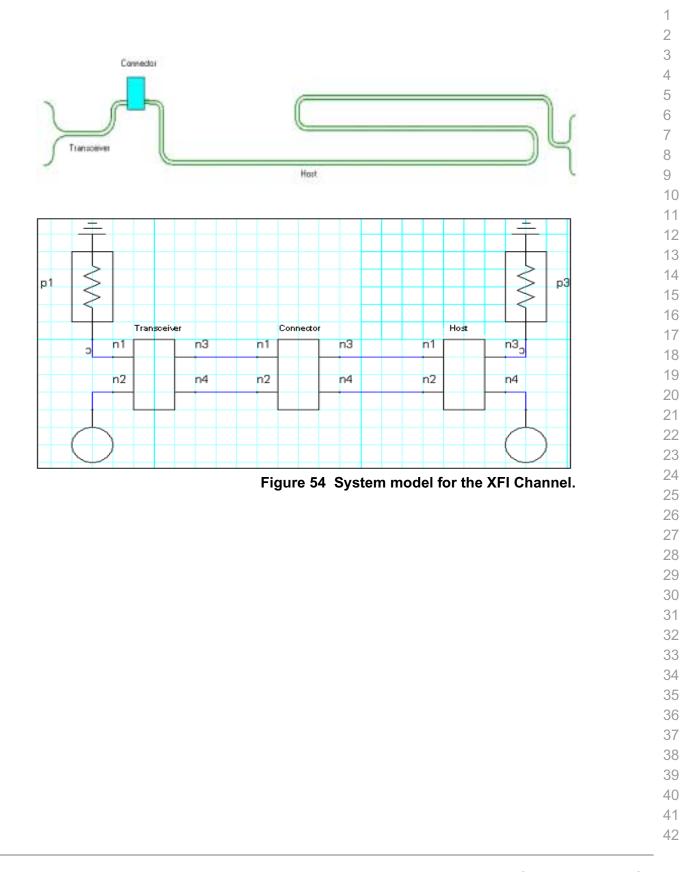
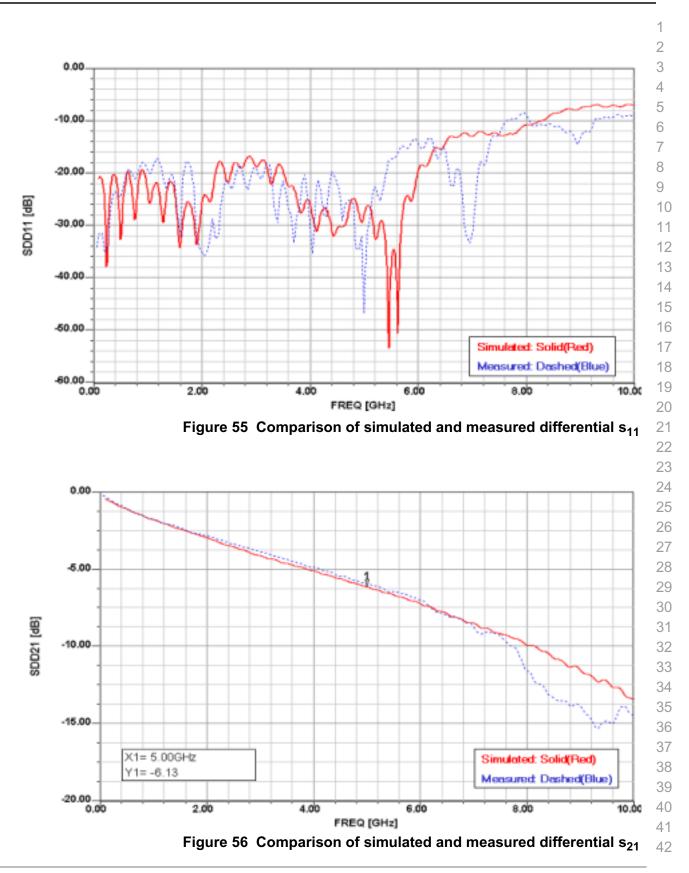


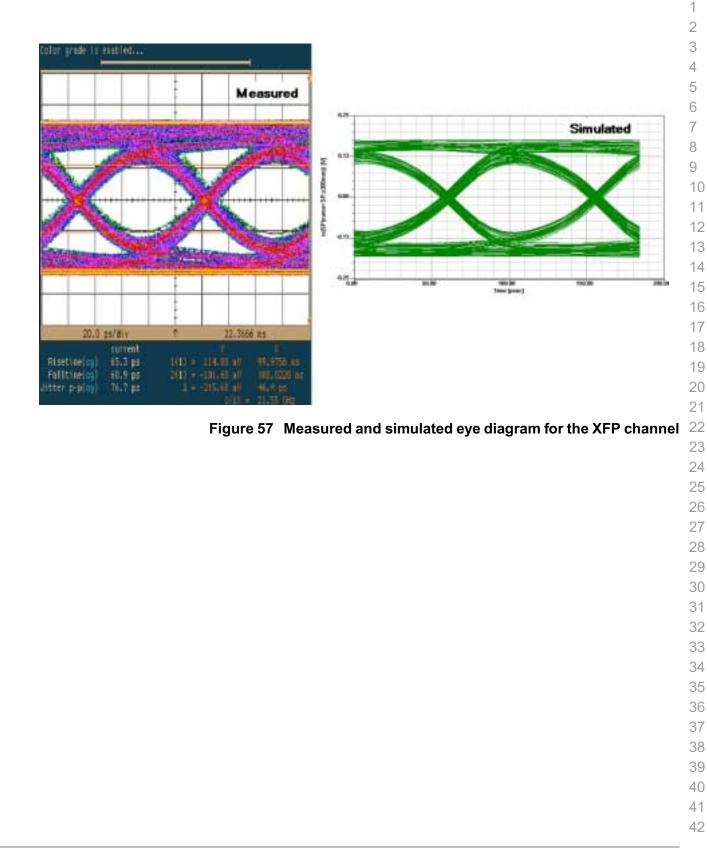
Figure 53 PCB Board Stack up

B.2 DESIGN GUIDELINE		1
	• Keep differential pair traces on the same side of the PCB to minimize impedance discontinuities.	2 3
	 When routing differential pairs, keep the trace length identical be- tween the two traces. Differences in trace lengths translate directly into signal skew and can give rise to common mode reflections. 	4 5 6
	Eliminate/reduce stub lengths of traces and vias.	7
	• Reduce, if not eliminate, vias to minimize impedance discontinuities. Remember that vias and their clearance holes in the power/ground planes can cause impedance discontinuities in nearby signals. Keep vias away from traces by 10 times the trace width if possible, 2.5 times as a minimum.	8 9 10 11 12
	 Use rounded corners rather than 90 or 45-degree corners. 	13
	 Keep signal traces far from other signals that might couple noise into the signals. A good rule of thumb is that "far" means ten times the width of the trace. 	14 15 16
	• Do not route digital signals from other circuits across the area of the transmitter and receiver.	17 18
	 Do not cut up the power or ground planes in an effort to steer current paths. This usually produces more noise, not less. Furthermore, place vias and clearances so as to maintain the integrity of the plane. Groups of vias spaced closely together often overlap clearances that can form a large hole in the plane. Return currents are forced around the holes, increasing loop area and therefore, EMI emissions. 	 19 20 21 22 23 24 25
B.3 USING SYSTEM SIMULATIC	N FOR CHANNEL MODELING	26
	Figure 54 depicts the system simulator model for the XFP channel of Figure 52 including the transceiver board traces, the Tyco connector, and the host board traces. S-parameter models that were computed from the circuit and electromagnetic simulations are cascaded to allow evaluation of end-to-end system performance.	27 28 29 30 31
	Figure 55 and Figure 56 contain comparisons of the simulated and mea- sured differential s-parameters for SDD11 and SDD21, respectively. Al- though differences between the simulated and measured are observed (especially for SDD11), it is clear that the simulations have accurately de- picted the trends for the overall system response.	 32 33 34 35 36 37 38 39

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APPENDIX C: DIFFERENTIAL S-PARAMETERS AND TDR

C.1 CHOOSING S-PARAMETERS VS TDR

S-Parameters measured with a Vector Network Analyzer (VNA) provide a good match to the frequency and time response, but do not correlate to the location of discontinuity.

TDR response can isolate location of discontinuity from the measured response and allow isolation of signal integrity issues.

oponioo		
		12
Advanta	age of VNA:	13
• 1	Nost accurate method of modeling passive networks	14
		15
	High BW >50GHz	16
Advanta	ages of TDR:	17
•	solate signal integrity location	18
		19
•	mmediate view of DUT while measuring	20
•	ntuitive display in anticipating eye pattern problems.	21
Disadva	Intage of VNA	22
		23
• 4	4-port VNA required or conversion from two ports	24
• [Measurement time	25
Disadva	intage of TDR	26
		27
•	Not very accurate to provide spatial information	28
	Accuracy decreases as frequency increases due to reduced pow- er in high frequency components.	29 30
		31
	Using averaging of many pulses to reduce effective noise, a prac- ical limit to usage is between 10 Ghz and 20 Ghz.	32
	TDR must be converted to S-parameters by FFT with tools such as: Tektronix IPA or NIST(free US govt) TDNACal	33 34
The cho	ice between TDR and VNA should be made based on availability	35
	ment and tools as well as accuracy required.	36
11-		37
		38

C.2 DIFFERENTIAL IMPEDANCE

2 Stripline and microstrip transmission lines are transverse electromagnetic 3 (TEM) and guasi-TEM structures, respectively. Waves that propagate on 4 these structures have propagation constants that are predominantly linear with frequency and hence phase velocities that are nearly constant with 5 frequency. In isolation, these lines exhibit a single-ended characteristic 6 impedance, phase velocity, and attenuation. As a pair of these lines are 7 moved closer together, coupling occurs that significantly alters the trans-8 mission line parameters and makes possible the propagation of differen-9 tial and common-mode guided waves.

The odd-mode differential impedance observed on a symmetrical differential pair is twice the single-ended impedance of each individual line minus the mutual impedance due to electromagnetic coupling. Strong coupling between the conductors forming a balanced differential pair will lower the differential impedance. In contrast, the differential impedance of a loosely coupled pair appears as the sum of the two individual singleended impedances. This is shown explicitly in the following equation

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 $Z_{diff} = (Z_{11} - Z_{12} + Z_{22} - Z_{21})$

For symmetrical structures may be given by

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 $Z_{diff} = 2 \cdot (Z_{11} - Z_{12}) = 2 \cdot (Z_{22} - Z_{21})$

where

 $Z = \begin{bmatrix} Z_{11} & Z_{12} \\ Z_{21} & Z_{22} \end{bmatrix}$ 29 30 31 32

Z_{diff} may is also given by

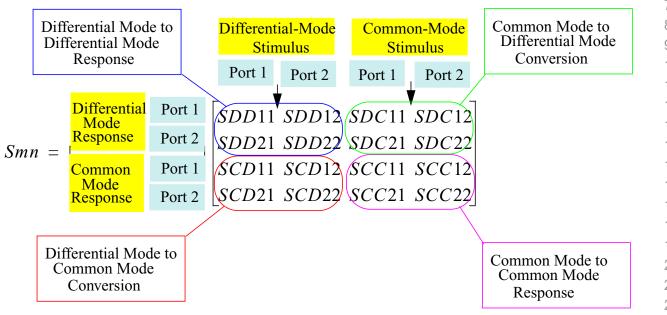
 $Z_{diff} = 2 \cdot Z_{odd}$ 35

where Z_{odd} is the odd impedance. Similarly the common mode impedance may be given by:

$$Z_{cm} = 0.5 \cdot Z_{even} \tag{40}$$

XFP Specification REVISION 2.0	Differential S-	Parameters and TDR	April 2, 2003	
	where Z _{even} is th	e even impedance.		
C.3 4 PORT SINGLE-ENI				
			ne ratio of two normalized power	
			us). A block diagram of a 4 port	
	device is shown i	n <u>Figure 58</u> .		
	Port 1		Port 2	
		DUT		
		DUI		
	Port 3		Port 4	
		Figure 58 4 Po	rt DUT	
	The 4 port S-Par	ameter matrix is given b	elow.	
	·	0		
		Stimulus Po	orts	
		<i>S</i> 11 <i>S</i> 12 <i>S</i> 13		
	$Sxy = \frac{Resp}{R}$			
	P	ort S31 S32 S33	S S34	
		S41 S42 S43	5 <i>S</i> 44	
C.4 2 PORT MIXED MOD	E DIFFERENTIAL S-PAR	AMETER DEFINITION		
			ed as voltages and currents in	
	0	•	ort Differential DUT, differential	
			are defined for each balanced	
	Figure 59.	gram of a two port differe	ential mixed mode is shown in	
	<u>- igaro co</u> .			
	Port 1	DUT	Port 2	
		Figure 59 Differentia	I 2 Port DUT	
XFP MSA		je 138	Copyright © 2002 by XFP MSA	-

The mixed-mode differential S-Parameters can be organized similar to the single ended S-Parameters. The mixed mode differential S-matrix consists of common mode and differential responses. The 2 Port Differential S-Parameters (Mixed-Mode) are given below:



The differential mode to differential mode performance, SDDxx, are the pure differential mode operation. If differential coupling is small, then the differential mode parameters are reduced to a 2-port single ended S-parameters. The differential mode to common mode conversion, SCDxx, should ideally be equal to Zero with perfect symmetry as it relates to the generation of EMI. The common mode stimulus to differential mode conversion, SDCxx, indicates susceptibility of a device to EMI and should be ideally zero. Common mode stimulus to common mode response indicate performance of the device under common mode.

The mixed mode differential S-Parameters may be written in terms of the two port single ended S-Parameters as the following:	1 2
	3 4 5
	6 7 8
$S^{mn} = \frac{1}{2} \begin{bmatrix} S_{11} - S_{31} - S_{13} + S_{33} & S_{12} - S_{32} - S_{14} + S_{34} & S_{11} - S_{31} + S_{13} - S_{33} & S_{12} - S_{32} + S_{14} - S_{34} \\ S_{21} - S_{41} - S_{23} + S_{43} & S_{22} - S_{42} - S_{24} + S_{44} & S_{21} - S_{41} + S_{23} - S_{43} & S_{22} - S_{43} + S_{24} - S_{44} \\ S_{11} + S_{31} - S_{13} - S_{33} & S_{12} + S_{32} - S_{14} - S_{34} & S_{11} + S_{31} + S_{13} + S_{33} & S_{12} + S_{32} + S_{14} + S_{34} \\ \hline \\ S_{11} + S_{31} - S_{13} - S_{33} & S_{12} + S_{32} - S_{14} - S_{34} & S_{11} + S_{13} + S_{33} & S_{12} + S_{32} + S_{14} + S_{34} \\ \hline \\ \end{bmatrix}$	8 9 10 11
$S = \frac{1}{2} \frac{1}{S_{11} + S_{31} - S_{13} - S_{33}} \frac{1}{S_{12} + S_{32} - S_{14} - S_{34}} \frac{1}{S_{11} + S_{31} + S_{13} + S_{33}} \frac{1}{S_{12} + S_{32} + S_{14} + S_{34}}{S_{11} + S_{13} + S_{13} + S_{13} + S_{14} + $	10
$\left[s21 + s41 - s23 - s43 \ s22 + s42 - s24 - s44 \ s21 + s41 + s23 + s43 \ s22 + s42 + s24 + s44 \right]$	12
	13
	14 15
A commonly available two ports Vector Network Analyzer with standard	15 16
calibration technique and the above relationship can be used to test for	17
compliance to the XFI channel. If a 4 port VNA is available then the differ- ential and common mode parameters can be measured directly.	18
SDD21 is given by	19 20
SDD21 is given by:	21
	22
$SDD21 = \frac{1}{2}(S21 - S41 - S23 + S43)$	23 24
	25
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	27 28
If the differential channels is symmetrical, then:	29
S21 = S43, S41 = S23, S12 = S34, S14 = S32, S11 = S33, S22 = S44	30
	31
In a typical application where the channel meets the XFI specification for differential return loss SDD21 can be approximated by the single ended	32 33
S-Parameter:	34
	35
$SDD21 \cong (S21 - S41) \cong S21.$	36 37
5DD21 = (521 - 541) = 521.	38
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APPENDIX D: OPTIMUM VIA DESIGN

D.1 VIAS

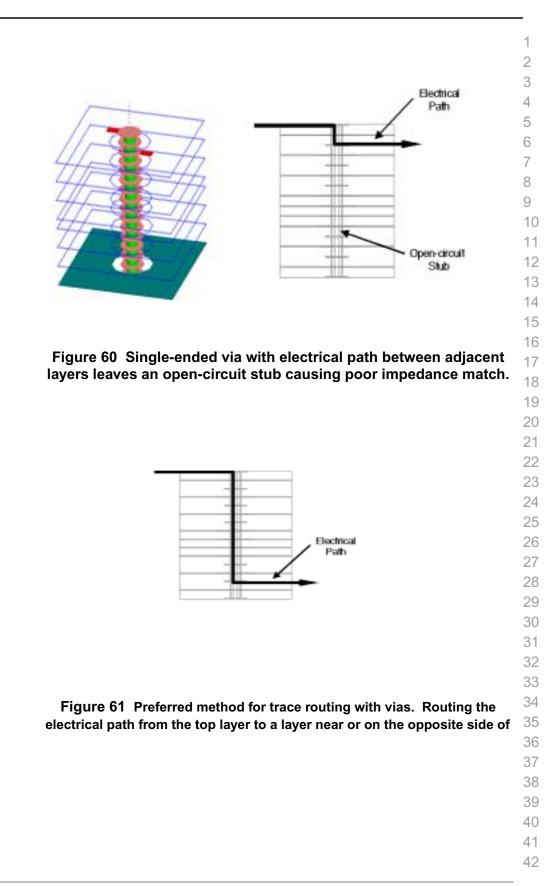
6 Via structures allow PCB designers to route circuit traces between layers 7 of a multilayer board. Vias may be particularly useful to transition from the 8 pins of a BGA or connector down to stripline traces within a host or trans-9 ceiver board. The most common and inexpensive via structure is the socalled through-hole via. A through-hole via is manufactured by drilling all the way through the PCB followed by a plating process. The plating process provides electrical continuity to top and buried traces by virtue of signal pads located on the desired layers. Alternatives to the through-hole via are the blind via and the back-drilled via. Although these alternatives may provide higher performance, it is generally believed that most XFP adopters will use the lower cost through-hole via for volume manufacturing.

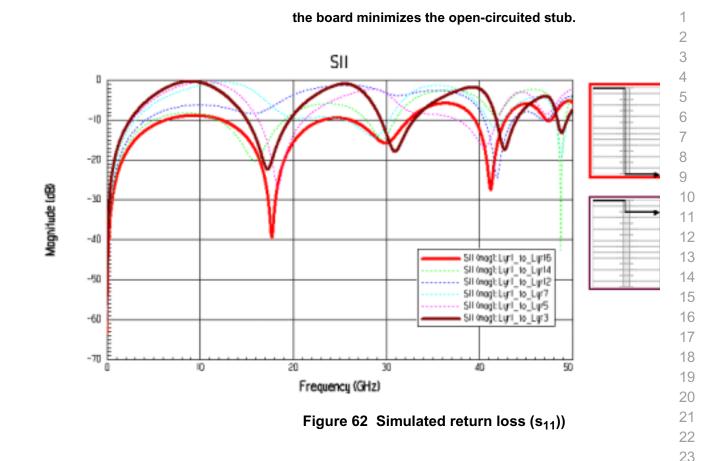
This section examines single-ended and differential through-hole vias for XFI implementation. Guidelines are provided for trace routing and for particular via dimensions.

D.2 SINGLE-ENDED VIAS

24 Figure 60 depicts a single-ended through-hole via that provides a transi-25 tion from the top layer to the next adjacent layer in a 16-layer PCB. Only 26 that portion of the via between the adjacent layers is used for electrical 27 path. The remaining portion provides an electrically short open-circulated transmission line stub. The additional reactance that results tends to lower 28 the characteristic impedance and hence causes reflections. A much 29 better approach is to route traces as shown in Figure 61. By transitioning 30 from the top layer to a layer near or on the opposite side of the board min-31 imizes the size of the open circulated stub and hence minimizes electrical 32 reflections. 33

Full-wave, 3D electromagnetic simulations were performed using Ansoft 34 High Frequency Structure Simulator (Ansoft HFSS™). The simulations 35 were used to evaluate the relative performance of via structures with and 36 without open-circulated stubs. Figure 62 is a plot of the extracted s-pa-37 rameters for transitions from the top layer to various layers of a 16-layer 38 PCB. The red curve is for trace routing from the top to the bottom layer and yields the best performance (lowest reflections).





D.3 DIFFERENTIAL VIAS

Because the XFI interface is differentially signaled, vias are generally ex-25 pected to occur in pairs. These differential vias are used to route signals 26 from top layer microstrip traces down to buried stripline traces. Figure 63 27 shows a differential via geometry with a pair of via structures traversing 28 through several power and ground planes on a 100mil thick multilayer 29 PCB. Critical dimensions are the via diameter (drill size), pad diameter, 30 gap between the pad and the ground/power plane cutout, and via pitch. 31 Fullwave 3D electromagnetic simulations were performed to identify dimensions that would minimize reflections and provide the best signal fi-32 delity. The tunable parameters are the via pitch and gap as illustrated in 33 the Figure 64. 34

Two board thicknesses were considered for the simulations: a 100 mil
thick board and a 62 mil thick board. A parametric sweep of via pitch and
gap revealed that the best performance was achieved using the dimen-
sions outlined in Table 64. Interestingly, the dimensions for both board
thicknesses are identical. This can be explained by considering the via
structure as a transmission line with propagation along the dimension per-
pendicular to the PCB plane. It is intuitive that this transmission line35
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should have a uniform cross-section that is independent of the length of the line (board thickness).

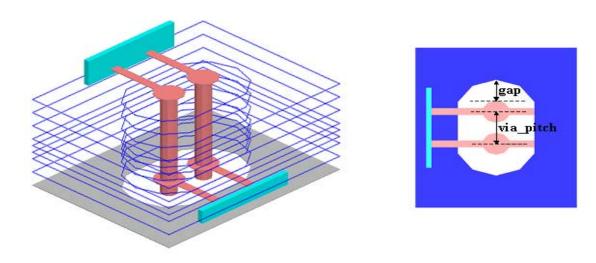


Figure 63 Differential via geometry a 100mil multilayer PCB.

Table 64	Optimized	differential via	geometry fo	or 100 mil	and 62 mil thick PCB
	~ p		8		

Parameter	Gap (mm)	Via Pitch (mm)	Drill Size (mm)	Pad Diameter (mm)
100 mil Board	0.52	0.8	0.3	0.56
62 mil Board	0.52	0.8	0.3	0.56

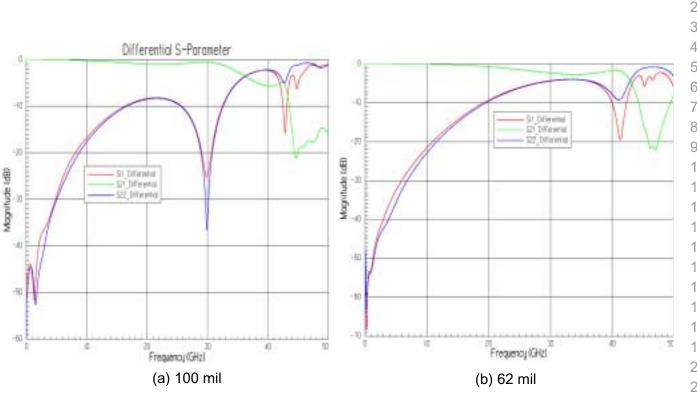
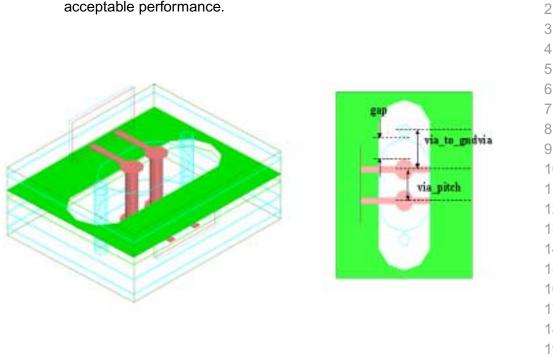


Figure 64 S-parameters for optimized via structures with dimensions given in Table 1. (a) 100 mil thick PCB. (B.) 62 mil thick board.

D.4 GSSG DIFFERENTIAL VIAS

An improvement to the traditional differential via is to utilize a groundsignal-signal-ground (GSSG) geometry. The GSSG differential via consists of four single-ended vias as shown in Figure 65. The two inner vias are the differential signal lines and the outer two vias are ground return lines. Although differential signaling generally provides for all return path currents, the GSSG geometry can support common-mode signals with a well-controlled return current path. Any common-mode signals that get coupled or generated can propagate through the via (rather than being scattered) and along the transmission line to the receiver where it is terminated.

Critical dimensions for the GSSG geometry are via diameter (drill size), pad diameter, gap between the pad and the ground/power plane cutout, via pitch, and via-to-ground via. With the additional conductors of the GSSG structure, there are more tunable parameters that can be used to provide optimal performance. Fullwave 3D electromagnetic simulations were performed to optimize the geometry on a 62-mil stack up. Table 65

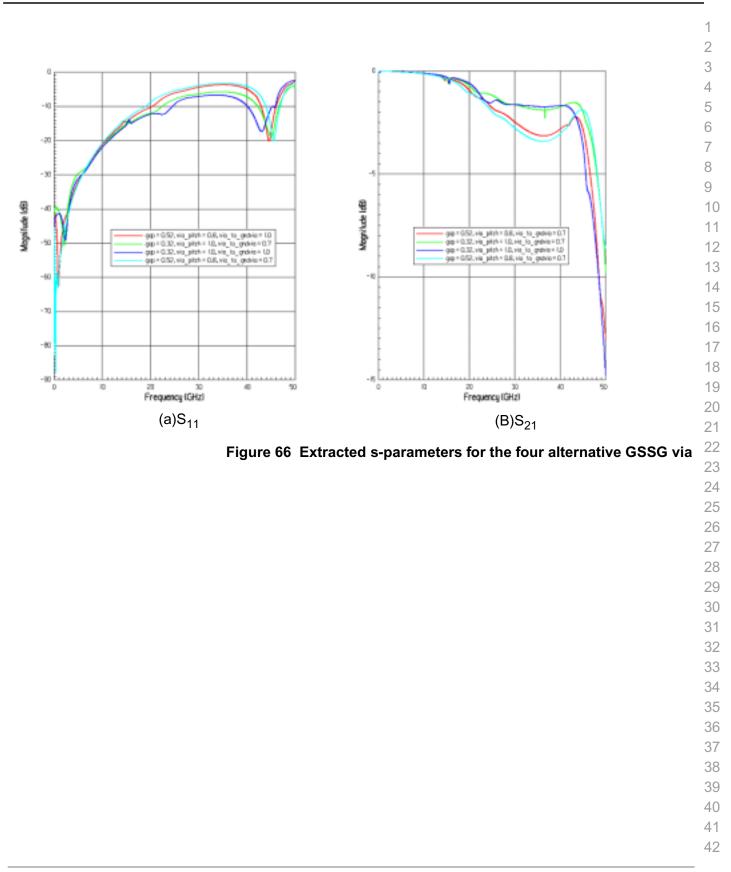


provides four alternative GSSG via dimension combinations that provide acceptable performance.

Figure 65 GSSG via structure

Table 65	Four alternative	GSSG via	dimension
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Gap (mm)	Via Pitch (mm)	Via-To_Ground (mm)	Drill Size (mm)	Pad Diameter (mm)
0.32	1.0	0.7	0.3	0.56
0.32	1.0	1.0	0.3	0.56
0.52	0.8	0.7	0.3	0.56
0.52	0.8	1.0	0.3	0.56



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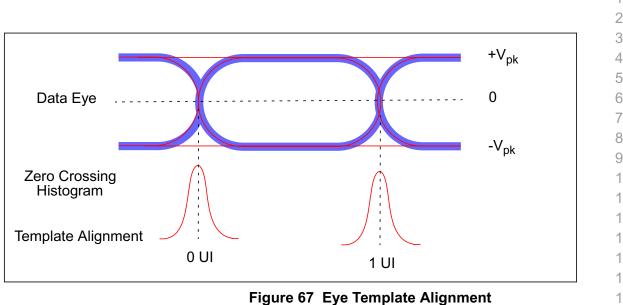
30 31

APPENDIX E: JITTER METHODOLOGY AND MEASUREMENT

E.1 EYE MASK COMPLIANCE

This annex describes requirements for determining eyemask compliance. Mask templates and coordinates are given in the appropriate subclauses in clause 2.

- Compliance is to be assured during system operation. However,
measurements with patterns such as PRBS23 or a valid 10GBASE-R10or 10GBASE-W or OC192c or STM-64 signal are likely to give similar
results.13
- During test, both transmit and receive paths must be active to include 14 the effects of crosstalk. Traffic in the other direction (than the one being tested) must use a asynchronous clock 16
- Compliance at higher rates can qualify for lower rates, however the opposite is not allowed.
 17
- Testing may include guard banding, extrapolation, or other methods, 19 but must ensure that mask violations do not occur at a rate above 1E-12.
- The eye template is to be measured differentially.
- If AC coupling is used the high pass 3 dB frequency corner shall low enough not to generate error floor > 1E-12.
- All loads are specified at 100 $\pm 5 \Omega$ differential.
- Zero "0" and One "1" on the unit interval scale are to be determined by the eye crossing means measured at the average value (zero volts) of the eye pattern, as illustrated in Figure 67. The average value ue might not be at the jitter waist.
 - 32 33 34 35 36 37 38 39 40 41



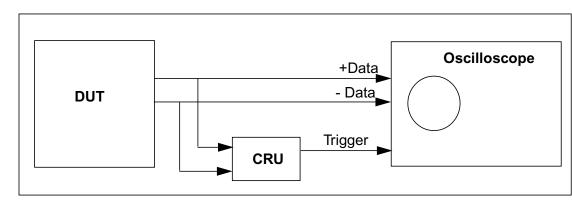


Figure 68 Eye mask measurement setup - block diagram.

A clock recovery unit (CRU) should be used to trigger the scope for mask measurements as shown in Figure 68. It should have a high frequency corner bandwidth of 4 MHz and a slope of –20 dB/decade with maximum peaking of 0.1 dB.

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E.2 NON-DDJ EYE MASK

2 Compliance point B and D are required to have bounded non-DDJ jitter. This test guarantees that the total jitter is not overwhelmed by the DCD 3 and random jitter. The setup is similar to the standard eye mask measure-4 ment but the eye is measured with and without the inverse channel filter. 5 The block diagram of the measurement is shown in Figure 69. 6

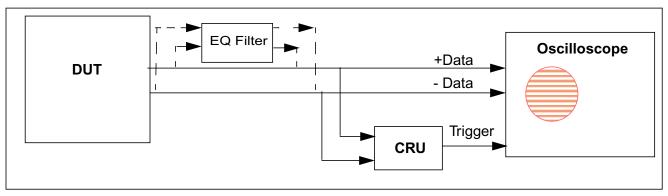


Figure 69 Eye mask measurement setup - block diagram.

EQ Filter is based on the inverse response of the channel, where the 21 channel is specified in section 3.4. An approximate EQ filter may be con-22 structed with following characteristics: 23

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	26
$H(f) = \frac{fl + if}{fu + if}$	27
fu + if	28

Where: fl=2.5 GHz fu=5 GHz

In addition the filter must meet:

- SDD21 accuracy must meet ± 1dB from 1MHz to 10 GHz.
- SDD11 > 20 dB from 1MHz to 10 GHz
- Differential Skew <5 ps

37 Alternatively the waveform may be captured and the above filter response 38 may be applied by post processing. It is also expected some time in the future there will be Time Interval Analyzer (TIA), which can measure the non-DDJ directly.

E.3 STRESS EYE TEST FOR RX TOLERANCE TESTING Applies to compliance B' and D with the maximum input peak to peak jitter applied. Jitter components are: data dependent jitter, DCD, random jitter, and periodic jitter¹. Jitter tolerance is performed with meeting the maximum input total jitter as well as meeting the maximum non-DDJ (non equalized portion of jitter). XFI receiver shall tolerate an additional sinu-

jitter to	lerance test is as the following:
•	Verify the XFI transmitter is compliant
•	Add ISI/DDJ to the channel
•	Verify total jitter and total non-DDJ requirement are met
•	Add sine jitter per given template
•	Avoid additive random jitter.
•	Amplitude control
•	Operate the link with recommended data pattern for SONET, 802.3ae, 10GFC, or G. 709.
•	Meet a minimum BER of 1E-12.
For fur 52.	ther information on this technique please see IEEE 802.3ae clause

osidal jitter as defined for Telecom and/or Datacom. The procedure for

E.4 JITTER PEAKING SPECIFICATIONS AND MEASUREMENTS

25 In Section 3.8 of the XFP MSA, module jitter peaking specifications are 26 given for datacom and telecom modules for both the receiver and trans-27 mitter paths. In the case of telecom modules to be used for looptiming based regenerator applications, the jitter peaking below 120 KHz is limited 28 to 0.03 dB for both receiver and transmitter. This last specification is de-29 rived from the need for the overall system jitter peaking to be kept below 30 0.1 dB for regenerator applications. While these requirements are be-31 lieved to be practical for existing signal conditioner and module optics 32 technology, verification of this performance presents considerable difficul-33 ties due to limitations of current measurement equipment. This annex describes these difficulties and suggests alternative characterization 34 techniques to be used until appropriate measurement equipment be-35 comes available. 36

Equipment exists today to do jitter transfer measurements on devices with electrical inputs and electrical outputs as well as for equipment with optical inputs and outputs. This type of equipment is able to achieve high ac-

1. Fiber Channel-Methodology for jitter and Signal Quality Specification-MJSQ, 41 INCITs T11.2/Project 1316-DT. 42

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curacy by calibrating measurements against measurements made with the instrument looped back to itself. Making an equivalent measurement of a device with electrical input and optical output, or vice versa, is more problematic. Even if an instrument can make such a measurement, its accuracy would probably be limited to far worse than 0.03 dB because a direct input to output calibration would not be possible.

7 In order to do an electrical-to-optical or optical-to-electrical jitter transfer measurement with high accuracy, a reference optical receiver or trans-8 mitter with well-characterized jitter transfer characteristics is required. 9 Such a reference device could be used to provide a reference calibration 10 measurement against which to compare the device under test in a system 11 configured to perform an electrical-to-optical or optical-to-electrical mea-12 surement. Alternatively, a reference receiver could be used to convert the 13 optical output of a device under test to electrical allowing a precision electrical-to-electrical measurement of the combination from which the 14 transfer characteristics of the reference receiver could be subtracted. Sim-15 ilarly, a reference transmitter could be used to stimulate an optical receiver 16 path under test. At this writing, such well-characterized reference trans-17 mitters and receivers are not commercially available. 18

There are several means by which host system and module manufac-19turers can verify the required performance needed to meet the overall sys-20tems requirements. (Examples are given for the difficult 0.03 dB peaking21case, but the same logic applies to the 1 dB peaking requirement for22datacom modules).23

5. Overall System Measurement

25 Host system manufacturers can qualify modules for jitter peaking by 26 measuring them in the desired final system environment. A module 27 under test can be placed in the target host system and the overall 28 system optical-to-optical jitter transfer can be measured by placing the 29 system in a looptiming loopback mode (which should be below 0.1 dB 30 at 120 KHz or less). For further accuracy, the host system's jitter peaking can be separately measured and subtracted from the total 31 measurement to approximate the module's total transmit and receive 32 path peaking which should be less than 0.06 dB below 120 kHz. This 33 measurement can be achieved by measuring the system's electrical to 34 electrical jitter peaking by substituting a host compliance test coupon 35 for the module under test.

6. Module Total Jitter Peaking Measurement

A useful, but not complete measurement can be made of the module jitter peaking directly by testing the module with the optical output looped back using an electrical-to-electrical jitter peaking test, or by looping the electrical output back to the transmitter input and performing an optical to optical measurement. In this case a measure of 42

XFP Specification REVISION 2.0		Jitter Methodology and Measurement	April 2, 2003	
		the sum of the transmit and receive path peaking is be less than 0.06 dB below 120 KHz, though this possibility that either the receive or transmit paths 0.03 dB.	still allows for the	
	7.	Measurement of Module Signal Conditioner		
		It is expected that the low frequency jitter transfer of XFP module will be dominated by the signal cond transmit and receive paths. While not a useful mod a module manufacturer can determine likely modu formance by separately characterizing the perforr conditioners used in the modules under likely wor Such measurements should be done with the sign test environment as similar as possible to that of the These measurements do have the advantage that separately characterize the module receive and the	litioners in the ule compliance test, ule jitter peaking per- nance of the signal rst-case conditions. nal conditioners in a the final module. they can be used to	
	pli	hile none of the above techniques is a perfect subst ance test of module jitter peaking, they probably pr ernative until appropriate test equipment is develop	ovide a reasonable	
E.5 AC COMMON MODE TEST	•			
	lim co on fur	minimize generation of common mode noise and a nits the maximum common mode voltage at the cor mmon mode voltage is measured by subtracting th the scope. The RMS value are calculated by apply nction to the common mode signal. Common mode ecified for the following test point:	mpliance point. The le differential output ying the Histogram	
		A 15 mV RMS - Output		
		B 25 mV RMS - Output		
		C' 15 mV RMS - Output		
		D 25 mV RMS - Input.		

E.6 TERMINATION MISMATCH

Termination mismatch is defined as the difference between the compli-37 mentary R_p and R_n resistors as shown in Figure 5. Measuring termination mismatch through an AC coupling capacitor requires access to the IC. 39 Termination mismatch is defined as:

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$$\Delta Z_M = 2 \times \frac{R_p - R_n}{R_p + R_n} \times 100$$

Alternatively, the termination mismatch can be measured by applying a low frequency test tone to the differential inputs as shown in <u>Figure 70</u>. The test frequency must be high enough to overcome the high pass effects of the AC coupling capacitor. Low frequency termination mismatch is then given by:

$$\Delta Z_M = 2 \times \frac{I_p - I_n}{I_p + I_n} \cdot \frac{R_{diff} + 100}{R_{diff}} \cdot 100$$

where I_p and I_n are the current flowing in to the XFI port as shown in Figure 70.

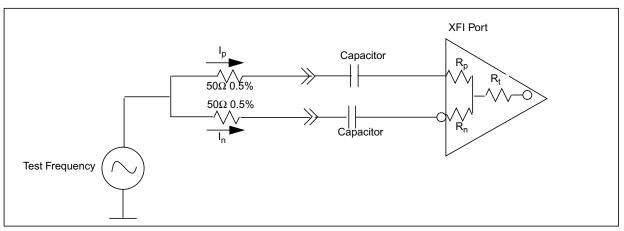


Figure 70 AC Termination Mismatch Measurement

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E.7 POWER SUPPLY NOISE TESTING METHODOLOGY

E.7.1 POWER SUPPLY NOISE COMPLIANCE

The module is specified to tolerate 2% of broadband noise amplitude on the power supply at frequencies up to 1 MHz, then 3% for frequencies up to 10Mhz. This methodology covers test methods to assure compliance to the XFP specification.

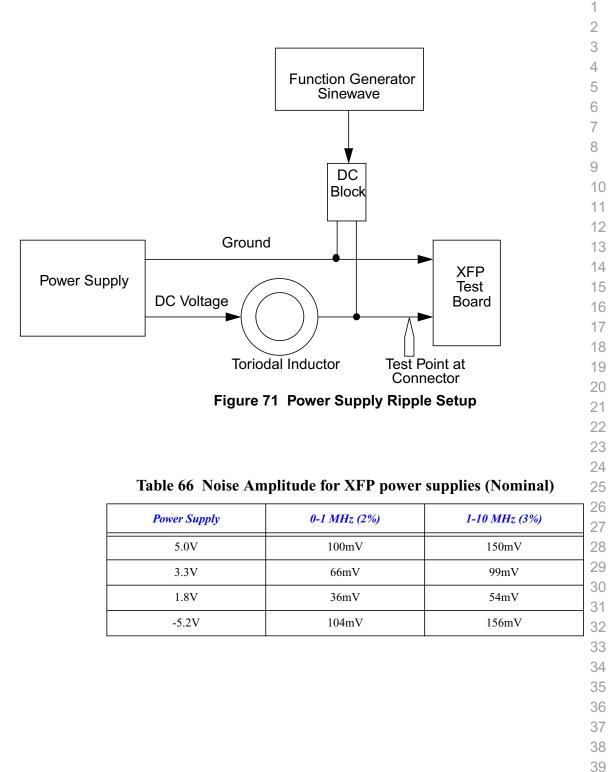
E.7.2 POWER SUPPLY NOISE METHODOLOGY

12 In this test noise is injected to the power supply rail from a function gen-13 erator generating a sine wave. The noise measurement set up is shown in Figure 71. The noise is AC coupled into the test board and the DC 14 power is coupled in through an inductor to keep the noise from sinking into 15 the power supply. The inductor should be optimized for maximum noise at 16 the test point over all frequencies tested. The amplitude should be mea-17 sured at the connector on the test board with the module plugged in. This 18 assures the noise induced into the module is filtered within the module re-19 gardless of amount of test board decoupling. The required amplitude of 20 the noise signal generator will vary from different test boards due to decoupling and layout differences. The typical noise amplitudes are listed in 21 Table 66. The worst case system noise is with the module plugged into the 22 socket while achieving the desired amount of noise. 23

E.7.3 POWER SUPPLY NOISE METHODOLOGY

27 Tests for power supply noise compliance should include optical receiver 28 sensitivity, which can be measured with SONET GR-253 or IEEE802.3ae methodologies. Also optical transmitter jitter with a worst-case electrical 29 eye as an input (Table 13) should be measured. Transmitter jitter testing 30 can be done with IEEE802.3ae eyemask and Tpd measurements, or 31 SONET GR-253 jitter generation measurements. Testing should look at 32 the difference of these parameters with and without the noise present. 33 The noise source frequency should be varied from 0 to 10Mhz to deter-34 mine if any frequency causes a parameter to fall out of the specification 35 limit. In all cases, the parameters measured should pass the optical standards with the noise present over all frequencies specified.

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APPENDIX F: MODULE THERMAL TESTING

F.1 MODULE THERMAL POWER CLASSES

XFP has four possible power classes:

- Power Level 1 modules Up to 1.5 W
- Power Level 2 modules Up to 2.5 W
- Power Level 3 modules Up to 3.5 W
- Power Level 4 modules Greater than 3.5 W

The module vendor is responsible to identify the power level of their module to the system designer.

F.2 THERMAL TEST RECOMMENDATION

The purpose of this appendix is to provide guidance to XFP module designers in creating a standard test environment for simulation and/or actual testing. It allows for "one" initial means of communication between module designers and system users.

XFP is designed with an adaptable approach to thermal management allowing use of a single module design in a wide variety of host environments. The tests described in this appendix focus on a module's thermal performance within a defined system level environment. Host system designs will often optimize one or more of the following parameters to achieve lower XFP case temperatures: module spacing, heatsink shape/length/width/fin design, and airflow direction/mixing.

The tests defined in this appendix are intended to be easy to produce by module manufacturers. For example, the number of modules on a host card has been limited to 4 and a heat sink has been defined for this testing. Module manufacturers may choose to provide additional test data of their module in customer specific applications that may have more or less modules, other heat sinks, or environments.

Substantial variations in module thermal performance can occur depending on system level design. This appendix does not guarantee system level performance, as each system will be designed independent of this document per the end user system requirements. It is the responsibility of the system designer to ensure the thermal characteristics meet

their individual system needs. All characterization results presented in this 1 appendix are intended as examples only. 2

F.3 THERMAL TEST CONFIGURATION

FIGURATION	0
There are two unique system environments anticipated for XFP trans- ceivers. One environment is a PCI envelope with limited vertical space, minimal airflow, and 1-2 transceivers (System A). In this envelope suffi- cient space is not available for a cage mounted heat sink. A second envi- ronment has more vertical space and forced airflow across a larger number of transceivers (system B)	6 7 8 9 10 11
Information presented by the module vendor in relation to this document should be obtained from a 'confined or ducted flow' described as:	12 13 14
 A duct defined by the host board on the bottom, a plane above the host board <u>Table 67</u>, the host board bezel, and a vertical plane 81 mm from the host board bezel. 	15 16 17
 PCB host board should have no copper content between planes except for grounding of the cage. 	18 19
 An insulated duct housing with poor thermal conduction must be used i.e. a plastic. 	20 21
 Dimensions of system should allow for 4 modules on 23.5 mm spacing. 	22 23
 For the multiple module configurations, it is assumed that the test conditions drawn for module 1, will be duplicated for module n. i.e. the cage configuration. 	24 25 26
 Multiple modules will be adjacent to one another with no gaps from empty module slots. 	27 28
 The test chamber will be clear of obstruction for 30cm after the outlet. 	29 30
 A steady state should be obtained to take measurements. 	31
 A blower mounted so that the direction of airflow is side to side. 	32 33
 Case temperature measurements points may be proprietary and vary from one module design to the next. Module vendors should identify these to the end user for verification in the system level environment. 	34 35 36 37
 Airflow should be characterized using a calibrated hot wire ane- mometer placed at the airflow inlet 	37 38 39
 Thermocouples should be used to measure case temperatures. 	40
 An example of measurement data is shown in <u>Figure 72</u>. 	41 42

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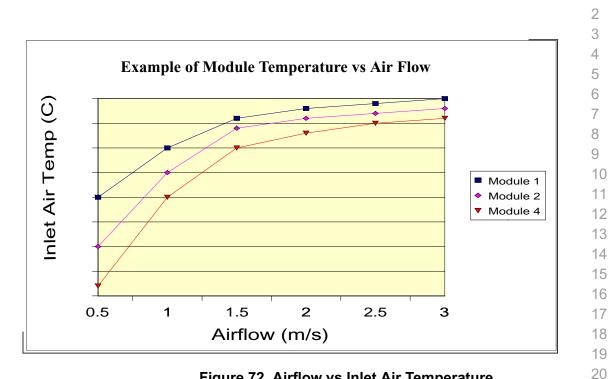


Figure 72 Airflow vs Inlet Air Temperature

- Identical module types will be expected to be characterized I.E. • no mix of 850nm,1310nm, or 1550nm is mandated.
- When undergoing thermal evaluation, transceivers should output ٠ bi-directional data using a PRBS 2³¹-1 data pattern.
- Other measurement data provided is at the discretion of the ven-• 27 dor.
- The system should provide uniform airflow across the vent opening and be of constant volume airflow.

The test conditions for system A and system B are defined Table 67.

Table 67 Environmental Test Conditions

Parameter	System A (PCI application)	System B (Switch application)
Number of modules	1 or 2	1,2,4
Inlet air temperature	5°C to 50°C	5°C to 40°C
Altitude	Sea Level	3000 m
Air Humidity	40% to 60%	40% to 60%

XFP MSA

Parameter	System A (PCI application)	System B (Switch application)
Minimum air flow	100 lfm	100 lfm
Maximum air flow	200 lfm	500 lfm
Free air space	14.5 mm	19 mm
MSA recommends cage mounted heat sink	No cage heat sink	Optional

Table 67 Environmental Test Conditions

For test purposes, the MSA recommended heat sink should be used to provide a consistent test methodology<u>Figure 73</u>.

